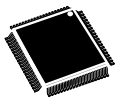
# STM32F103xF STM32F103xG

## XL-density performance line ARM®-based 32-bit MCU with 768 KB to 1 MB Flash, USB, CAN, 17 timers, 3 ADCs, 13 com. interfaces

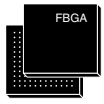
**Datasheet – production data**

## Features

- Core: ARM® 32-bit Cortex®-M3 CPU with MPU
  - 72 MHz maximum frequency, 1.25 DMIPS/MHz (Dhrystone 2.1) performance at 0 wait state memory access
  - Single-cycle multiplication and hardware division
- Memories
  - 768 Kbytes to 1 Mbyte of Flash memory
  - 96 Kbytes of SRAM
  - Flexible static memory controller with 4 Chip Select. Supports Compact Flash, SRAM, PSRAM, NOR and NAND memories
  - LCD parallel interface, 8080/6800 modes
- Clock, reset and supply management
  - 2.0 to 3.6 V application supply and I/Os
  - POR, PDR, and programmable voltage detector (PVD)
  - 4-to-16 MHz crystal oscillator
  - Internal 8 MHz factory-trimmed RC
  - Internal 40 kHz RC with calibration
  - 32 kHz oscillator for RTC with calibration
- Low power
  - Sleep, Stop and Standby modes
  - $V_{BAT}$ supply for RTC and backup registers
- 3 × 12-bit, 1 µs A/D converters (up to 21 channels)
  - Conversion range: 0 to 3.6 V
  - Triple-sample and hold capability
  - Temperature sensor
- 2 × 12-bit D/A converters
- DMA: 12-channel DMA controller
  - Supported peripherals: timers, ADCs, DAC, SDIO, $I^2S$s, SPIs, $I^2C$s and USARTs
- Debug mode
  - Serial wire debug (SWD) & JTAG interfaces
  - Cortex®-M3 Embedded Trace Macrocell™
- Up to 112 fast I/O ports
  - 51/80/112 I/Os, all mappable on 16 external interrupt vectors and almost all 5 V-tolerant
- Up to 17 timers
  - Up to ten 16-bit timers, each with up to 4 IC/OC/PWM or pulse counter and quadrature (incremental) encoder input
  - 2 × 16-bit motor control PWM timers with dead-time generation and emergency stop
  - 2 × watchdog timers (Independent and Window)
  - SysTick timer: a 24-bit downcounter
  - 2 × 16-bit basic timers to drive the DAC
- Up to 13 communication interfaces
  - Up to 2 × $I^2C$ interfaces (SMBus/PMBus)
  - Up to 5 USARTs (ISO 7816 interface, LIN, IrDA capability, modem control)
  - Up to 3 SPIs (18 Mbit/s), 2 with $I^2S$ interface multiplexed
  - CAN interface (2.0B Active)
  - USB 2.0 full speed interface
  - SDIO interface
- CRC calculation unit, 96-bit unique ID
- ECOPACK® packages



LQFP64 10 × 10 mm,
LQFP100 14 × 14 mm,
LQFP144 20 × 20 mm




LFBGA144 10 × 10 mm

**Table 1. Device summary**

| Reference | Part number |
|---|---|
| STM32F103xF | STM32F103RF STM32F103VF STM32F103ZF |
| STM32F103xG | STM32F103RG STM32F103VG STM32F103ZG |



This is information on a product in full production. www.st.com

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# 1 Introduction

This datasheet provides the ordering information and mechanical device characteristics of the STM32F103xF and STM32F103xG XL-density performance line microcontrollers. For more details on the whole STMicroelectronics STM32F103xF/G family, please refer to *Section 2.2: Full compatibility throughout the family*.

The XL-density STM32F103xF/G datasheet should be read in conjunction with the STM32F10xxx reference manual.
For information on programming, erasing and protection of the internal Flash memory please refer to the *STM32F10xxx Flash programming manual.*
The reference and Flash programming manuals are both available from the STMicroelectronics website *www.st.com*.

For information on the Cortex®-M3 core please refer to the Cortex®-M3 Technical Reference Manual, available from the *www.arm.com* website at the following address: *http://infocenter.arm.com*.

# 2 Description

The STM32F103xF and STM32F103xG performance line family incorporates the high-performance ARM® Cortex®-M3 32-bit RISC core operating at a 72 MHz frequency, high-speed embedded memories (Flash memory up to 1 Mbyte and SRAM up to 96 Kbytes), and an extensive range of enhanced I/Os and peripherals connected to two APB buses. All devices offer three 12-bit ADCs, ten general-purpose 16-bit timers plus two PWM timers, as well as standard and advanced communication interfaces: up to two $I^2C$s, three SPIs, two $I^2S$s, one SDIO, five USARTs, an USB and a CAN.

The STM32F103xF/G XL-density performance line family operates in the –40 to +105 °C temperature range, from a 2.0 to 3.6 V power supply. A comprehensive set of power-saving mode allows the design of low-power applications.

These features make the STM32F103xF/G high-density performance line microcontroller family suitable for a wide range of applications such as motor drives, application control, medical and handheld equipment, PC and gaming peripherals, GPS platforms, industrial applications, PLCs, inverters, printers, scanners, alarm systems and video intercom.

## 2.1 Device overview

The STM32F103xF/G XL-density performance line family offers devices in four different package types: from 64 pins to 144 pins. Depending on the device chosen, different sets of peripherals are included, the description below gives an overview of the complete range of peripherals proposed in this family.

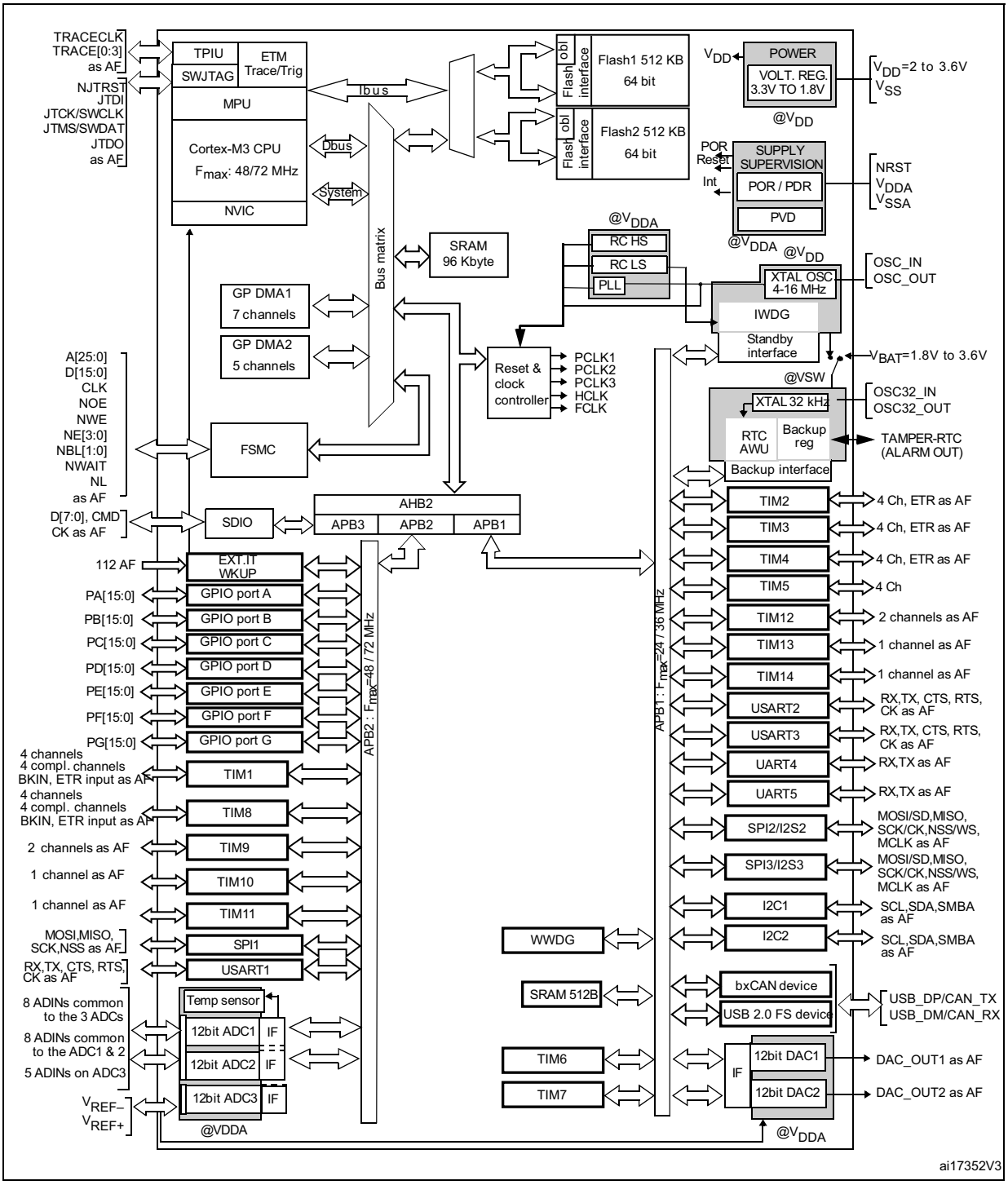
*Figure 1* shows the general block diagram of the device family.

**Table 2. STM32F103xF and STM32F103xG features and peripheral counts**

| Peripherals | | STM32F103Rx | | STM32F103Vx | | STM32F103Zx | |
|---|---|---|---|---|---|---|---|
| Flash memory | | 768 KB | 1 MB | 768 KB | 1 MB | 768 KB | 1 MB |
| SRAM in Kbytes | | 96 | | 96 | | 96 | |
| FSMC | | No | | Yes(1) | | Yes | |
| Timers | General-purpose | 10 | | | | | |
| | Advanced-control | 2 | | | | | |
| | Basic | 2 | | | | | |
| Comm | SPI($I^2S$)(2) | 3(2) | | | | | |
| | $I^2C$ | 2 | | | | | |
| | USART | 5 | | | | | |
| | USB | 1 | | | | | |
| | CAN | 1 | | | | | |
| | SDIO | 1 | | | | | |
| GPIOs | | 51 | | 80 | | 112 | |
| 12-bit ADC<br>Number of channels | | 3<br>16 | | 3<br>16 | | 3<br>21 | |
| 12-bit DAC<br>Number of channels | | 2<br>2 | | | | | |
| CPU frequency | | 72 MHz | | | | | |
| Operating voltage | | 2.0 to 3.6 V | | | | | |
| Operating temperatures | | Ambient temperatures: –40 to +85 °C /–40 to +105 °C (see *Table 10*)<br>Junction temperature: –40 to + 125 °C (see *Table 10*) | | | | | |
| Package | | LQFP64 | | LQFP100 | | LQFP144, BGA144 | |

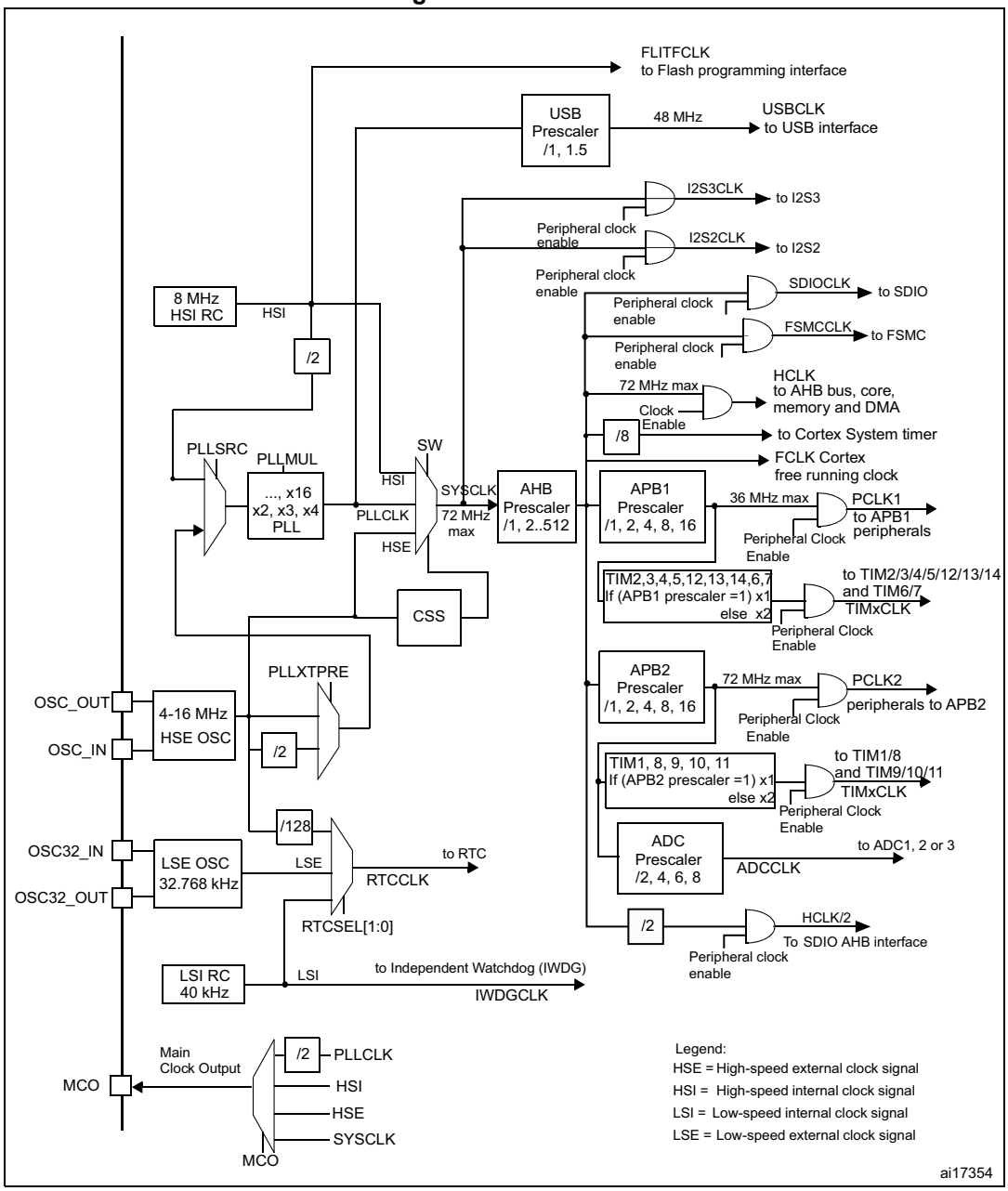
1. For the LQFP100 package, only FSMC Bank1 and Bank2 are available. Bank1 can only support a multiplexed NOR/PSRAM memory using the NE1 Chip Select. Bank2 can only support a 16- or 8-bit NAND Flash memory using the NCE2 Chip Select. The interrupt line cannot be used since Port G is not available in this package.
2. The SPI2 and SPI3 interfaces give the flexibility to work in an exclusive way in either the SPI mode or the $I^2S$ audio mode.

**Figure 1. STM32F103xF and STM32F103xG performance line block diagram**




1. $T_A$ = –40 °C to +85 °C (suffix 6, see *Table 73*) or –40 °C to +105 °C (suffix 7, see *Table 73*), junction temperature up to 105 °C or 125 °C, respectively.
2. AF = alternate function on I/O port pin.9

**Figure 2. Clock tree**




1. When the HSI is used as a PLL clock input, the maximum system clock frequency that can be achieved is 64 MHz.
2. For the USB function to be available, both HSE and PLL must be enabled, with the USBCLK at 48 MHz.
3. To have an ADC conversion time of 1 µs, APB2 must be at 14 MHz, 28 MHz or 56 MHz.

## 2.2 Full compatibility throughout the family

The STM32F103xF/G is a complete family whose members are fully pin-to-pin, software and feature compatible. In the reference manual, the STM32F103x4 and STM32F103x6 are identified as low-density devices, the STM32F103x8 and STM32F103xB are referred to as medium-density devices, the STM32F103xF, STM32F103xD and STM32F103xG are referred to as high-density devices and the STM32F103xF and STM32F103xG are called XL-density devices.

Low-density, high-density and XL-density devices are an extension of the STM32F103x8/B medium-density devices, they are specified in the STM32F103x4/6, STM32F103xC/D/E and STM32F103xF/G datasheets, respectively. Low-density devices feature lower Flash memory and RAM capacities, less timers and peripherals. High-density devices have higher Flash memory and RAM capacities, and additional peripherals like SDIO, FSMC, $I^2S$ and DAC. XL-density devices bring even more Flash and RAM memory, and extra features, namely an MPU, a greater number of timers and a dual bank Flash structure while remaining fully compatible with the other members of the family.

The STM32F103x4, STM32F103x6, STM32F103xF, STM32F103xD, STM32F103xG, STM32F103xF and STM32F103xG are a drop-in replacement for the STM32F103x8/B devices, allowing the user to try different memory densities and providing a greater degree of freedom during the development cycle.

Moreover, the STM32F103xx performance line family is fully compatible with all existing STM32F101xx access line and STM32F102xx USB access line devices.

**Table 3. STM32F103xx family**

<table>
<tr><th rowspan="3">Pinout</th><th colspan="2">Low-density devices</th><th colspan="2">Medium-density devices</th><th colspan="3">High-density devices</th><th colspan="2">XL-density devices</th></tr>
<tr><th>16 KB Flash</th><th>32 KB Flash(1)</th><th>64 KB Flash</th><th>128 KB Flash</th><th>256 KB Flash</th><th>384 KB Flash</th><th>512 KB Flash</th><th>768 KB Flash</th><th>1 MB Flash</th></tr>
<tr><th>6 KB RAM</th><th>10 KB RAM</th><th>20 KB RAM</th><th>20 KB RAM</th><th>48 or 64 KB(2) RAM</th><th>64 KB RAM</th><th>64 KB RAM</th><th>96 KB RAM</th><th>96 KB RAM</th></tr>
<tr><td>144</td><td colspan="4" rowspan="2"></td><td colspan="3" rowspan="3">5 × USARTs<br>4 × 16-bit timers,<br>2 × basic timers<br>3 × SPIs, 2 × I2Ss, 2 × I2Cs<br>USB, CAN, 2 × PWM timers<br>3 × ADCs, 2 × DACs,<br>1 × SDIO<br>FSMC (100- and 144-pin packages(3))</td><td colspan="2" rowspan="3">5 × USARTs<br>10 × 16-bit timers,<br>2 × basic timers<br>3 × SPIs, 2 × I2Ss, 2 × I2Cs<br>USB, CAN, 2 × PWM timers<br>3 × ADCs, 2 × DACs, 1 × SDIO, Cortex-M3 with MPU<br>FSMC (100- and 144-pin packages(4)), dual bank Flash memory</td></tr>
<tr><td>100</td><td colspan="2" rowspan="2">3 × USARTs<br>3 × 16-bit timers<br>2 × SPIs, 2 × I2Cs,<br>USB, CAN,<br>1 × PWM timer<br>2 × ADCs</td></tr>
<tr><td>64</td><td colspan="2" rowspan="3">2 × USARTs<br>2 × 16-bit timers<br>1 × SPI, 1 × I2C,<br>USB, CAN,<br>1 × PWM timer<br>2 × ADCs</td><td colspan="3" rowspan="2"></td></tr>
<tr><td>48</td><td colspan="2"></td></tr>
<tr><td>36</td><td colspan="5"></td></tr>
</table>

1. For orderable part numbers that do not show the A internal code after the temperature range code (6 or 7), the reference datasheet for electrical characteristics is that of the STM32F103x8/B medium-density devices.
2. 64 KB RAM for 256 KB Flash are available on devices delivered in CSP packages only.
3. Ports F and G are not available in devices delivered in 100-pin packages.
4. Ports F and G are not available in devices delivered in 100-pin packages.

## 2.3 Overview

### 2.3.1 ARM® Cortex®-M3 core with embedded Flash and SRAM

The ARM Cortex®-M3 processor is the latest generation of ARM processors for embedded systems. It has been developed to provide a low-cost platform that meets the needs of MCU implementation, with a reduced pin count and low-power consumption, while delivering outstanding computational performance and an advanced system response to interrupts.

The ARM Cortex®-M3 32-bit RISC processor features exceptional code-efficiency, delivering the high-performance expected from an ARM core in the memory size usually associated with 8- and 16-bit devices.

With its embedded ARM core, STM32F103xF and STM32F103xG performance line family is compatible with all ARM tools and software.

*Figure 1* shows the general block diagram of the device family.

### 2.3.2 Memory protection unit

The memory protection unit (MPU) is used to separate the processing of tasks from the data protection. The MPU can manage up to 8 protection areas that can all be further divided up into 8 subareas. The protection area sizes are between 32 bytes and the whole 4 gigabytes of addressable memory.

The memory protection unit is especially helpful for applications where some critical or certified code has to be protected against the misbehavior of other tasks. It is usually managed by an RTOS (real-time operating system). If a program accesses a memory location that is prohibited by the MPU, the RTOS can detect it and take action. In an RTOS environment, the kernel can dynamically update the MPU area setting, based on the process to be executed.

The MPU is optional and can be bypassed for applications that do not need it.

### 2.3.3 Embedded Flash memory

768 Kbytes to 1 Mbyte of embedded Flash are available for storing programs and data. The Flash memory is organized as two banks. The first bank has a size of 512 Kbytes. The second bank is either 256 or 512 Kbytes depending on the device. This gives the device the capability of writing to one bank while executing code from the other bank (read-while-write capability).

### 2.3.4 CRC (cyclic redundancy check) calculation unit

The CRC (cyclic redundancy check) calculation unit is used to get a CRC code from a 32-bit data word and a fixed generator polynomial.

Among other applications, CRC-based techniques are used to verify data transmission or storage integrity. In the scope of the EN/IEC 60335-1 standard, they offer a means of verifying the Flash memory integrity. The CRC calculation unit helps compute a signature of the software during runtime, to be compared with a reference signature generated at link-time and stored at a given memory location.

### 2.3.5 Embedded SRAM

96 Kbytes of embedded SRAM accessed (read/write) at CPU clock speed with 0 wait states.

### 2.3.6 FSMC (flexible static memory controller)

The FSMC is embedded in the STM32F103xF and STM32F103xG performance line family. It has four Chip Select outputs supporting the following modes: PC Card/Compact Flash, SRAM, PSRAM, NOR and NAND.

Functionality overview:

- The three FSMC interrupt lines are ORed in order to be connected to the NVIC
- Write FIFO
- Code execution from external memory except for NAND Flash and PC Card
- The targeted frequency, $f_{CLK}$, is HCLK/2, so external access is at 36 MHz when HCLK is at 72 MHz and external access is at 24 MHz when HCLK is at 48 MHz

### 2.3.7 LCD parallel interface

The FSMC can be configured to interface seamlessly with most graphic LCD controllers. It supports the Intel 8080 and Motorola 6800 modes, and is flexible enough to adapt to specific LCD interfaces. This LCD parallel interface capability makes it easy to build cost-effective graphic applications using LCD modules with embedded controllers or high-performance solutions using external controllers with dedicated acceleration.

### 2.3.8 Nested vectored interrupt controller (NVIC)

The STM32F103xF and STM32F103xG performance line embeds a nested vectored interrupt controller able to handle up to 60 maskable interrupt channels (not including the 16 interrupt lines of Cortex®-M3) and 16 priority levels.

- Closely coupled NVIC gives low latency interrupt processing
- Interrupt entry vector table address passed directly to the core
- Closely coupled NVIC core interface
- Allows early processing of interrupts
- Processing of *late arriving* higher priority interrupts
- Support for tail-chaining
- Processor state automatically saved
- Interrupt entry restored on interrupt exit with no instruction overhead

This hardware block provides flexible interrupt management features with minimal interrupt latency.

### 2.3.9 External interrupt/event controller (EXTI)

The external interrupt/event controller consists of 19 edge detector lines used to generate interrupt/event requests. Each line can be independently configured to select the trigger event (rising edge, falling edge, both) and can be masked independently. A pending register maintains the status of the interrupt requests. The EXTI can detect an external line with a pulse width shorter than the Internal APB2 clock period. Up to 112 GPIOs can be connected to the 16 external interrupt lines.

### 2.3.10 Clocks and startup

System clock selection is performed on startup, however the internal RC 8 MHz oscillator is selected as default CPU clock on reset. An external 4-16 MHz clock can be selected, in which case it is monitored for failure. If failure is detected, the system automatically switches back to the internal RC oscillator. A software interrupt is generated if enabled. Similarly, full interrupt management of the PLL clock entry is available when necessary (for example with failure of an indirectly used external oscillator).

Several prescalers allow the configuration of the AHB frequency, the high speed APB (APB2) and the low speed APB (APB1) domains. The maximum frequency of the AHB and the high speed APB domains is 72 MHz. The maximum allowed frequency of the low speed APB domain is 36 MHz. See *Figure 2* for details on the clock tree.

### 2.3.11 Boot modes

At startup, boot pins are used to select one of three boot options:

- Boot from user Flash: you have an option to boot from any of two memory banks. By default, boot from Flash memory bank 1 is selected. You can choose to boot from Flash memory bank 2 by setting a bit in the option bytes.
- Boot from system memory
- Boot from embedded SRAM

The boot loader is located in system memory. It is used to reprogram the Flash memory by using USART1.

### 2.3.12 Power supply schemes

- $V_{DD}$ = 2.0 to 3.6 V: external power supply for I/Os and the internal regulator. Provided externally through $V_{DD}$ pins.
- $V_{SSA}$, $V_{DDA}$ = 2.0 to 3.6 V: external analog power supplies for ADC, DAC, Reset blocks, RCs and PLL (minimum voltage to be applied to VDDA is 2.4 V when the ADC or DAC is used). $V_{DDA}$ and $V_{SSA}$ must be connected to $V_{DD}$ and $V_{SS}$, respectively.
- $V_{BAT}$ = 1.8 to 3.6 V: power supply for RTC, external clock 32 kHz oscillator and backup registers (through power switch) when $V_{DD}$ is not present.

For more details on how to connect power pins, refer to *Figure 10: Power supply scheme*.

### 2.3.13 Power supply supervisor

The device has an integrated power-on reset (POR)/power-down reset (PDR) circuitry. It is always active, and ensures proper operation starting from/down to 2 V. The device remains in reset mode when $V_{DD}$ is below a specified threshold, $V_{POR/PDR}$, without the need for an external reset circuit.

The device features an embedded programmable voltage detector (PVD) that monitors the $V_{DD}/V_{DDA}$ power supply and compares it to the $V_{PVD}$ threshold. An interrupt can be generated when $V_{DD}/V_{DDA}$ drops below the $V_{PVD}$ threshold and/or when $V_{DD}/V_{DDA}$ is higher than the $V_{PVD}$ threshold. The interrupt service routine can then generate a warning message and/or put the MCU into a safe state. The PVD is enabled by software. Refer to *Table 12: Embedded reset and power control block characteristics* for the values of $V_{POR/PDR}$ and $V_{PVD}$.

### 2.3.14 Voltage regulator

The regulator has three operation modes: main (MR), low-power (LPR) and power down.

- MR is used in the nominal regulation mode (Run)
- LPR is used in the Stop modes.
- Power down is used in Standby mode: the regulator output is in high impedance: the kernel circuitry is powered down, inducing zero consumption (but the contents of the registers and SRAM are lost)

This regulator is always enabled after reset. It is disabled in Standby mode.

### 2.3.15 Low-power modes

The STM32F103xF and STM32F103xG performance line supports three low-power modes to achieve the best compromise between low-power consumption, short startup time and available wakeup sources:

- **Sleep** mode

  In Sleep mode, only the CPU is stopped. All peripherals continue to operate and can wake up the CPU when an interrupt/event occurs.

- **Stop** mode

  Stop mode achieves the lowest power consumption while retaining the content of SRAM and registers. All clocks in the 1.8 V domain are stopped, the PLL, the HSI RC and the HSE crystal oscillators are disabled. The voltage regulator can also be put either in normal or in low-power mode.
  The device can be woken up from Stop mode by any of the EXTI line. The EXTI line source can be one of the 16 external lines, the PVD output, the RTC alarm or the USB wakeup.

- **Standby** mode

  The Standby mode is used to achieve the lowest power consumption. The internal voltage regulator is switched off so that the entire 1.8 V domain is powered off. The PLL, the HSI RC and the HSE crystal oscillators are also switched off. After entering Standby mode, SRAM and register contents are lost except for registers in the Backup domain and Standby circuitry.

  The device exits Standby mode when an external reset (NRST pin), an IWDG reset, a rising edge on the WKUP pin, or an RTC alarm occurs.

*Note: The RTC, the IWDG, and the corresponding clock sources are not stopped by entering Stop or Standby mode.*

### 2.3.16 DMA

The flexible 12-channel general-purpose DMAs (7 channels for DMA1 and 5 channels for DMA2) are able to manage memory-to-memory, peripheral-to-memory and memory-to-peripheral transfers. The two DMA controllers support circular buffer management, removing the need for user code intervention when the controller reaches the end of the buffer.

Each channel is connected to dedicated hardware DMA requests, with support for software trigger on each channel. Configuration is made by software and transfer sizes between source and destination are independent.

The DMA can be used with the main peripherals: SPI, $I^2C$, USART, general-purpose, basic and advanced-control timers TIMx, DAC, $I^2S$, SDIO and ADC.

### 2.3.17 RTC (real-time clock) and backup registers

The RTC and the backup registers are supplied through a switch that takes power either on $V_{DD}$ supply when present or through the $V_{BAT}$ pin. The backup registers are forty-two 16-bit registers used to store 84 bytes of user application data when $V_{DD}$ power is not present. They are not reset by a system or power reset, and they are not reset when the device wakes up from the Standby mode.

The real-time clock provides a set of continuously running counters which can be used with suitable software to provide a clock calendar function, and provides an alarm interrupt and a periodic interrupt. It is clocked by a 32.768 kHz external crystal, resonator or oscillator, the internal low-power RC oscillator or the high-speed external clock divided by 128. The internal low-speed RC has a typical frequency of 40 kHz. The RTC can be calibrated using an external 512 Hz output to compensate for any natural quartz deviation. The RTC features a 32-bit programmable counter for long term measurement using the Compare register to generate an alarm. A 20-bit prescaler is used for the time base clock and is by default configured to generate a time base of 1 second from a clock at 32.768 kHz.

### 2.3.18 Timers and watchdogs

The XL-density STM32F103xF/G performance line devices include up to two advanced-control timers, up to ten general-purpose timers, two basic timers, two watchdog timers and a SysTick timer.

*Table 4* compares the features of the advanced-control, general-purpose and basic timers.

**Table 4. STM32F103xF and STM32F103xG timer feature comparison**

| Timer | Counter resolution | Counter type | Prescaler factor | DMA request generation | Capture/compare channels | Complementary outputs |
|---|---|---|---|---|---|---|
| TIM1, TIM8 | 16-bit | Up, down, up/down | Any integer between 1 and 65536 | Yes | 4 | Yes |
| TIM2, TIM3, TIM4, TIM5 | 16-bit | Up, down, up/down | Any integer between 1 and 65536 | Yes | 4 | No |
| TIM9, TIM12 | 16-bit | Up | Any integer between 1 and 65536 | No | 2 | No |
| TIM10, TIM11 TIM13, TIM14 | 16-bit | Up | Any integer between 1 and 65536 | No | 1 | No |
| TIM6, TIM7 | 16-bit | Up | Any integer between 1 and 65536 | Yes | 0 | No |

### Advanced-control timers (TIM1 and TIM8)

The two advanced-control timers (TIM1 and TIM8) can each be seen as a three-phase PWM multiplexed on 6 channels. They have complementary PWM outputs with programmable inserted dead-times. They can also be seen as a complete general-purpose timer. The 4 independent channels can be used for:

- Input capture
- Output compare
- PWM generation (edge or center-aligned modes)
- One-pulse mode output

If configured as a standard 16-bit timer, it has the same features as the TIMx timer. If configured as the 16-bit PWM generator, it has full modulation capability (0-100%).

In debug mode, the advanced-control timer counter can be frozen and the PWM outputs disabled to turn off any power switch driven by these outputs.

Many features are shared with those of the general-purpose TIM timers which have the same architecture. The advanced-control timer can therefore work together with the TIM timers via the Timer Link feature for synchronization or event chaining.

### General-purpose timers (TIMx)

There are10 synchronizable general-purpose timers embedded in the STM32F103xF and STM32F103xG performance line devices (see *Table 4* for differences).

- **TIM2, TIM3, TIM4, TIM5**

  There are up to 4 synchronizable general-purpose timers (TIM2, TIM3, TIM4 and TIM5) embedded in the STM32F103xF and STM32F103xG access line devices.

  These timers are based on a 16-bit auto-reload up/down counter, a 16-bit prescaler and feature 4 independent channels each for input capture/output compare, PWM or one-pulse mode output. This gives up to 16 input captures / output compares / PWMs on the largest packages.

  Their counter can be frozen in debug mode. Any of the general-purpose timers can be used to generate PWM outputs. They all have independent DMA request generation.

  These timers are capable of handling quadrature (incremental) encoder signals and the digital outputs from 1 to 3 hall-effect sensors.

- **TIM10, TIM11 and TIM9**

  These timers are based on a 16-bit auto-reload upcounter and a 16-bit prescaler. TIM10 and TIM11 feature one independent channel, whereas TIM9 has two independent channels for input capture/output compare, PWM or one-pulse mode output. They can be synchronized with the TIM2, TIM3, TIM4, TIM5 full-featured general-purpose timers. They can also be used as simple time bases.

- **TIM13, TIM14 and TIM12**

  These timers are based on a 16-bit auto-reload upcounter and a 16-bit prescaler. TIM13 and TIM14 feature one independent channel, whereas TIM12 has two independent channels for input capture/output compare, PWM or one-pulse mode output. They can be synchronized with the TIM2, TIM3, TIM4, TIM5 full-featured general-purpose timers. They can also be used as simple time bases.

### Basic timers TIM6 and TIM7

These timers are mainly used for DAC trigger generation. They can also be used as a generic 16-bit time base.

### Independent watchdog

The independent watchdog is based on a 12-bit downcounter and 8-bit prescaler. It is clocked from an independent 40 kHz internal RC and as it operates independently from the main clock, it can operate in Stop and Standby modes. It can be used either as a watchdog to reset the device when a problem occurs, or as a free running timer for application timeout management. It is hardware or software configurable through the option bytes. The counter can be frozen in debug mode.

### Window watchdog

The window watchdog is based on a 7-bit downcounter that can be set as free running. It can be used as a watchdog to reset the device when a problem occurs. It is clocked from the main clock. It has an early warning interrupt capability and the counter can be frozen in debug mode.

### SysTick timer

This timer is dedicated to real-time operating systems, but could also be used as a standard down counter. It features:

- A 24-bit down counter
- Autoreload capability
- Maskable system interrupt generation when the counter reaches 0.
- Programmable clock source

## 2.3.19 I²C bus

Up to two I²C bus interfaces can operate in multimaster and slave modes. They can support standard and fast modes.

They support 7/10-bit addressing mode and 7-bit dual addressing mode (as slave). A hardware CRC generation/verification is embedded.

They can be served by DMA and they support SMBus 2.0/PMBus.

## 2.3.20 Universal synchronous/asynchronous receiver transmitters (USARTs)

The STM32F103xF and STM32F103xG performance line embeds three universal synchronous/asynchronous receiver transmitters (USART1, USART2 and USART3) and two universal asynchronous receiver transmitters (UART4 and UART5).

These five interfaces provide asynchronous communication, IrDA SIR ENDEC support, multiprocessor communication mode, single-wire half-duplex communication mode and have LIN Master/Slave capability.

The USART1 interface is able to communicate at speeds of up to 4.5 Mbit/s. The other available interfaces communicate at up to 2.25 Mbit/s.

USART1, USART2 and USART3 also provide hardware management of the CTS and RTS signals, Smart Card mode (ISO 7816 compliant) and SPI-like communication capability. All interfaces can be served by the DMA controller except for UART5.

### 2.3.21 Serial peripheral interface (SPI)

Up to three SPIs are able to communicate up to 18 Mbits/s in slave and master modes in full-duplex and simplex communication modes. The 3-bit prescaler gives 8 master mode frequencies and the frame is configurable to 8 bits or 16 bits. The hardware CRC generation/verification supports basic SD Card/MMC modes.

All SPIs can be served by the DMA controller.

### 2.3.22 Inter-integrated sound ($I^2S$)

Two standard $I^2S$ interfaces (multiplexed with SPI2 and SPI3) are available, that can be operated in master or slave mode. These interfaces can be configured to operate with 16/32 bit resolution, as input or output channels. Audio sampling frequencies from 8 kHz up to 48 kHz are supported. When either or both of the $I^2S$ interfaces is/are configured in master mode, the master clock can be output to the external DAC/CODEC at 256 times the sampling frequency.

### 2.3.23 SDIO

An SD/SDIO/MMC host interface is available, that supports MultiMediaCard System Specification Version 4.2 in three different databus modes: 1-bit (default), 4-bit and 8-bit. The interface allows data transfer at up to 48 MHz in 8-bit mode, and is compliant with SD Memory Card Specifications Version 2.0.
The SDIO Card Specification Version 2.0 is also supported with two different databus modes: 1-bit (default) and 4-bit.

The current version supports only one SD/SDIO/MMC4.2 card at any one time and a stack of MMC4.1 or previous.

In addition to SD/SDIO/MMC, this interface is also fully compliant with the CE-ATA digital protocol Rev1.1.

### 2.3.24 Controller area network (CAN)

The CAN is compliant with specifications 2.0A and B (active) with a bit rate up to 1 Mbit/s. It can receive and transmit standard frames with 11-bit identifiers as well as extended frames with 29-bit identifiers. It has three transmit mailboxes, two receive FIFOs with 3 stages and 14 scalable filter banks.

### 2.3.25 Universal serial bus (USB)

The STM32F103xF and STM32F103xG performance line embed a USB device peripheral compatible with the USB full-speed 12 Mbs. The USB interface implements a full-speed (12 Mbit/s) function interface. It has software-configurable endpoint setting and suspend/resume support. The dedicated 48 MHz clock is generated from the internal main PLL (the clock source must use a HSE crystal oscillator).

### 2.3.26 GPIOs (general-purpose inputs/outputs)

Each of the GPIO pins can be configured by software as output (push-pull or open-drain), as input (with or without pull-up or pull-down) or as peripheral alternate function. Most of the GPIO pins are shared with digital or analog alternate functions. All GPIOs are high current-capable.

The I/Os alternate function configuration can be locked if needed following a specific sequence in order to avoid spurious writing to the I/Os registers.

### 2.3.27 ADC (analog to digital converter)

Three 12-bit analog-to-digital converters are embedded into STM32F103xF and STM32F103xG performance line devices and each ADC shares up to 21 external channels, performing conversions in single-shot or scan modes. In scan mode, automatic conversion is performed on a selected group of analog inputs.

Additional logic functions embedded in the ADC interface allow:

- Simultaneous sample and hold
- Interleaved sample and hold
- Single shunt

The ADC can be served by the DMA controller.

An analog watchdog feature allows very precise monitoring of the converted voltage of one, some or all selected channels. An interrupt is generated when the converted voltage is outside the programmed thresholds.

The events generated by the general-purpose timers (TIMx) and the advanced-control timers (TIM1 and TIM8) can be internally connected to the ADC start trigger and injection trigger, respectively, to allow the application to synchronize A/D conversion and timers.

### 2.3.28 DAC (digital-to-analog converter)

The two 12-bit buffered DAC channels can be used to convert two digital signals into two analog voltage signal outputs. The chosen design structure is composed of integrated resistor strings and an amplifier in inverting configuration.

This dual digital Interface supports the following features:

- two DAC converters: one for each output channel
- 8-bit or 12-bit monotonic output
- left or right data alignment in 12-bit mode
- synchronized update capability
- noise-wave generation
- triangular-wave generation
- dual DAC channel independent or simultaneous conversions
- DMA capability for each channel
- external triggers for conversion
- input voltage reference $V_{REF+}$

Eight DAC trigger inputs are used in the STM32F103xF and STM32F103xG performance line family. The DAC channels are triggered through the timer update outputs that are also connected to different DMA channels.

### 2.3.29 Temperature sensor

The temperature sensor has to generate a voltage that varies linearly with temperature. The conversion range is between 2 V < $V_{DDA}$ < 3.6 V. The temperature sensor is internally connected to the ADC1_IN16 input channel which is used to convert the sensor output voltage into a digital value.

### 2.3.30 Serial wire JTAG debug port (SWJ-DP)

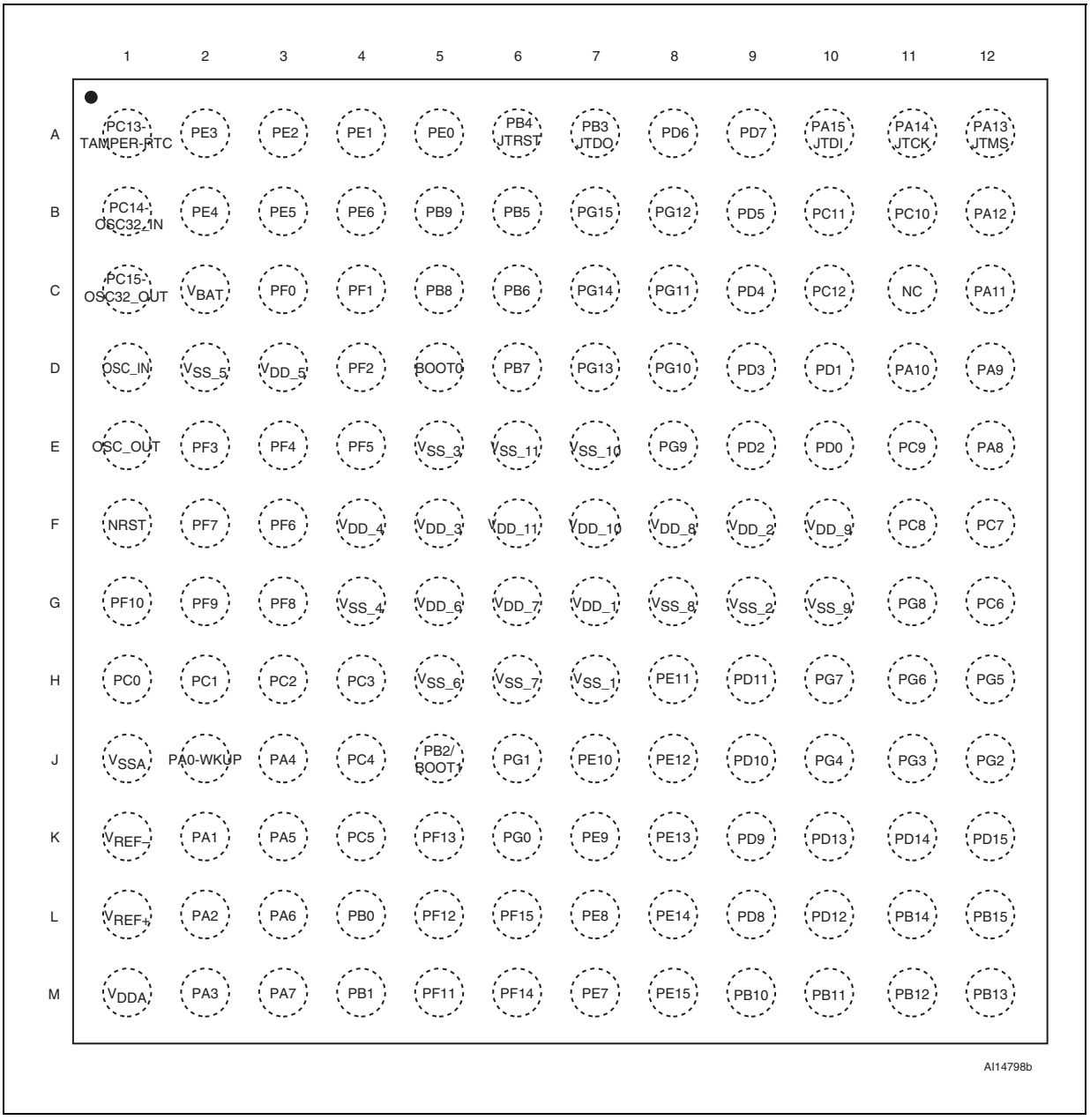
The ARM SWJ-DP Interface is embedded, and is a combined JTAG and serial wire debug port that enables either a serial wire debug or a JTAG probe to be connected to the target. The JTAG TMS and TCK pins are shared respectively with SWDIO and SWCLK and a specific sequence on the TMS pin is used to switch between JTAG-DP and SW-DP.

### 2.3.31 Embedded Trace Macrocell™

The ARM® Embedded Trace Macrocell provides a greater visibility of the instruction and data flow inside the CPU core by streaming compressed data at a very high rate from the STM32F10xxx through a small number of ETM pins to an external hardware trace port analyzer (TPA) device. The TPA is connected to a host computer using USB, Ethernet, or any other high-speed channel. Real-time instruction and data flow activity can be recorded and then formatted for display on the host computer running debugger software. TPA hardware is commercially available from common development tool vendors. It operates with third party debugger software tools.

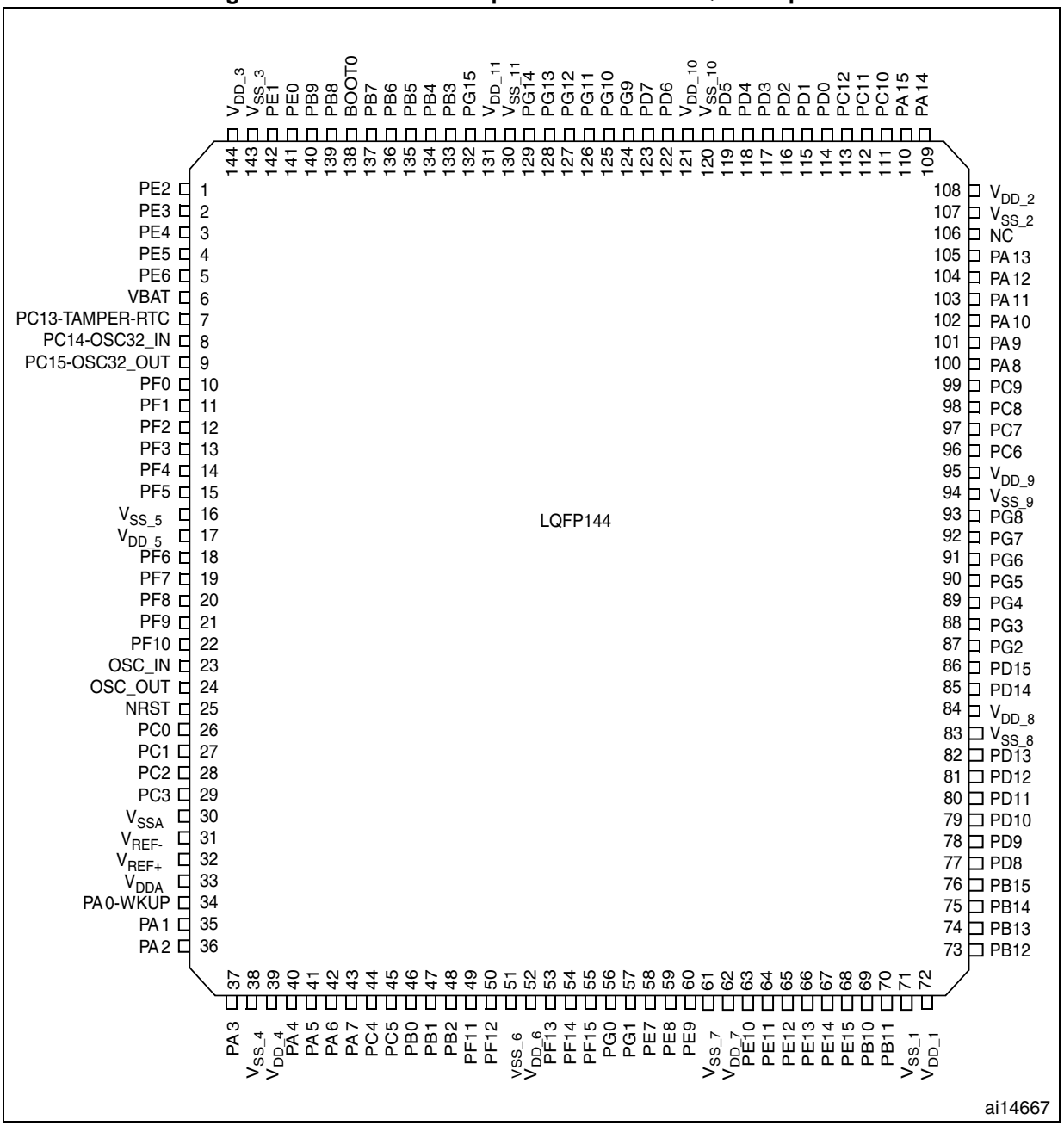
# 3 Pinouts and pin descriptions

**Figure 3. STM32F103xF/G BGA144 ballout**



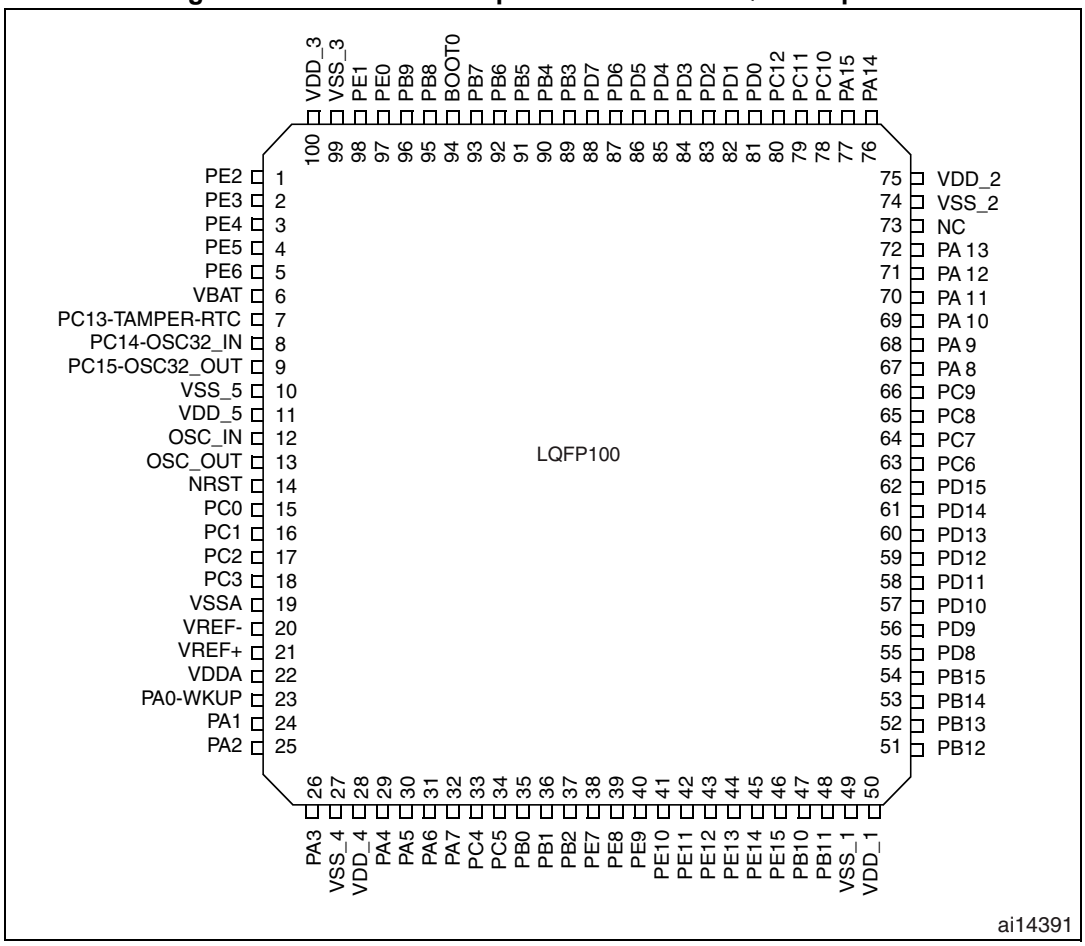

1. The above figure shows the package top view.

**Figure 4. STM32F103xF/G performance line LQFP144 pinout**



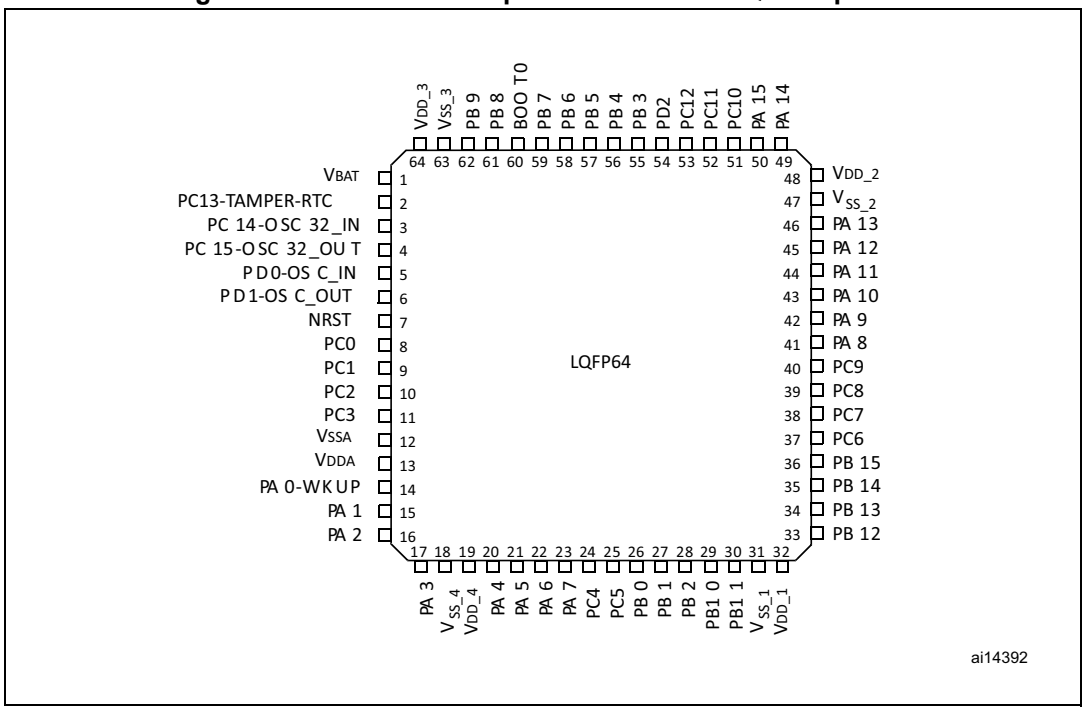

1. The above figure shows the package top view.

**Figure 5. STM32F103xF/G performance line LQFP100 pinout**




1. The above figure shows the package top view.

**Figure 6. STM32F103xF/G performance line LQFP64 pinout**




1. The above figure shows the package top view.

Table 5. STM32F103xF and STM32F103xG pin definitions

| Pins | | | | Pin name | Type(1) | I / O level(2) | Main function(3) (after reset) | Alternate functions(4) | |
|---|---|---|---|---|---|---|---|---|---|
| LFBGA144 | LQFP64 | LQFP100 | LQFP144 | | | | | Default | Remap |
| A3 | - | 1 | 1 | PE2 | I/O | FT | PE2 | TRACECK / FSMC_A23 | - |
| A2 | - | 2 | 2 | PE3 | I/O | FT | PE3 | TRACED0 / FSMC_A19 | - |
| B2 | - | 3 | 3 | PE4 | I/O | FT | PE4 | TRACED1/ FSMC_A20 | - |
| B3 | - | 4 | 4 | PE5 | I/O | FT | PE5 | TRACED2/ FSMC_A21 | TIM9_CH1 |
| B4 | - | 5 | 5 | PE6 | I/O | FT | PE6 | TRACED3 / FSMC_A22 | TIM9_CH2 |
| C2 | 1 | 6 | 6 | $V_{BAT}$ | S | | $V_{BAT}$ | - | - |
| A1 | 2 | 7 | 7 | PC13-TAMPER-RTC(5) | I/O | | PC13(6) | TAMPER-RTC | - |
| B1 | 3 | 8 | 8 | PC14-OSC32_IN(5) | I/O | | PC14(6) | OSC32_IN | - |
| C1 | 4 | 9 | 9 | PC15-OSC32_OUT(5) | I/O | | PC15(6) | OSC32_OUT | - |
| C3 | - | - | 10 | PF0 | I/O | FT | PF0 | FSMC_A0 | - |
| C4 | - | - | 11 | PF1 | I/O | FT | PF1 | FSMC_A1 | - |
| D4 | - | - | 12 | PF2 | I/O | FT | PF2 | FSMC_A2 | - |
| E2 | - | - | 13 | PF3 | I/O | FT | PF3 | FSMC_A3 | - |
| E3 | - | - | 14 | PF4 | I/O | FT | PF4 | FSMC_A4 | - |
| E4 | - | - | 15 | PF5 | I/O | FT | PF5 | FSMC_A5 | - |
| D2 | - | 10 | 16 | $V_{SS_5}$ | S | | $V_{SS_5}$ | - | - |
| D3 | - | 11 | 17 | $V_{DD_5}$ | S | | $V_{DD_5}$ | - | - |
| F3 | - | - | 18 | PF6 | I/O | | PF6 | ADC3_IN4 / FSMC_NIORD | TIM10_CH1 |
| F2 | - | - | 19 | PF7 | I/O | | PF7 | ADC3_IN5 / FSMC_NREG | TIM11_CH1 |
| G3 | - | - | 20 | PF8 | I/O | | PF8 | ADC3_IN6 / FSMC_NIOWR | TIM13_CH1 |
| G2 | - | - | 21 | PF9 | I/O | | PF9 | ADC3_IN7 / FSMC_CD | TIM14_CH1 |
| G1 | - | - | 22 | PF10 | I/O | | PF10 | ADC3_IN8 / FSMC_INTR | - |
| D1 | 5 | 12 | 23 | OSC_IN | I | | OSC_IN | - | PD0(7) |
| E1 | 6 | 13 | 24 | OSC_OUT | O | | OSC_OUT | - | PD1(7) |
| F1 | 7 | 14 | 25 | NRST | I/O | | NRST | - | - |
| H1 | 8 | 15 | 26 | PC0 | I/O | | PC0 | ADC123_IN10 | - |
| H2 | 9 | 16 | 27 | PC1 | I/O | | PC1 | ADC123_IN11 | - |

Table 5. STM32F103xF and STM32F103xG pin definitions (continued)

| Pins | | | | Pin name | Type(1) | I / O level(2) | Main function(3) (after reset) | Alternate functions(4) | |
|---|---|---|---|---|---|---|---|---|---|
| LFBGA144 | LQFP64 | LQFP100 | LQFP144 | | | | | Default | Remap |
| H3 | 10 | 17 | 28 | PC2 | I/O | | PC2 | ADC123_IN12 | - |
| H4 | 11 | 18 | 29 | PC3 | I/O | | PC3 | ADC123_IN13 | - |
| J1 | 12 | 19 | 30 | $V_{SSA}$ | S | | $V_{SSA}$ | - | - |
| K1 | - | 20 | 31 | $V_{REF-}$ | S | | $V_{REF-}$ | - | - |
| L1 | - | 21 | 32 | $V_{REF+}$ | S | | $V_{REF+}$ | - | - |
| M1 | 13 | 22 | 33 | $V_{DDA}$ | S | | $V_{DDA}$ | - | - |
| J2 | 14 | 23 | 34 | PA0-WKUP | I/O | | PA0 | WKUP/USART2_CTS(8) / ADC123_IN0 / TIM2_CH1_ETR / TIM5_CH1 / TIM8_ETR | - |
| K2 | 15 | 24 | 35 | PA1 | I/O | | PA1 | USART2_RTS(7) / ADC123_IN1 / TIM5_CH2 / TIM2_CH2(7) | - |
| L2 | 16 | 25 | 36 | PA2 | I/O | | PA2 | USART2_TX(7) / TIM5_CH3 / ADC123_IN2 / TIM9_CH1 / TIM2_CH3 (7) | - |
| M2 | 17 | 26 | 37 | PA3 | I/O | | PA3 | USART2_RX(7) / TIM5_CH4 / ADC123_IN3 / TIM2_CH4(7)/ TIM9_CH2 | - |
| G4 | 18 | 27 | 38 | $V_{SS_4}$ | S | | $V_{SS_4}$ | - | - |
| F4 | 19 | 28 | 39 | $V_{DD_4}$ | S | | $V_{DD_4}$ | - | - |
| J3 | 20 | 29 | 40 | PA4 | I/O | | PA4 | SPI1_NSS(7) / USART2_CK(7) / DAC_OUT1 / ADC12_IN4 | - |
| K3 | 21 | 30 | 41 | PA5 | I/O | | PA5 | SPI1_SCK(7) / DAC_OUT2 / ADC12_IN5 | - |
| L3 | 22 | 31 | 42 | PA6 | I/O | | PA6 | SPI1_MISO(7) / TIM8_BKIN / ADC12_IN6 / TIM3_CH1(7)/ TIM13_CH1 | TIM1_BKIN |
| M3 | 23 | 32 | 43 | PA7 | I/O | | PA7 | SPI1_MOSI(7)/ TIM8_CH1N / ADC12_IN7 / TIM3_CH2(7) / TIM14_CH1 | TIM1_CH1N |
| J4 | 24 | 33 | 44 | PC4 | I/O | | PC4 | ADC12_IN14 | - |
| K4 | 25 | 34 | 45 | PC5 | I/O | | PC5 | ADC12_IN15 | - |
| L4 | 26 | 35 | 46 | PB0 | I/O | | PB0 | ADC12_IN8 / TIM3_CH3 / TIM8_CH2N | TIM1_CH2N |

Table 5. STM32F103xF and STM32F103xG pin definitions (continued)

| Pins | | | | Pin name | Type(1) | I / O level(2) | Main function(3) (after reset) | Alternate functions(4) | |
|---|---|---|---|---|---|---|---|---|---|
| LFBGA144 | LQFP64 | LQFP100 | LQFP144 | | | | | Default | Remap |
| M4 | 27 | 36 | 47 | PB1 | I/O | | PB1 | ADC12_IN9 / TIM3_CH4(7) / TIM8_CH3N | TIM1_CH3N |
| J5 | 28 | 37 | 48 | PB2 | I/O | FT | PB2/BOOT1 | - | - |
| M5 | - | - | 49 | PF11 | I/O | FT | PF11 | FSMC_NIOS16 | - |
| L5 | - | - | 50 | PF12 | I/O | FT | PF12 | FSMC_A6 | - |
| H5 | - | - | 51 | $V_{SS_6}$ | S | | $V_{SS_6}$ | - | - |
| G5 | - | - | 52 | $V_{DD_6}$ | S | | $V_{DD_6}$ | - | - |
| K5 | - | - | 53 | PF13 | I/O | FT | PF13 | FSMC_A7 | - |
| M6 | - | - | 54 | PF14 | I/O | FT | PF14 | FSMC_A8 | - |
| L6 | - | - | 55 | PF15 | I/O | FT | PF15 | FSMC_A9 | - |
| K6 | - | - | 56 | PG0 | I/O | FT | PG0 | FSMC_A10 | - |
| J6 | - | - | 57 | PG1 | I/O | FT | PG1 | FSMC_A11 | - |
| M7 | - | 38 | 58 | PE7 | I/O | FT | PE7 | FSMC_D4 | TIM1_ETR |
| L7 | - | 39 | 59 | PE8 | I/O | FT | PE8 | FSMC_D5 | TIM1_CH1N |
| K7 | - | 40 | 60 | PE9 | I/O | FT | PE9 | FSMC_D6 | TIM1_CH1 |
| H6 | - | - | 61 | $V_{SS_7}$ | S | | $V_{SS_7}$ | - | - |
| G6 | - | - | 62 | $V_{DD_7}$ | S | | $V_{DD_7}$ | - | - |
| J7 | - | 41 | 63 | PE10 | I/O | FT | PE10 | FSMC_D7 | TIM1_CH2N |
| H8 | - | 42 | 64 | PE11 | I/O | FT | PE11 | FSMC_D8 | TIM1_CH2 |
| J8 | - | 43 | 65 | PE12 | I/O | FT | PE12 | FSMC_D9 | TIM1_CH3N |
| K8 | - | 44 | 66 | PE13 | I/O | FT | PE13 | FSMC_D10 | TIM1_CH3 |
| L8 | - | 45 | 67 | PE14 | I/O | FT | PE14 | FSMC_D11 | TIM1_CH4 |
| M8 | - | 46 | 68 | PE15 | I/O | FT | PE15 | FSMC_D12 | TIM1_BKIN |
| M9 | 29 | 47 | 69 | PB10 | I/O | FT | PB10 | I2C2_SCL / USART3_TX(7) | TIM2_CH3 |
| M10 | 30 | 48 | 70 | PB11 | I/O | FT | PB11 | I2C2_SDA / USART3_RX(7) | TIM2_CH4 |
| H7 | 31 | 49 | 71 | $V_{SS_1}$ | S | | $V_{SS_1}$ | - | - |
| G7 | 32 | 50 | 72 | $V_{DD_1}$ | S | | $V_{DD_1}$ | - | - |
| M11 | 33 | 51 | 73 | PB12 | I/O | FT | PB12 | SPI2_NSS / I2S2_WS / I2C2_SMBA / USART3_CK(7) / TIM1_BKIN(7) | - |

Table 5. STM32F103xF and STM32F103xG pin definitions (continued)

| Pins | | | | Pin name | Type(1) | I / O level(2) | Main function(3) (after reset) | Alternate functions(4) | |
|---|---|---|---|---|---|---|---|---|---|
| LFBGA144 | LQFP64 | LQFP100 | LQFP144 | | | | | Default | Remap |
| M12 | 34 | 52 | 74 | PB13 | I/O | FT | PB13 | SPI2_SCK / I2S2_CK / USART3_CTS(7) / TIM1_CH1N | - |
| L11 | 35 | 53 | 75 | PB14 | I/O | FT | PB14 | SPI2_MISO / TIM1_CH2N / USART3_RTS(7)/ TIM12_CH1 | - |
| L12 | 36 | 54 | 76 | PB15 | I/O | FT | PB15 | SPI2_MOSI / I2S2_SD / TIM1_CH3N(7) / TIM12_CH2 | - |
| L9 | - | 55 | 77 | PD8 | I/O | FT | PD8 | FSMC_D13 | USART3_TX |
| K9 | - | 56 | 78 | PD9 | I/O | FT | PD9 | FSMC_D14 | USART3_RX |
| J9 | - | 57 | 79 | PD10 | I/O | FT | PD10 | FSMC_D15 | USART3_CK |
| H9 | - | 58 | 80 | PD11 | I/O | FT | PD11 | FSMC_A16 | USART3_CTS |
| L10 | - | 59 | 81 | PD12 | I/O | FT | PD12 | FSMC_A17 | TIM4_CH1 / USART3_RTS |
| K10 | - | 60 | 82 | PD13 | I/O | FT | PD13 | FSMC_A18 | TIM4_CH2 |
| G8 | - | - | 83 | $V_{SS_8}$ | S | | $V_{SS_8}$ | - | - |
| F8 | - | - | 84 | $V_{DD_8}$ | S | | $V_{DD_8}$ | - | - |
| K11 | - | 61 | 85 | PD14 | I/O | FT | PD14 | FSMC_D0 | TIM4_CH3 |
| K12 | - | 62 | 86 | PD15 | I/O | FT | PD15 | FSMC_D1 | TIM4_CH4 |
| J12 | - | - | 87 | PG2 | I/O | FT | PG2 | FSMC_A12 | - |
| J11 | - | - | 88 | PG3 | I/O | FT | PG3 | FSMC_A13 | - |
| J10 | - | - | 89 | PG4 | I/O | FT | PG4 | FSMC_A14 | - |
| H12 | - | - | 90 | PG5 | I/O | FT | PG5 | FSMC_A15 | - |
| H11 | - | - | 91 | PG6 | I/O | FT | PG6 | FSMC_INT2 | - |
| H10 | - | - | 92 | PG7 | I/O | FT | PG7 | FSMC_INT3 | - |
| G11 | - | - | 93 | PG8 | I/O | FT | PG8 | - | - |
| G10 | - | - | 94 | $V_{SS_9}$ | S | | $V_{SS_9}$ | - | - |
| F10 | - | - | 95 | $V_{DD_9}$ | S | | $V_{DD_9}$ | - | - |
| G12 | 37 | 63 | 96 | PC6 | I/O | FT | PC6 | I2S2_MCK / TIM8_CH1 / SDIO_D6 | TIM3_CH1 |
| F12 | 38 | 64 | 97 | PC7 | I/O | FT | PC7 | I2S3_MCK / TIM8_CH2 / SDIO_D7 | TIM3_CH2 |
| F11 | 39 | 65 | 98 | PC8 | I/O | FT | PC8 | TIM8_CH3 / SDIO_D0 | TIM3_CH3 |

Table 5. STM32F103xF and STM32F103xG pin definitions (continued)

| Pins | | | | Pin name | Type(1) | I / O level(2) | Main function(3) (after reset) | Alternate functions(4) | |
|---|---|---|---|---|---|---|---|---|---|
| LFBGA144 | LQFP64 | LQFP100 | LQFP144 | | | | | Default | Remap |
| E11 | 40 | 66 | 99 | PC9 | I/O | FT | PC9 | TIM8_CH4 / SDIO_D1 | TIM3_CH4 |
| E12 | 41 | 67 | 100 | PA8 | I/O | FT | PA8 | USART1_CK / TIM1_CH1(7) / MCO | - |
| D12 | 42 | 68 | 101 | PA9 | I/O | FT | PA9 | USART1_TX(7) / TIM1_CH2(7) | - |
| D11 | 43 | 69 | 102 | PA10 | I/O | FT | PA10 | USART1_RX(7) / TIM1_CH3(7) | - |
| C12 | 44 | 70 | 103 | PA11 | I/O | FT | PA11 | USART1_CTS / USB_DM / CAN_RX(7) / TIM1_CH4(7) | - |
| B12 | 45 | 71 | 104 | PA12 | I/O | FT | PA12 | USART1_RTS / USB_DP / CAN_TX(7) / TIM1_ETR(7) | - |
| A12 | 46 | 72 | 105 | PA13 | I/O | FT | JTMS-SWDIO | - | PA13 |
| C11 | - | 73 | 106 | Not connected | | | | | |
| G9 | 47 | 74 | 107 | $V_{SS_2}$ | S | | $V_{SS_2}$ | - | - |
| F9 | 48 | 75 | 108 | $V_{DD_2}$ | S | | $V_{DD_2}$ | - | - |
| A11 | 49 | 76 | 109 | PA14 | I/O | FT | JTCK-SWCLK | - | PA14 |
| A10 | 50 | 77 | 110 | PA15 | I/O | FT | JTDI | SPI3_NSS / I2S3_WS | TIM2_CH1_ETR PA15/ SPI1_NSS |
| B11 | 51 | 78 | 111 | PC10 | I/O | FT | PC10 | UART4_TX / SDIO_D2 | USART3_TX |
| B10 | 52 | 79 | 112 | PC11 | I/O | FT | PC11 | UART4_RX / SDIO_D3 | USART3_RX |
| C10 | 53 | 80 | 113 | PC12 | I/O | FT | PC12 | UART5_TX / SDIO_CK | USART3_CK |
| E10 | - | 81 | 114 | PD0 | I/O | FT | PD0 | FSMC_D2(9) | CAN_RX |
| D10 | - | 82 | 115 | PD1 | I/O | FT | PD1 | FSMC_D3(9) | CAN_TX |
| E9 | 54 | 83 | 116 | PD2 | I/O | FT | PD2 | TIM3_ETR / UART5_RX / SDIO_CMD | - |
| D9 | - | 84 | 117 | PD3 | I/O | FT | PD3 | FSMC_CLK | USART2_CTS |
| C9 | - | 85 | 118 | PD4 | I/O | FT | PD4 | FSMC_NOE | USART2_RTS |
| B9 | - | 86 | 119 | PD5 | I/O | FT | PD5 | FSMC_NWE | USART2_TX |
| E7 | - | - | 120 | $V_{SS_10}$ | S | | $V_{SS_10}$ | - | - |
| F7 | - | - | 121 | $V_{DD_10}$ | S | | $V_{DD_10}$ | - | - |
| A8 | - | 87 | 122 | PD6 | I/O | FT | PD6 | FSMC_NWAIT | USART2_RX |

**Table 5. STM32F103xF and STM32F103xG pin definitions (continued)**

| Pins | | | | Pin name | Type(1) | I / O level(2) | Main function(3) (after reset) | Alternate functions(4) | |
|---|---|---|---|---|---|---|---|---|---|
| LFBGA144 | LQFP64 | LQFP100 | LQFP144 | | | | | Default | Remap |
| A9 | - | 88 | 123 | PD7 | I/O | FT | PD7 | FSMC_NE1 / FSMC_NCE2 | USART2_CK |
| E8 | - | - | 124 | PG9 | I/O | FT | PG9 | FSMC_NE2 / FSMC_NCE3 | - |
| D8 | - | - | 125 | PG10 | I/O | FT | PG10 | FSMC_NCE4_1 / FSMC_NE3 | - |
| C8 | - | - | 126 | PG11 | I/O | FT | PG11 | FSMC_NCE4_2 | - |
| B8 | - | - | 127 | PG12 | I/O | FT | PG12 | FSMC_NE4 | - |
| D7 | - | - | 128 | PG13 | I/O | FT | PG13 | FSMC_A24 | - |
| C7 | - | - | 129 | PG14 | I/O | FT | PG14 | FSMC_A25 | - |
| E6 | - | - | 130 | $V_{SS_11}$ | S | | $V_{SS_11}$ | - | - |
| F6 | - | - | 131 | $V_{DD_11}$ | S | | $V_{DD_11}$ | - | - |
| B7 | - | - | 132 | PG15 | I/O | FT | PG15 | - | - |
| A7 | 55 | 89 | 133 | PB3 | I/O | FT | JTDO | SPI3_SCK / I2S3_CK/ | PB3/TRACESWO TIM2_CH2 / SPI1_SCK |
| A6 | 56 | 90 | 134 | PB4 | I/O | FT | NJTRST | SPI3_MISO | PB4/ TIM3_CH1 SPI1_MISO |
| B6 | 57 | 91 | 135 | PB5 | I/O | | PB5 | I2C1_SMBA / SPI3_MOSI / I2S3_SD | TIM3_CH2 / SPI1_MOSI |
| C6 | 58 | 92 | 136 | PB6 | I/O | FT | PB6 | I2C1_SCL(8)/ TIM4_CH1(8) | USART1_TX |
| D6 | 59 | 93 | 137 | PB7 | I/O | FT | PB7 | I2C1_SDA(8) / FSMC_NADV / TIM4_CH2(8) | USART1_RX |
| D5 | 60 | 94 | 138 | BOOT0 | I | | BOOT0 | - | - |
| C5 | 61 | 95 | 139 | PB8 | I/O | FT | PB8 | TIM4_CH3(8) / SDIO_D4 / TIM10_CH1 | I2C1_SCL/ CAN_RX |
| B5 | 62 | 96 | 140 | PB9 | I/O | FT | PB9 | TIM4_CH4(8) / SDIO_D5 / TIM11_CH1 | I2C1_SDA / CAN_TX |
| A5 | - | 97 | 141 | PE0 | I/O | FT | PE0 | TIM4_ETR / FSMC_NBL0 | - |
| A4 | - | 98 | 142 | PE1 | I/O | FT | PE1 | FSMC_NBL1 | - |
| E5 | 63 | 99 | 143 | $V_{SS_3}$ | S | | $V_{SS_3}$ | - | - |
| F5 | 64 | 100 | 144 | $V_{DD_3}$ | S | | $V_{DD_3}$ | - | - |

1. I = input, O = output, S = supply.
2. FT = 5 V tolerant.
3. Function availability depends on the chosen device.

4. If several peripherals share the same I/O pin, to avoid conflict between these alternate functions only one peripheral should be enabled at a time through the peripheral clock enable bit (in the corresponding RCC peripheral clock enable register).
5. PC13, PC14 and PC15 are supplied through the power switch. Since the switch only sinks a limited amount of current (3 mA), the use of GPIOs PC13 to PC15 in output mode is limited: the speed should not exceed 2 MHz with a maximum load of 30 pF and these IOs must not be used as a current source (e.g. to drive an LED).
6. Main function after the first backup domain power-up. Later on, it depends on the contents of the Backup registers even after reset (because these registers are not reset by the main reset). For details on how to manage these IOs, refer to the Battery backup domain and BKP register description sections in the STM32F10xxx reference manual, available from the STMicroelectronics website: www.st.com.
7. For the LQFP64 package, the pins number 5 and 6 are configured as OSC_IN/OSC_OUT after reset, however the functionality of PD0 and PD1 can be remapped by software on these pins. For the LQFP100 and LQFP144/BGA144 packages, PD0 and PD1 are available by default, so there is no need for remapping. For more details, refer to Alternate function I/O and debug configuration section in the STM32F10xxx reference manual.
8. This alternate function can be remapped by software to some other port pins (if available on the used package). For more details, refer to the Alternate function I/O and debug configuration section in the STM32F10xxx reference manual, available from the STMicroelectronics website: www.st.com.
9. For devices delivered in LQFP64 packages, the FSMC function is not available.

Table 6. FSMC pin definition

| Pins | FSMC | | | | | LQFP100[1] |
|---|---|---|---|---|---|---|
| | CF | CF/IDE | NOR/PSRAM/ SRAM | NOR/PSRAM Mux | NAND 16 bit | |
| PE2 | - | - | A23 | A23 | - | Yes |
| PE3 | - | - | A19 | A19 | - | Yes |
| PE4 | - | - | A20 | A20 | - | Yes |
| PE5 | - | - | A21 | A21 | - | Yes |
| PE6 | - | - | A22 | A22 | - | Yes |
| PF0 | A0 | A0 | A0 | - | - | - |
| PF1 | A1 | A1 | A1 | - | - | - |
| PF2 | A2 | A2 | A2 | - | - | - |
| PF3 | A3 | - | A3 | - | - | - |
| PF4 | A4 | - | A4 | - | - | - |
| PF5 | A5 | - | A5 | - | - | - |
| PF6 | NIORD | NIORD | | - | - | - |
| PF7 | NREG | NREG | | - | - | - |
| PF8 | NIOWR | NIOWR | | - | - | - |
| PF9 | CD | CD | | - | - | - |
| PF10 | INTR | INTR | | - | - | - |
| PF11 | NIOS16 | NIOS16 | | - | - | - |
| PF12 | A6 | - | A6 | - | - | - |
| PF13 | A7 | - | A7 | - | - | - |
| PF14 | A8 | - | A8 | - | - | - |
| PF15 | A9 | - | A9 | - | - | - |
| PG0 | A10 | - | A10 | - | - | - |
| PG1 | - | - | A11 | - | - | - |
| PE7 | D4 | D4 | D4 | DA4 | D4 | Yes |
| PE8 | D5 | D5 | D5 | DA5 | D5 | Yes |
| PE9 | D6 | D6 | D6 | DA6 | D6 | Yes |
| PE10 | D7 | D7 | D7 | DA7 | D7 | Yes |
| PE11 | D8 | D8 | D8 | DA8 | D8 | Yes |
| PE12 | D9 | D9 | D9 | DA9 | D9 | Yes |
| PE13 | D10 | D10 | D10 | DA10 | D10 | Yes |
| PE14 | D11 | D11 | D11 | DA11 | D11 | Yes |
| PE15 | D12 | D12 | D12 | DA12 | D12 | Yes |
| PD8 | D13 | D13 | D13 | DA13 | D13 | Yes |

Table 6. FSMC pin definition (continued)

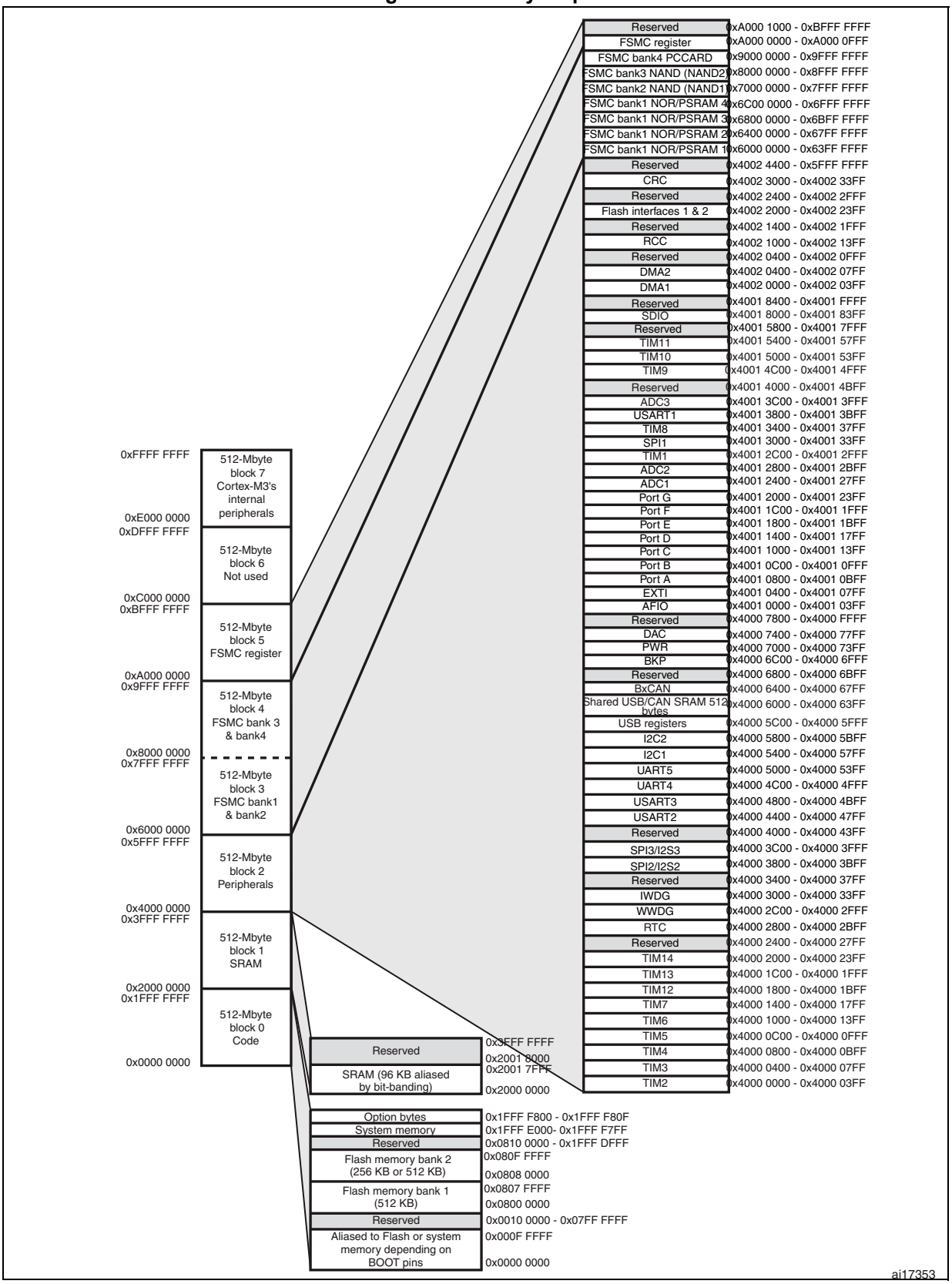
| Pins | FSMC | | | | | LQFP100[1] |
|---|---|---|---|---|---|---|
| | CF | CF/IDE | NOR/PSRAM/ SRAM | NOR/PSRAM Mux | NAND 16 bit | |
| PD9 | D14 | D14 | D14 | DA14 | D14 | Yes |
| PD10 | D15 | D15 | D15 | DA15 | D15 | Yes |
| PD11 | - | - | A16 | A16 | CLE | Yes |
| PD12 | - | - | A17 | A17 | ALE | Yes |
| PD13 | - | - | A18 | A18 | | Yes |
| PD14 | D0 | D0 | D0 | DA0 | D0 | Yes |
| PD15 | D1 | D1 | D1 | DA1 | D1 | Yes |
| PG2 | - | - | A12 | - | - | - |
| PG3 | - | - | A13 | - | - | - |
| PG4 | - | - | A14 | - | - | - |
| PG5 | - | - | A15 | - | - | - |
| PG6 | - | - | - | - | INT2 | - |
| PG7 | - | - | - | - | INT3 | - |
| PD0 | D2 | D2 | D2 | DA2 | D2 | Yes |
| PD1 | D3 | D3 | D3 | DA3 | D3 | Yes |
| PD3 | - | - | CLK | CLK | - | Yes |
| PD4 | NOE | NOE | NOE | NOE | NOE | Yes |
| PD5 | NWE | NWE | NWE | NWE | NWE | Yes |
| PD6 | NWAIT | NWAIT | NWAIT | NWAIT | NWAIT | Yes |
| PD7 | - | - | NE1 | NE1 | NCE2 | Yes |
| PG9 | - | - | NE2 | NE2 | NCE3 | - |
| PG10 | NCE4_1 | NCE4_1 | NE3 | NE3 | - | - |
| PG11 | NCE4_2 | NCE4_2 | - | - | - | - |
| PG12 | - | - | NE4 | NE4 | - | - |
| PG13 | - | - | A24 | A24 | - | - |
| PG14 | - | - | A25 | A25 | - | - |
| PB7 | - | - | NADV | NADV | - | Yes |
| PE0 | - | - | NBL0 | NBL0 | - | Yes |
| PE1 | - | - | NBL1 | NBL1 | - | Yes |

1. Ports F and G are not available in devices delivered in 100-pin packages.

# 4 Memory mapping

The memory map is shown in *Figure 7*.

**Figure 7. Memory map**



# 5 Electrical characteristics

## 5.1 Parameter conditions

Unless otherwise specified, all voltages are referenced to $V_{SS}$.

### 5.1.1 Minimum and maximum values

Unless otherwise specified the minimum and maximum values are guaranteed in the worst conditions of ambient temperature, supply voltage and frequencies by tests in production on 100% of the devices with an ambient temperature at $T_A$ = 25 °C and $T_A$ = $T_A$max (given by the selected temperature range).

Data based on characterization results, design simulation and/or technology characteristics are indicated in the table footnotes and are not tested in production. Based on characterization, the minimum and maximum values refer to sample tests and represent the mean value plus or minus three times the standard deviation (mean±3Σ).

### 5.1.2 Typical values

Unless otherwise specified, typical data are based on $T_A$ = 25 °C, $V_{DD}$ = 3.3 V (for the 2 V £ $V_{DD}$ £ 3.6 V voltage range). They are given only as design guidelines and are not tested.

Typical ADC accuracy values are determined by characterization of a batch of samples from a standard diffusion lot over the full temperature range, where 95% of the devices have an error less than or equal to the value indicated (mean±2Σ).

### 5.1.3 Typical curves

Unless otherwise specified, all typical curves are given only as design guidelines and are not tested.

### 5.1.4 Loading capacitor

The loading conditions used for pin parameter measurement are shown in *Figure 8*.

### 5.1.5 Pin input voltage

The input voltage measurement on a pin of the device is described in *Figure 9*.

**Figure 8. Pin loading conditions**

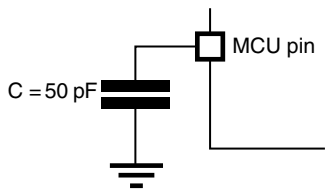
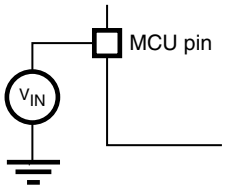
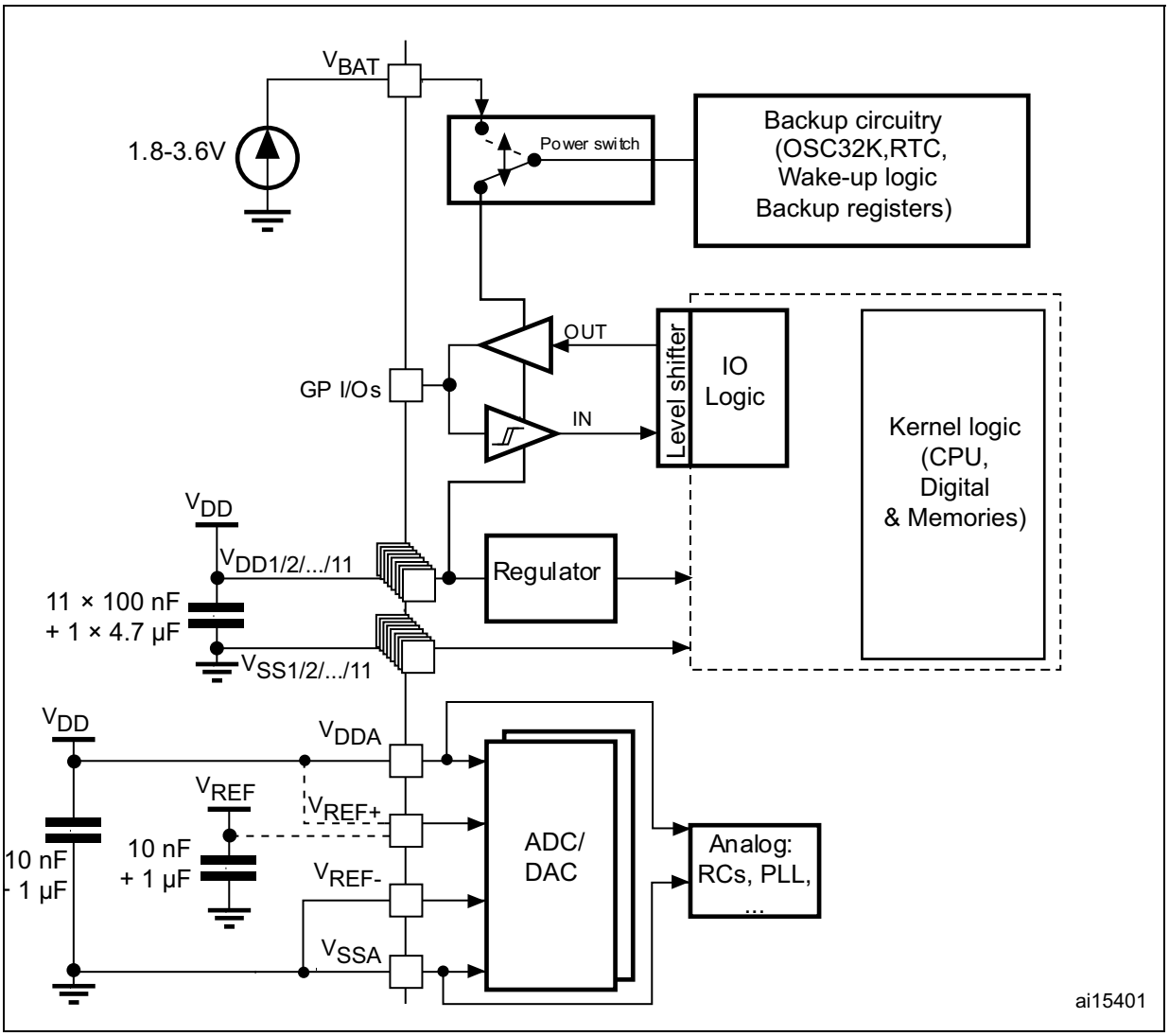



**Figure 9. Pin input voltage**



### 5.1.6 Power supply scheme

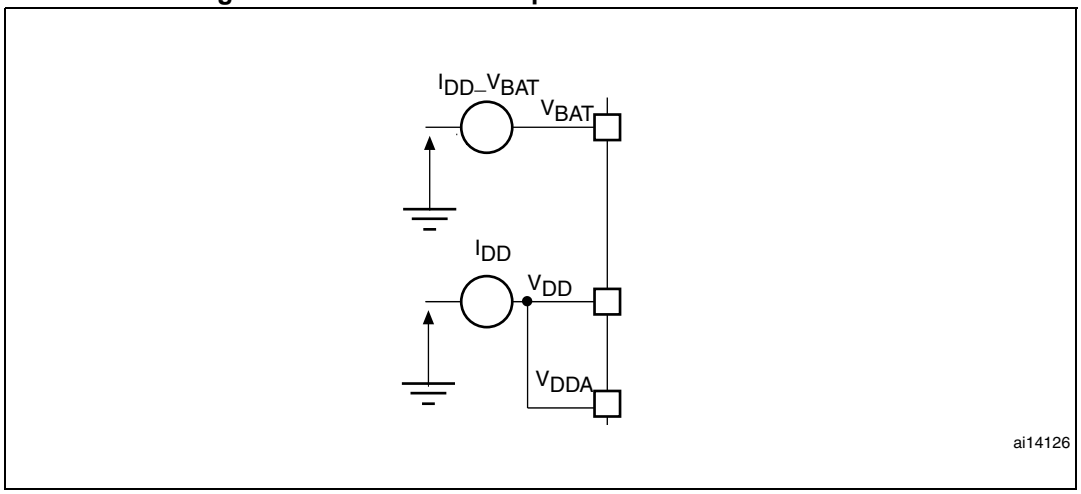
**Figure 10. Power supply scheme**




**Caution:** In *Figure 10*, the 4.7 µF capacitor must be connected to $V_{DD3}$.

### 5.1.7 Current consumption measurement

**Figure 11. Current consumption measurement scheme**



## 5.2 Absolute maximum ratings

Stresses above the absolute maximum ratings listed in *Table 7: Voltage characteristics*, *Table 8: Current characteristics*, and *Table 9: Thermal characteristics* may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these conditions is not implied. Exposure to maximum rating conditions for extended periods may affect device reliability.

**Table 7. Voltage characteristics**

| Symbol | Ratings | Min | Max | Unit |
|---|---|---|---|---|
| $V_{DD}$–$V_{SS}$ | External main supply voltage (including $V_{DDA}$ and $V_{DD}$)(1) | –0.3 | 4.0 | V |
| $V_{IN}$(2) | Input voltage on five volt tolerant pin | $V_{SS}$ – 0.3 | $V_{DD}$ + 4.0 | |
| | Input voltage on any other pin | $V_{SS}$ – 0.3 | 4.0 | |
| $\|\Delta V_{DDx}\|$ | Variations between different $V_{DD}$ power pins | - | 50 | mV |
| $\|V_{SSX} - V_{SS}\|$ | Variations between all the different ground pins | - | 50 | |
| $V_{ESD(HBM)}$ | Electrostatic discharge voltage (human body model) | see *Section 5.3.12: Absolute maximum ratings (electrical sensitivity)* | | |

1. All main power ($V_{DD}$, $V_{DDA}$) and ground ($V_{SS}$, $V_{SSA}$) pins must always be connected to the external power supply, in the permitted range.
2. $V_{IN}$ maximum must always be respected. Refer to *Table 8: Current characteristics* for the maximum allowed injected current values.

**Table 8. Current characteristics**

| Symbol | Ratings | Max. | Unit |
|---|---|---|---|
| $I_{VDD}$ | Total current into $V_{DD}$/$V_{DDA}$ power lines (source)(1) | 150 | mA |
| $I_{VSS}$ | Total current out of $V_{SS}$ ground lines (sink)(1) | 150 | |
| $I_{IO}$ | Output current sunk by any I/O and control pin | 25 | |
| | Output current source by any I/Os and control pin | – 25 | |
| $I_{INJ(PIN)}$(2) | Injected current on five volt tolerant pins(3) | -5/+0 | |
| | Injected current on any other pin(4) | ± 5 | |
| $\Sigma I_{INJ(PIN)}$ | Total injected current (sum of all I/O and control pins)(5) | ± 25 | |

1. All main power ($V_{DD}$, $V_{DDA}$) and ground ($V_{SS}$, $V_{SSA}$) pins must always be connected to the external power supply, in the permitted range.
2. Negative injection disturbs the analog performance of the device. See note 3 below *Table 65 on page 110*.
3. Positive injection is not possible on these I/Os. A negative injection is induced by $V_{IN}<V_{SS}$. $I_{INJ(PIN)}$ must never be exceeded. Refer to *Table 7: Voltage characteristics* for the maximum allowed input voltage values.
4. A positive injection is induced by $V_{IN}>V_{DD}$ while a negative injection is induced by $V_{IN}<V_{SS}$. $I_{INJ(PIN)}$ must never be exceeded. Refer to *Table 7: Voltage characteristics* for the maximum allowed input voltage values.
5. When several inputs are submitted to a current injection, the maximum $\Sigma I_{INJ(PIN)}$ is the absolute sum of the positive and negative injected currents (instantaneous values).

**Table 9. Thermal characteristics**

| Symbol | Ratings | Value | Unit |
|---|---|---|---|
| $T_{STG}$ | Storage temperature range | –65 to +150 | °C |
| $T_J$ | Maximum junction temperature | 150 | °C |

## 5.3 Operating conditions

### 5.3.1 General operating conditions

**Table 10. General operating conditions**

| Symbol | Parameter | Conditions | Min | Max | Unit |
|---|---|---|---|---|---|
| $f_{HCLK}$ | Internal AHB clock frequency | - | 0 | 72 | MHz |
| $f_{PCLK1}$ | Internal APB1 clock frequency | - | 0 | 36 | |
| $f_{PCLK2}$ | Internal APB2 clock frequency | - | 0 | 72 | |
| $V_{DD}$ | Standard operating voltage | - | 2 | 3.6 | V |
| $V_{DDA}$(1) | Analog operating voltage (ADC not used) | Must be the same potential as $V_{DD}$(2) | 2 | 3.6 | V |
| | Analog operating voltage (ADC used) | | 2.4 | 3.6 | |
| $V_{BAT}$ | Backup operating voltage | - | 1.8 | 3.6 | V |
| $P_D$ | Power dissipation at $T_A$ = 85 °C for suffix 6 or $T_A$ = 105 °C for suffix 7(3) | LQFP144 | - | 666 | mW |
| | | LQFP100 | - | 434 | |
| | | LQFP64 | - | 444 | |
| | | LFBGA144 | - | 500 | |
| $T_A$ | Ambient temperature for 6 suffix version | Maximum power dissipation | –40 | 85 | °C |
| | | Low-power dissipation(4) | –40 | 105 | |
| | Ambient temperature for 7 suffix version | Maximum power dissipation | –40 | 105 | °C |
| | | Low-power dissipation(4) | –40 | 125 | |
| $T_J$ | Junction temperature range | 6 suffix version | –40 | 105 | °C |
| | | 7 suffix version | –40 | 125 | |

1. When the ADC is used, refer to *Table 62: ADC characteristics*.
2. It is recommended to power $V_{DD}$ and $V_{DDA}$ from the same source. A maximum difference of 300 mV between $V_{DD}$ and $V_{DDA}$ can be tolerated during power-up and operation.
3. If $T_A$ is lower, higher $P_D$ values are allowed as long as $T_J$ does not exceed $T_J$max (see *Table 6.5: Thermal characteristics on page 129*).
4. In low-power dissipation state, $T_A$ can be extended to this range as long as $T_J$ does not exceed $T_J$max (see *Table 6.5: Thermal characteristics on page 129*).

### 5.3.2 Operating conditions at power-up / power-down

The parameters given in *Table 11* are derived from tests performed under the ambient temperature condition summarized in *Table 10*.

**Table 11. Operating conditions at power-up / power-down**

| Symbol | Parameter | Conditions | Min | Max | Unit |
|---|---|---|---|---|---|
| $t_{VDD}$ | $V_{DD}$ rise time rate | - | 0 | ¥ | µs/V |
| | $V_{DD}$ fall time rate | | 20 | ¥ | |

### 5.3.3 Embedded reset and power control block characteristics

The parameters given in *Table 12* are derived from tests performed under ambient temperature and $V_{DD}$ supply voltage conditions summarized in *Table 10*.

**Table 12. Embedded reset and power control block characteristics**

| Symbol | Parameter | Conditions | Min | Typ | Max | Unit |
|---|---|---|---|---|---|---|
| $V_{PVD}$ | Programmable voltage detector level selection | PLS[2:0]=000 (rising edge) | 2.1 | 2.18 | 2.26 | V |
| | | PLS[2:0]=000 (falling edge) | 2 | 2.08 | 2.16 | V |
| | | PLS[2:0]=001 (rising edge) | 2.19 | 2.28 | 2.37 | V |
| | | PLS[2:0]=001 (falling edge) | 2.09 | 2.18 | 2.27 | V |
| | | PLS[2:0]=010 (rising edge) | 2.28 | 2.38 | 2.48 | V |
| | | PLS[2:0]=010 (falling edge) | 2.18 | 2.28 | 2.38 | V |
| | | PLS[2:0]=011 (rising edge) | 2.38 | 2.48 | 2.58 | V |
| | | PLS[2:0]=011 (falling edge) | 2.28 | 2.38 | 2.48 | V |
| | | PLS[2:0]=100 (rising edge) | 2.47 | 2.58 | 2.69 | V |
| | | PLS[2:0]=100 (falling edge) | 2.37 | 2.48 | 2.59 | V |
| | | PLS[2:0]=101 (rising edge) | 2.57 | 2.68 | 2.79 | V |
| | | PLS[2:0]=101 (falling edge) | 2.47 | 2.58 | 2.69 | V |
| | | PLS[2:0]=110 (rising edge) | 2.66 | 2.78 | 2.9 | V |
| | | PLS[2:0]=110 (falling edge) | 2.56 | 2.68 | 2.8 | V |
| | | PLS[2:0]=111 (rising edge) | 2.76 | 2.88 | 3 | V |
| | | PLS[2:0]=111 (falling edge) | 2.66 | 2.78 | 2.9 | V |
| $V_{PVDhyst}$(2) | PVD hysteresis | - | - | 100 | - | mV |
| $V_{POR/PDR}$ | Power on/power down reset threshold | Falling edge | 1.8(1) | 1.88 | 1.96 | V |
| | | Rising edge | 1.84 | 1.92 | 2.0 | V |
| $V_{PDRhyst}$(2) | PDR hysteresis | - | - | 40 | - | mV |
| $T_{RSTTEMPO}$(2) | Reset temporization | - | 1 | 2.5 | 4.5 | mS |

1. The product behavior is guaranteed by design down to the minimum $V_{POR/PDR}$ value.
2. Guaranteed by design, not tested in production.

### 5.3.4 Embedded reference voltage

The parameters given in *Table 13* are derived from tests performed under ambient temperature and $V_{DD}$ supply voltage conditions summarized in *Table 10*.

**Table 13. Embedded internal reference voltage**

| Symbol | Parameter | Conditions | Min | Typ | Max | Unit |
|---|---|---|---|---|---|---|
| $V_{REFINT}$ | Internal reference voltage | –40 °C < $T_A$ < +105 °C | 1.16 | 1.20 | 1.26 | V |
| | | –40 °C < $T_A$ < +85 °C | 1.16 | 1.20 | 1.24 | V |
| $T_{S_vrefint}$(1) | ADC sampling time when reading the internal reference voltage | - | - | 5.1 | 17.1(2) | µs |
| $V_{RERINT}$(2) | Internal reference voltage spread over the temperature range | $V_{DD}$ = 3 V ±10 mV | - | - | 10 | mV |
| $T_{Coeff}$(2) | Temperature coefficient | - | - | - | 100 | ppm/°C |

1. Shortest sampling time can be determined in the application by multiple iterations.
2. Guaranteed by design, not tested in production.

### 5.3.5 Supply current characteristics

The current consumption is a function of several parameters and factors such as the operating voltage, ambient temperature, I/O pin loading, device software configuration, operating frequencies, I/O pin switching rate, program location in memory and executed binary code.
The current consumption is measured as described in *Figure 11: Current consumption measurement scheme*.
All Run-mode current consumption measurements given in this section are performed with a reduced code that gives a consumption equivalent to Dhrystone 2.1 code.

#### Maximum current consumption

The MCU is placed under the following conditions:

- All I/O pins are in input mode with a static value at $V_{DD}$ or $V_{SS}$ (no load)
- All peripherals are disabled except when explicitly mentioned
- The Flash memory access time is adjusted to the $f_{HCLK}$ frequency (0 wait state from 0 to 24 MHz, 1 wait state from 24 to 48 MHz and 2 wait states above)
- Prefetch in ON (reminder: this bit must be set before clock setting and bus prescaling)
- When the peripherals are enabled $f_{PCLK1} = f_{HCLK}/2$, $f_{PCLK2} = f_{HCLK}$

The parameters given in *Table 14*, *Table 15* and *Table 16* are derived from tests performed under ambient temperature and $V_{DD}$ supply voltage conditions summarized in *Table 10*.

**Table 14. Maximum current consumption in Run mode, code with data processing running from Flash**

| Symbol | Parameter | Conditions | $f_{HCLK}$ | Max(1) | | Unit |
|---|---|---|---|---|---|---|
| | | | | $T_A$ = 85 °C | $T_A$ = 105 °C | |
| $I_{DD}$ | Supply current in Run mode | External clock(2), all peripherals enabled | 72 MHz | 68 | 69 | mA |
| | | | 48 MHz | 51 | 51 | |
| | | | 36 MHz | 41 | 41 | |
| | | | 24 MHz | 29 | 30 | |
| | | | 16 MHz | 22 | 22.5 | |
| | | | 8 MHz | 12.5 | 14 | |
| | | External clock(2), all peripherals disabled | 72 MHz | 39 | 39 | |
| | | | 48 MHz | 29.5 | 30 | |
| | | | 36 MHz | 24 | 24.5 | |
| | | | 24 MHz | 17.5 | 19 | |
| | | | 16 MHz | 14 | 15 | |
| | | | 8 MHz | 8.5 | 10.5 | |

1. Guaranteed by characterization results, not tested in production.
2. External clock is 8 MHz and PLL is on when $f_{HCLK}$ > 8 MHz.

**Table 15. Maximum current consumption in Run mode, code with data processing running from RAM**

| Symbol | Parameter | Conditions | $f_{HCLK}$ | Max(1) | | Unit |
|---|---|---|---|---|---|---|
| | | | | $T_A$ = 85 °C | $T_A$ = 105 °C | |
| $I_{DD}$ | Supply current in Run mode | External clock(2), all peripherals enabled | 72 MHz | 65 | 65.5 | mA |
| | | | 48 MHz | 46.5 | 47 | |
| | | | 36 MHz | 37 | 37 | |
| | | | 24 MHz | 26.5 | 27 | |
| | | | 16 MHz | 19 | 20 | |
| | | | 8 MHz | 11.5 | 13 | |
| | | External clock(2), all peripherals disabled | 72 MHz | 34.5 | 36 | |
| | | | 48 MHz | 25 | 26 | |
| | | | 36 MHz | 20.5 | 21 | |
| | | | 24 MHz | 15 | 16 | |
| | | | 16 MHz | 11 | 13 | |
| | | | 8 MHz | 7.5 | 9 | |

1. Guaranteed by characterization results, not tested in production at $V_{DD}$ max, $f_{HCLK}$ max.
2. External clock is 8 MHz and PLL is on when $f_{HCLK}$ > 8 MHz.

**Figure 12. Typical current consumption in Run mode versus frequency (at 3.6 V) - code with data processing running from RAM, peripherals enabled**

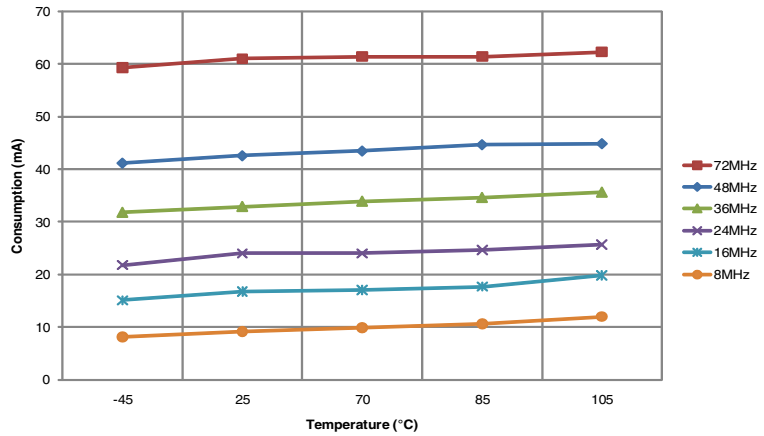



**Figure 13. Typical current consumption in Run mode versus frequency (at 3.6 V)- code with data processing running from RAM, peripherals disabled**

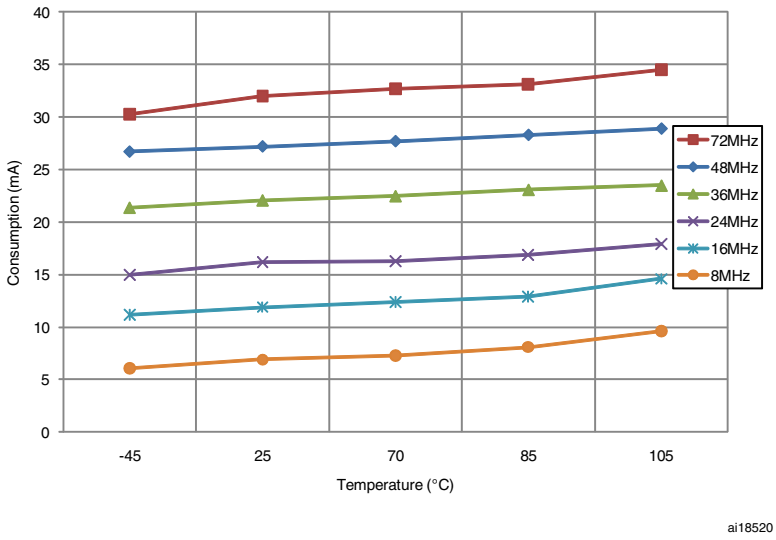


**Table 16. Maximum current consumption in Sleep mode, code running from Flash or RAM**

| Symbol | Parameter | Conditions | $f_{HCLK}$ | Max(1) | | Unit |
|---|---|---|---|---|---|---|
| | | | | $T_A$ = 85 °C | $T_A$ = 105 °C | |
| $I_{DD}$ | Supply current in Sleep mode | External clock(2), all peripherals enabled | 72 MHz | 47.5 | 48.5 | mA |
| | | | 48 MHz | 34 | 35 | |
| | | | 36 MHz | 27.5 | 27.5 | |
| | | | 24 MHz | 20 | 20.5 | |
| | | | 16 MHz | 15 | 16 | |
| | | | 8 MHz | 9 | 11 | |
| | | External clock(2), all peripherals disabled | 72 MHz | 9.5 | 11.2 | |
| | | | 48 MHz | 7.7 | 9.5 | |
| | | | 36 MHz | 6.9 | 8.5 | |
| | | | 24 MHz | 5.9 | 7.8 | |
| | | | 16 MHz | 5.4 | 7.2 | |
| | | | 8 MHz | 4.7 | 6.4 | |

1. Guaranteed by characterization results, not tested in production at $V_{DD}$ max, $f_{HCLK}$ max with peripherals enabled.
2. External clock is 8 MHz and PLL is on when $f_{HCLK}$ > 8 MHz.

**Table 17. Typical and maximum current consumptions in Stop and Standby modes**

| Symbol | Parameter | Conditions | Typ(1) | | | Max | | Unit |
|---|---|---|---|---|---|---|---|---|
| | | | $V_{DD}/V_{BAT}$ = 2.0 V | $V_{DD}/V_{BAT}$ = 2.4 V | $V_{DD}/V_{BAT}$ = 3.3 V | $T_A$ = 85 °C | $T_A$ = 105 °C | |
| $I_{DD}$ | Supply current in Stop mode | Regulator in run mode, low-speed and high-speed internal RC oscillators and high-speed oscillator OFF (no independent watchdog), $f_{CK}$=8 MHz | 44.8 | 45.3 | 46.4 | 810 | 1680 | µA |
| | | Regulator in low-power mode, low-speed and high-speed internal RC oscillators and high-speed oscillator OFF (no independent watchdog) | 37.4 | 37.8 | 38.7 | 790 | 1660 | |
| | Supply current in Standby mode | Low-speed internal RC oscillator and independent watchdog OFF, low-speed oscillator and RTC OFF | 1.8 | 2.0 | 2.5 | 5(2) | 8(2) | |
| $I_{DD_VBAT}$ | Backup domain supply current | Low-speed oscillator and RTC ON | 1.05 | 1.1 | 1.4 | 2(2) | 2.3(2) | |

1. Typical values are measured at $T_A$ = 25 °C.
2. Guaranteed by characterization results, not tested in production..

**Figure 14. Typical current consumption on $V_{BAT}$ with RTC on vs. temperature at different $V_{BAT}$ values**

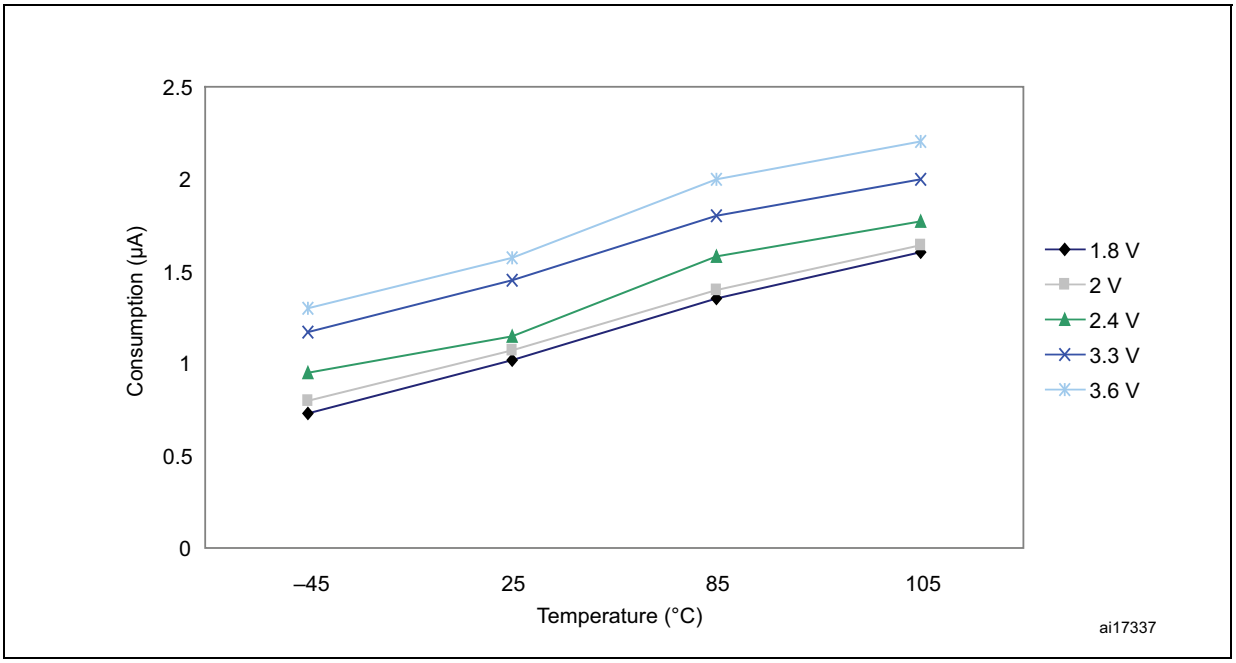


**Figure 15. Typical current consumption in Stop mode with regulator in run mode versus temperature at different $V_{DD}$ values**

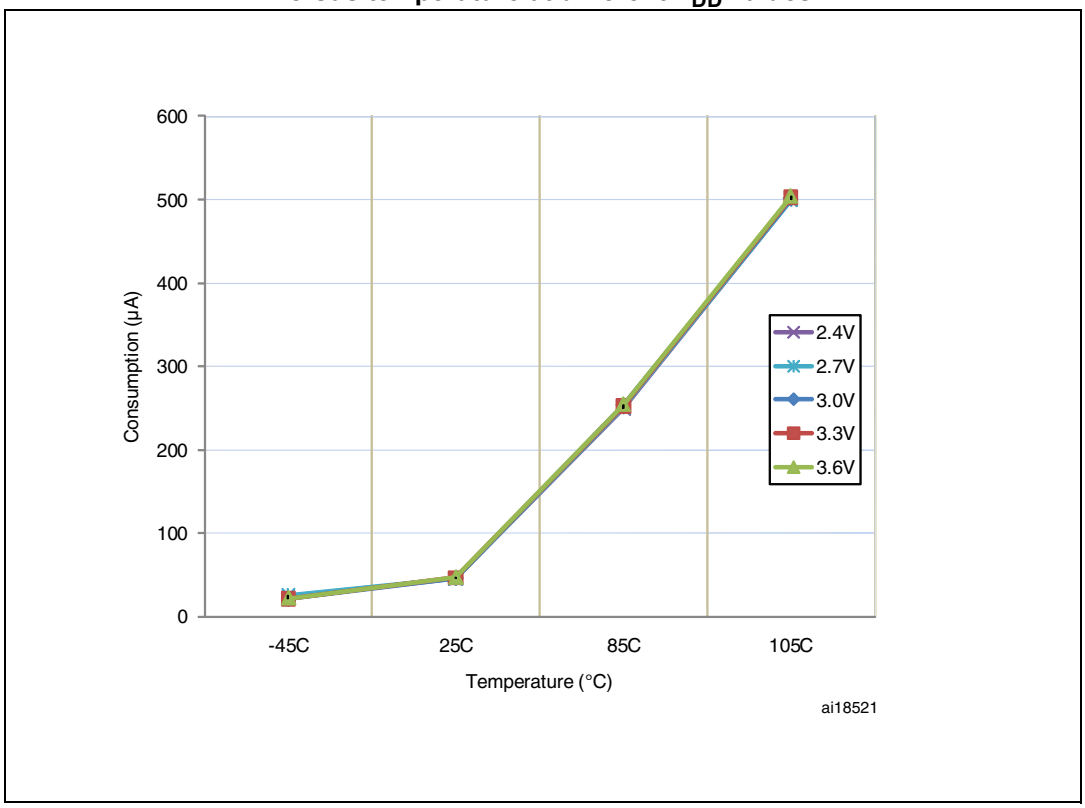


**Figure 16. Typical current consumption in Stop mode with regulator in low-power mode versus temperature at different $V_{DD}$ values**

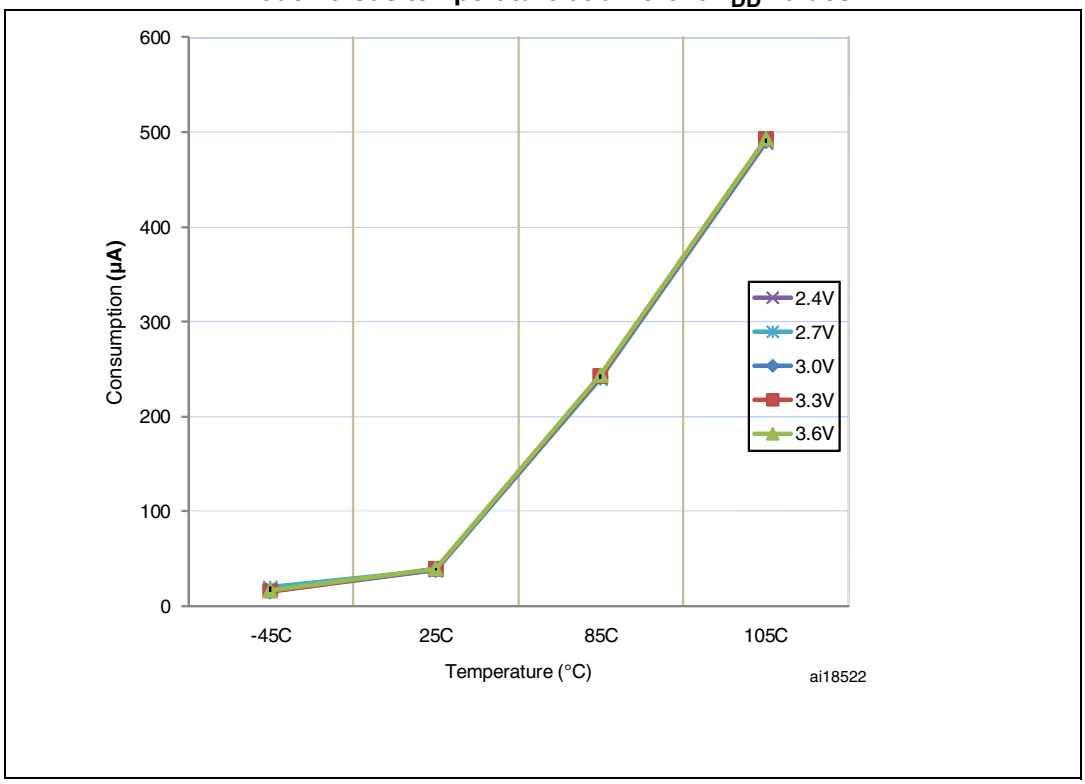
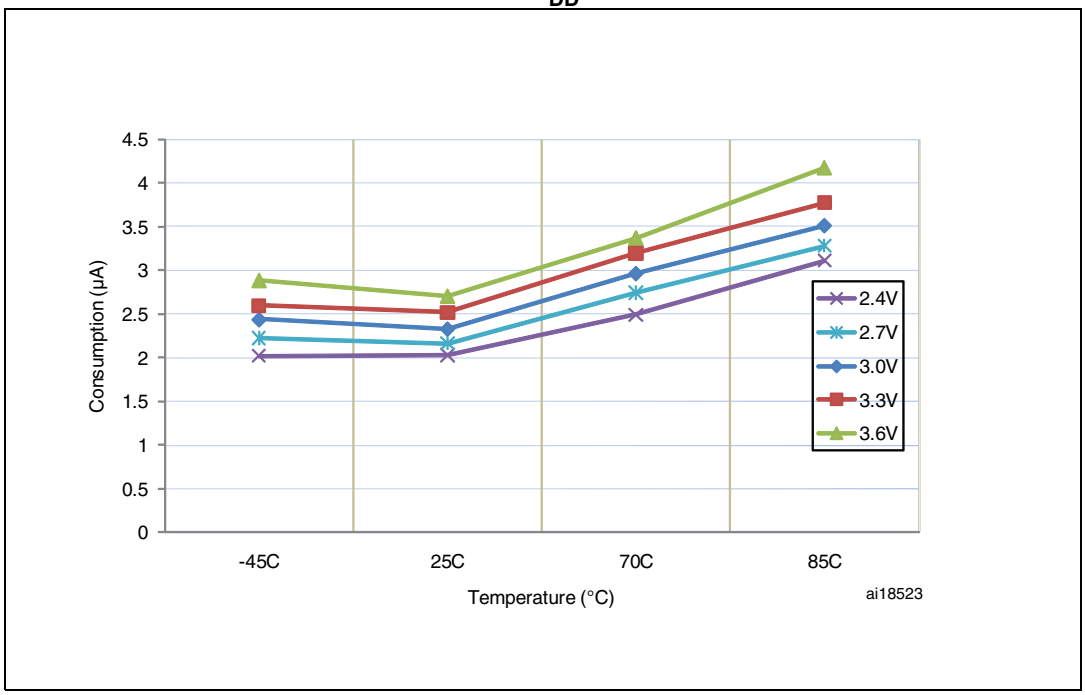



**Figure 17. Typical current consumption in Standby mode versus temperature at different $V_{DD}$ values**



### Typical current consumption

The MCU is placed under the following conditions:

- All I/O pins are in input mode with a static value at $V_{DD}$ or $V_{SS}$ (no load).
- All peripherals are disabled except if it is explicitly mentioned.
- The Flash access time is adjusted to $f_{HCLK}$ frequency (0 wait state from 0 to 24 MHz, 1 wait state from 24 to 48 MHZ and 2 wait states above).
- Ambient temperature and $V_{DD}$ supply voltage conditions summarized in *Table 10*.
- Prefetch is ON (Reminder: this bit must be set before clock setting and bus prescaling)

When the peripherals are enabled $f_{PCLK1} = f_{HCLK}/4$, $f_{PCLK}2 = f_{HCLK}/2$, $f_{ADCCLK} = f_{PCLK2}/4$

**Table 18. Typical current consumption in Run mode, code with data processing running from Flash**

| Symbol | Parameter | Conditions | $f_{HCLK}$ | Typ(1) | | Unit |
|---|---|---|---|---|---|---|
| | | | | All peripherals enabled(2) | All peripherals disabled | |
| $I_{DD}$ | Supply current in Run mode | External clock(3) | 72 MHz | 52.5 | 33.5 | mA |
| | | | 48 MHz | 36.6 | 23.8 | |
| | | | 36 MHz | 28.5 | 18.7 | |
| | | | 24 MHz | 24.1 | 12.8 | |
| | | | 16 MHz | 14 | 9.2 | |
| | | | 8 MHz | 7.7 | 5.4 | |
| | | | 4 MHz | 4.6 | 3.4 | |
| | | | 2 MHz | 3 | 2.3 | |
| | | | 1 MHz | 2.2 | 1.8 | |
| | | | 500 kHz | 1.7 | 1.5 | |
| | | | 125 kHz | 1.4 | 1.3 | |
| | | Running on high speed internal RC (HSI), AHB prescaler used to reduce the frequency | 64 MHz | 45.5 | 28.6 | mA |
| | | | 48 MHz | 35.1 | 22.4 | |
| | | | 36 MHz | 27.5 | 17.5 | |
| | | | 24 MHz | 18.9 | 11.6 | |
| | | | 16 MHz | 12.2 | 8.2 | |
| | | | 8 MHz | 7.2 | 4.8 | |
| | | | 4 MHz | 4 | 2.7 | |
| | | | 2 MHz | 2.3 | 1.7 | |
| | | | 1 MHz | 1.5 | 1.2 | |
| | | | 500 kHz | 1.1 | 0.9 | |
| | | | 125 kHz | 0.75 | 0.7 | |

1. Typical values are measures at $T_A$ = 25 °C, $V_{DD}$ = 3.3 V.
2. Add an additional power consumption of 0.8 mA per ADC for the analog part. In applications, this consumption occurs only while the ADC is on (ADON bit is set in the ADC_CR2 register).
3. External clock is 8 MHz and PLL is on when $f_{HCLK}$ > 8 MHz.

**Table 19. Typical current consumption in Sleep mode, code running from Flash or RAM**

| Symbol | Parameter | Conditions | $f_{HCLK}$ | Typ(1) | | Unit |
|---|---|---|---|---|---|---|
| | | | | All peripherals enabled(2) | All peripherals disabled | |
| $I_{DD}$ | Supply current in Sleep mode | External clock(3) | 72 MHz | 32.5 | 7 | mA |
| | | | 48 MHz | 23 | 5 | |
| | | | 36 MHz | 17.7 | 4 | |
| | | | 24 MHz | 12.2 | 3.1 | |
| | | | 16 MHz | 8.4 | 2.3 | |
| | | | 8 MHz | 4.6 | 1.5 | |
| | | | 4 MHz | 3 | 1.3 | |
| | | | 2 MHz | 2.15 | 1.25 | |
| | | | 1 MHz | 1.7 | 1.2 | |
| | | | 500 kHz | 1.5 | 1.15 | |
| | | | 125 kHz | 1.35 | 1.15 | |
| | | Running on high speed internal RC (HSI), AHB prescaler used to reduce the frequency | 64 MHz | 28.7 | 5.7 | |
| | | | 48 MHz | 22 | 4.4 | |
| | | | 36 MHz | 17 | 3.35 | |
| | | | 24 MHz | 11.6 | 2.3 | |
| | | | 16 MHz | 7.7 | 1.6 | |
| | | | 8 MHz | 3.9 | 0.8 | |
| | | | 4 MHz | 2.3 | 0.7 | |
| | | | 2 MHz | 1.5 | 0.6 | |
| | | | 1 MHz | 1.1 | 0.5 | |
| | | | 500 kHz | 0.9 | 0.5 | |
| | | | 125 kHz | 0.7 | 0.5 | |

1. Typical values are measures at $T_A$ = 25 °C, $V_{DD}$ = 3.3 V.
2. Add an additional power consumption of 0.8 mA per ADC for the analog part. In applications, this consumption occurs only while the ADC is on (ADON bit is set in the ADC_CR2 register).
3. External clock is 8 MHz and PLL is on when $f_{HCLK}$ > 8 MHz.

### On-chip peripheral current consumption

The current consumption of the on-chip peripherals is given in *Table 20*. The MCU is placed under the following conditions:

- all I/O pins are in input mode with a static value at $V_{DD}$ or $V_{SS}$ (no load)
- all peripherals are disabled unless otherwise mentioned
- the given value is calculated by measuring the current consumption
  - with all peripherals clocked off
  - with only one peripheral clocked on
- ambient operating temperature and $V_{DD}$ supply voltage conditions summarized in *Table 7*

**Table 20. Peripheral current consumption(1)**

| Peripheral | | Current consumption |
|---|---|---|
| AHB (up to 72 MHz) | DMA1 | 23,06 |
| | DMA2 | 18,47 |
| | FSMC | 55,14 |
| | CRC | 2,08 |
| | SDIO | 32,22 |
| | BusMatrix(2) | 11,67 |

**Table 20. Peripheral current consumption(1) (continued)**

| Peripheral | | Current consumption |
|---|---|---|
| APB1 (up to 36 MHz) | APB1-Bridge | 8,61 |
| | TIM2 | 37,22 |
| | TIM3 | 36,39 |
| | TIM4 | 35,56 |
| | TIM5 | 33,61 |
| | TIM6 | 7,78 |
| | TIM7 | 7,78 |
| | TIM12 | 19,17 |
| | TIM13 | 12,22 |
| | TIM14 | 13,33 |
| | SPI2/I2S2(3) | 8,33 |
| | SPI3/I2S3(3) | 8,33 |
| | USART2 | 12,22 |
| | USART3 | 12,22 |
| | UART4 | 12,22 |
| | UART5 | 12,22 |
| | I2C1 | 10,28 |
| | I2C2 | 10,28 |
| | USB | 18,89 |
| | CAN1 | 18,89 |
| | DAC(4) | 9,17 |
| | WWDG | 3,06 |
| | PWR | 2,50 |
| | BKP | 2,78 |
| | IWDG | 4,44 |

**Table 20. Peripheral current consumption(1) (continued)**

| Peripheral | | Current consumption |
|---|---|---|
| APB2 (up to 72 MHz) | APB2-Bridge | 2,78 |
| | GPIOA | 7,64 |
| | GPIOB | 7,64 |
| | GPIOC | 7,64 |
| | GPIOD | 8,47 |
| | GPIOE | 8,47 |
| | GPIOF | 8,19 |
| | GPIOG | 8,19 |
| | SPI1 | 5,14 |
| | USART1 | 16,67 |
| | TIM1 | 28,47 |
| | TIM8 | 24,31 |
| | TIM9 | 11,81 |
| | TIM10 | 8,47 |
| | TIM11 | 8,47 |
| | ADC1(5)(6) | 17,68 |
| | ADC2(5)(6) | 15,54 |
| | ADC3(5)(6) | 16,43 |

1. $f_{HCLK}$ = 72 MHz, $f_{APB1} = f_{HCLK}/2$, $f_{APB2} = f_{HCLK}$, default prescaler value for each peripheral.
2. The BusMatrix is automatically active when at least one master peripheral is ON.
3. When the I2S is enabled, a current consumption equal to 0.02 mA must be added.
4. When DAC_OU1 or DAC_OUT2 is enabled, a current consumption equal to 0.36 mA must be added.
5. Specific conditions for ADC: $f_{HCLK}$ = 56 MHz, $f_{APB1} = f_{HCLK/2}$, $f_{APB2} = f_{HCLK}$, $f_{ADCCLK} = f_{APB2}/4$/ When ADON bit in the ADC_CR2 register is set to 1, a current consumption equal to 0.59 mA must be added.
6. When the ADC is enabled, a current consumption equal to 0.1 mA must be added.

## 5.3.6 External clock source characteristics

### High-speed external user clock generated from an external source

The characteristics given in *Table 21* result from tests performed using an high-speed external clock source, and under ambient temperature and supply voltage conditions summarized in *Table 10*.

**Table 21. High-speed external user clock characteristics**

| Symbol | Parameter | Conditions | Min | Typ | Max | Unit |
|---|---|---|---|---|---|---|
| $f_{HSE_ext}$ | User external clock source frequency(1) | - | 1 | 8 | 25 | MHz |
| $V_{HSEH}$ | OSC_IN input pin high level voltage | | $0.7V_{DD}$ | - | $V_{DD}$ | V |
| $V_{HSEL}$ | OSC_IN input pin low level voltage | | $V_{SS}$ | - | $0.3V_{DD}$ | |
| $t_{w(HSE)}$ $t_{w(HSE)}$ | OSC_IN high or low time(1) | | 5 | - | - | ns |
| $t_{r(HSE)}$ $t_{f(HSE)}$ | OSC_IN rise or fall time(1) | | - | - | 20 | |
| $C_{in(HSE)}$ | OSC_IN input capacitance(1) | - | - | 5 | - | pF |
| $DuCy_{(HSE)}$ | Duty cycle | - | 45 | - | 55 | % |
| $I_L$ | OSC_IN Input leakage current | $V_{SS} \le V_{IN} \le V_{DD}$ | - | - | ±1 | µA |

1. Guaranteed by design, not tested in production.

### Low-speed external user clock generated from an external source

The characteristics given in *Table 22* result from tests performed using an low-speed external clock source, and under ambient temperature and supply voltage conditions summarized in *Table 10*.

**Table 22. Low-speed external user clock characteristics**

| Symbol | Parameter | Conditions | Min | Typ | Max | Unit |
|---|---|---|---|---|---|---|
| $f_{LSE_ext}$ | User External clock source frequency(1) | - | - | 32.768 | 1000 | kHz |
| $V_{LSEH}$ | OSC32_IN input pin high level voltage | | $0.7V_{DD}$ | - | $V_{DD}$ | V |
| $V_{LSEL}$ | OSC32_IN input pin low level voltage | | $V_{SS}$ | - | $0.3V_{DD}$ | |
| $t_{w(LSE)}$ $t_{w(LSE)}$ | OSC32_IN high or low time(1) | | 450 | - | - | ns |
| $t_{r(LSE)}$ $t_{f(LSE)}$ | OSC32_IN rise or fall time(1) | | - | - | 50 | |
| $C_{in(LSE)}$ | OSC32_IN input capacitance(1) | - | - | 5 | - | pF |
| $DuCy_{(LSE)}$ | Duty cycle | - | 30 | - | 70 | % |
| $I_L$ | OSC32_IN Input leakage current | $V_{SS} \le V_{IN} \le V_{DD}$ | - | - | ±1 | µA |

1. Guaranteed by design, not tested in production.

**Figure 18. High-speed external clock source AC timing diagram**

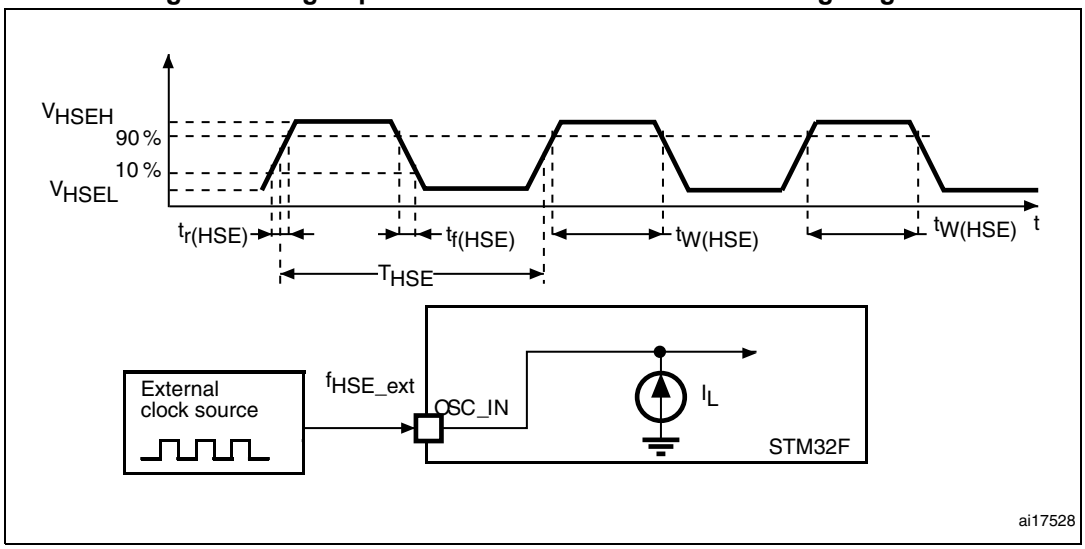
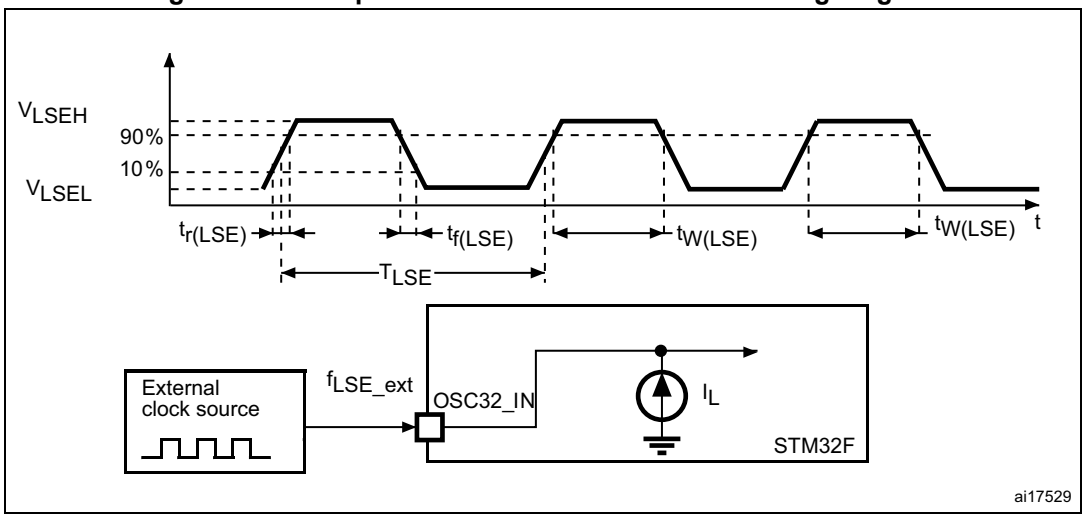



**Figure 19. Low-speed external clock source AC timing diagram**



### High-speed external clock generated from a crystal/ceramic resonator

The high-speed external (HSE) clock can be supplied with a 4 to 16 MHz crystal/ceramic resonator oscillator. All the information given in this paragraph are based on characterization results obtained with typical external components specified in *Table 23*. In the application, the resonator and the load capacitors have to be placed as close as possible to the oscillator pins in order to minimize output distortion and startup stabilization time. Refer to the crystal resonator manufacturer for more details on the resonator characteristics (frequency, package, accuracy).

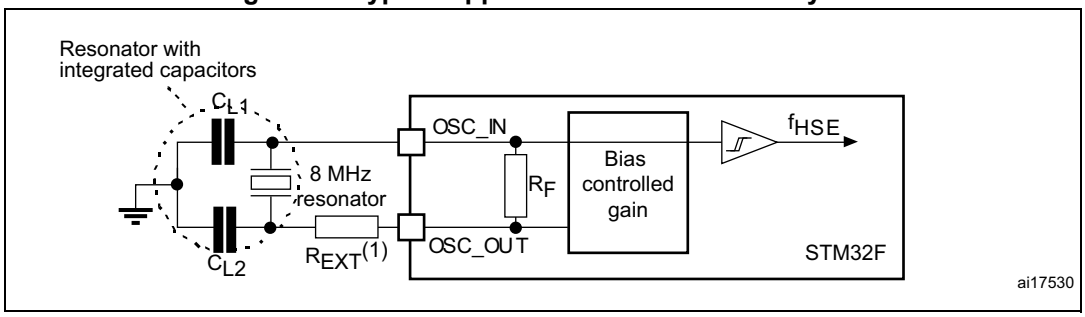
**Table 23. HSE 4-16 MHz oscillator characteristics(1)(2)**

| Symbol | Parameter | Conditions | Min | Typ | Max | Unit |
|---|---|---|---|---|---|---|
| $f_{OSC_IN}$ | Oscillator frequency | - | 4 | 8 | 16 | MHz |
| $R_F$ | Feedback resistor | - | - | 200 | - | kΩ |
| C | Recommended load capacitance versus equivalent serial resistance of the crystal ($R_S$)(3) | $R_S$ = 30 Ω | - | 30 | - | pF |
| $i_2$ | HSE driving current | $V_{DD}$= 3.3 V, $V_{IN}$ = $V_{SS}$ with 30 pF load | - | - | 1 | mA |
| $g_m$ | Oscillator transconductance | Startup | 25 | - | - | mA/V |
| $t_{SU(HSE)}$(4) | Startup time | $V_{DD}$ is stabilized | - | 2 | - | ms |

1. Resonator characteristics given by the crystal/ceramic resonator manufacturer.
2. Guaranteed by characterization results, not tested in production.
3. The relatively low value of the RF resistor offers a good protection against issues resulting from use in a humid environment, due to the induced leakage and the bias condition change. However, it is recommended to take this point into account if the MCU is used in tough humidity conditions.
4. $t_{SU(HSE)}$ is the startup time measured from the moment it is enabled (by software) to a stabilized 8 MHz oscillation is reached. This value is measured for a standard crystal resonator and it can vary significantly with the crystal manufacturer

For $C_{L1}$ and $C_{L2}$, it is recommended to use high-quality external ceramic capacitors in the 5 pF to 25 pF range (typ.), designed for high-frequency applications, and selected to match the requirements of the crystal or resonator (see *Figure 20*). $C_{L1}$ and $C_{L2}$ are usually the same size. The crystal manufacturer typically specifies a load capacitance which is the series combination of $C_{L1}$ and $C_{L2}$. PCB and MCU pin capacitance must be included (10 pF can be used as a rough estimate of the combined pin and board capacitance) when sizing $C_{L1}$ and $C_{L2}$. Refer to the application note AN2867 “Oscillator design guide for ST microcontrollers” available from the ST website *www.st.com*.

**Figure 20. Typical application with an 8 MHz crystal**




1. $R_{EXT}$ value depends on the crystal characteristics.

### Low-speed external clock generated from a crystal/ceramic resonator

The low-speed external (LSE) clock can be supplied with a 32.768 kHz crystal/ceramic resonator oscillator. All the information given in this paragraph are based on characterization results obtained with typical external components specified in *Table 24*. In the application, the resonator and the load capacitors have to be placed as close as possible to the oscillator pins in order to minimize output distortion and startup stabilization time. Refer to the crystal resonator manufacturer for more details on the resonator characteristics (frequency, package, accuracy).

**Table 24. LSE oscillator characteristics ($f_{LSE}$ = 32.768 kHz)(1)(2)**

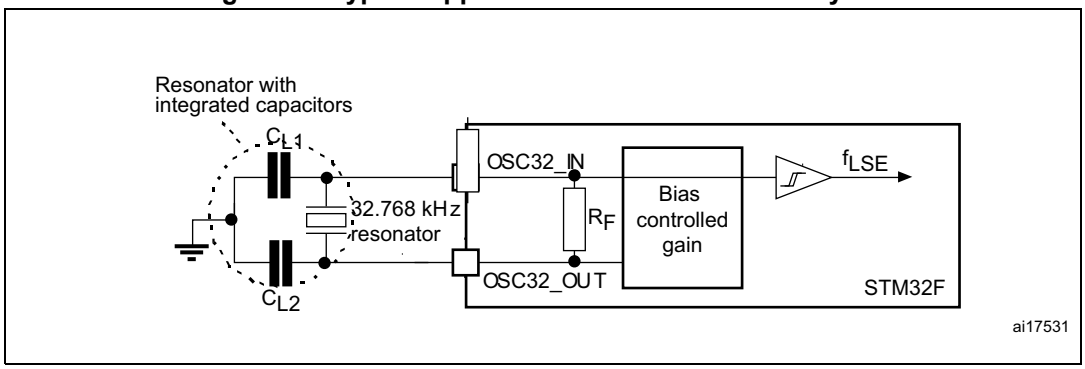
| Symbol | Parameter | Conditions | | Min | Typ | Max | Unit |
|---|---|---|---|---|---|---|---|
| $R_F$ | Feedback resistor | - | | - | 5 | - | MΩ |
| C(2) | Recommended load capacitance versus equivalent serial resistance of the crystal ($R_S$) | $R_S$ = 30 kΩ | | - | - | 15 | pF |
| $I_2$ | LSE driving current | $V_{DD}$ = 3.3 V, $V_{IN}$ = $V_{SS}$ | | - | - | 1.4 | µA |
| $g_m$ | Oscillator transconductance | - | | 5 | - | - | µA/V |
| $t_{SU(LSE)}$(3) | Startup time | $V_{DD}$ is stabilized | $T_A$ = 50 °C | - | 1.5 | - | s |
| | | | $T_A$ = 25 °C | - | 2.5 | - | |
| | | | $T_A$ = 10 °C | - | 4 | - | |
| | | | $T_A$ = 0 °C | - | 6 | - | |
| | | | $T_A$ = -10 °C | - | 10 | - | |
| | | | $T_A$ = -20 °C | - | 17 | - | |
| | | | $T_A$ = -30 °C | - | 32 | - | |
| | | | $T_A$ = -40 °C | - | 60 | - | |

1. Guaranteed by characterization results, not tested in production.
2. Refer to the note and caution paragraphs below the table, and to the application note AN2867 “Oscillator design guide for ST microcontrollers”.
3. $t_{SU(LSE)}$ is the startup time measured from the moment it is enabled (by software) until a stabilized 32.768 kHz oscillation is reached. This value is measured for a standard crystal and it can vary significantly with the crystal manufacturer, PCB layout and humidity.

*Note: For $C_{L1}$ and $C_{L2}$, it is recommended to use high-quality ceramic capacitors in the 5 pF to 15 pF range selected to match the requirements of the crystal or resonator (see Figure 21). $C_{L1}$ and $C_{L2}$, are usually the same size. The crystal manufacturer typically specifies a load capacitance which is the series combination of $C_{L1}$ and $C_{L2}$.*
*Load capacitance $C_L$ has the following formula: $C_L = C_{L1} \times C_{L2} / (C_{L1} + C_{L2}) + C_{stray}$ where $C_{stray}$ is the pin capacitance and board or trace PCB-related capacitance. Typically, it is between 2 pF and 7 pF.*

**Caution:** To avoid exceeding the maximum value of $C_{L1}$ and $C_{L2}$ (15 pF) it is strongly recommended to use a resonator with a load capacitance $C_L \leq$ 7 pF. Never use a resonator with a load capacitance of 12.5 pF.
**Example:** if you choose a resonator with a load capacitance of $C_L$ = 6 pF, and $C_{stray}$ = 2 pF, then $C_{L1}$ = $C_{L2}$ = 8 pF.

**Figure 21. Typical application with a 32.768 kHz crystal**




## 5.3.7 Internal clock source characteristics

The parameters given in *Table 25* are derived from tests performed under ambient temperature and $V_{DD}$ supply voltage conditions summarized in *Table 10*.

### High-speed internal (HSI) RC oscillator

**Table 25. HSI oscillator characteristics(1)**

| Symbol | Parameter | Conditions | | Min | Typ | Max | Unit |
|---|---|---|---|---|---|---|---|
| $f_{HSI}$ | Frequency | - | | - | 8 | | MHz |
| $DuCy_{(HSI)}$ | Duty cycle | - | | 45 | - | 55 | % |
| $ACC_{HSI}$ | Accuracy of the HSI oscillator | User-trimmed with the RCC_CR register(2) | | - | - | 1(3) | % |
| | | Factory-calibrated(4) | $T_A$ = –40 to 105 °C | –2 | - | 2.5 | % |
| | | | $T_A$ = –10 to 85 °C | –1.5 | - | 2.2 | % |
| | | | $T_A$ = 0 to 70 °C | –1.3 | - | 2 | % |
| | | | $T_A$ = 25 °C | –1.1 | - | 1.8 | % |
| $t_{su(HSI)}$(4) | HSI oscillator startup time | - | | 1 | - | 2 | µs |
| $I_{DD(HSI)}$(4) | HSI oscillator power consumption | - | | - | 80 | 100 | µA |

1. $V_{DD}$ = 3.3 V, $T_A$ = –40 to 105 °C unless otherwise specified.
2. Refer to application note AN2868 “STM32F10xxx internal RC oscillator (HSI) calibration” available from the ST website *www.st.com*.
3. Guaranteed by design, not tested in production.
4. Guaranteed by characterization results, not tested in production.

### Low-speed internal (LSI) RC oscillator

**Table 26. LSI oscillator characteristics (1)**

| Symbol | Parameter | Min | Typ | Max | Unit |
|---|---|---|---|---|---|
| $f_{LSI}$(2) | Frequency | 30 | 40 | 60 | kHz |
| $t_{su(LSI)}$(3) | LSI oscillator startup time | - | - | 85 | µs |
| $I_{DD(LSI)}$(3) | LSI oscillator power consumption | - | 0.65 | 1.2 | µA |

1. $V_{DD}$ = 3 V, $T_A$ = –40 to 105 °C unless otherwise specified.
2. Guaranteed by characterization results, not tested in production.
3. Guaranteed by design, not tested in production.

### Wakeup time from low-power mode

The wakeup times given in *Table 27* is measured on a wakeup phase with a 8-MHz HSI RC oscillator. The clock source used to wake up the device depends from the current operating mode:

- Stop or Standby mode: the clock source is the RC oscillator
- Sleep mode: the clock source is the clock that was set before entering Sleep mode.

All timings are derived from tests performed under ambient temperature and $V_{DD}$ supply voltage conditions summarized in *Table 10*.

**Table 27. Low-power mode wakeup timings**

| Symbol | Parameter | Typ | Unit |
|---|---|---|---|
| $t_{WUSLEEP}$(1) | Wakeup from Sleep mode | 1.8 | µs |
| $t_{WUSTOP}$(1) | Wakeup from Stop mode (regulator in run mode) | 3.6 | µs |
| | Wakeup from Stop mode (regulator in low-power mode) | 5.4 | |
| $t_{WUSTDBY}$(1) | Wakeup from Standby mode | 50 | µs |

1. The wakeup times are measured from the wakeup event to the point in which the user application code reads the first instruction.

### 5.3.8 PLL characteristics

The parameters given in *Table 28* are derived from tests performed under ambient temperature and $V_{DD}$ supply voltage conditions summarized in *Table 10*.

**Table 28. PLL characteristics**

| Symbol | Parameter | Value | | | Unit |
|---|---|---|---|---|---|
| | | Min | Typ | Max(1) | |
| $f_{PLL_IN}$ | PLL input clock(2) | 1 | 8.0 | 25 | MHz |
| | PLL input clock duty cycle | 40 | - | 60 | % |
| $f_{PLL_OUT}$ | PLL multiplier output clock | 16 | - | 72 | MHz |
| $t_{LOCK}$ | PLL lock time | - | - | 200 | µs |
| Jitter | Cycle-to-cycle jitter | - | - | 300 | ps |

1. Guaranteed by characterization results, not tested in production.
2. Take care of using the appropriate multiplier factors so as to have PLL input clock values compatible with the range defined by $f_{PLL_OUT}$.

### 5.3.9 Memory characteristics

#### Flash memory

The characteristics are given at $T_A$ = –40 to 105 °C unless otherwise specified.

**Table 29. Flash memory characteristics**

| Symbol | Parameter | Conditions | Min | Typ | Max(1) | Unit |
|---|---|---|---|---|---|---|
| $t_{prog}$ | 16-bit programming time | $T_A$ = –40 to +105 °C | 40 | 52.5 | 70 | µs |
| $t_{ERASE}$ | Page (2 KB) erase time | $T_A$ = –40 to +105 °C | 20 | - | 40 | ms |
| $t_{ME}$ | Mass erase time | $T_A$ = –40 to +105 °C | 20 | - | 40 | ms |
| $I_{DD}$ | Supply current | Read mode $f_{HCLK}$ = 72 MHz with 2 wait states, $V_{DD}$ = 3.3 V | - | - | 28 | mA |
| | | Write mode $f_{HCLK}$ = 72 MHz, $V_{DD}$ = 3.3 V | - | - | 7 | mA |
| | | Erase mode $f_{HCLK}$ = 72 MHz, $V_{DD}$ = 3.3 V | - | - | 5 | mA |
| | | Power-down mode / Halt, $V_{DD}$ = 3.0 to 3.6 V | - | - | 50 | µA |
| $V_{prog}$ | Programming voltage | - | 2 | - | 3.6 | V |

1. Guaranteed by design, not tested in production.

**Table 30. Flash memory endurance and data retention**

| Symbol | Parameter | Conditions | Value | Unit |
|---|---|---|---|---|
| | | | Min(1) | |
| $N_{END}$ | Endurance | $T_A$ = –40 to +85 °C (6 suffix versions)<br>$T_A$ = –40 to +105 °C (7 suffix versions) | 10 | kcycles |
| $t_{RET}$ | Data retention | 1 kcycle(2) at $T_A$ = 85 °C | 30 | Years |
| | | 1 kcycle(2) at $T_A$ = 105 °C | 10 | |
| | | 10 kcycles(2) at $T_A$ = 55 °C | 20 | |

1. Guaranteed by characterization results, not tested in production.
2. Cycling performed over the whole temperature range.

## 5.3.10 FSMC characteristics

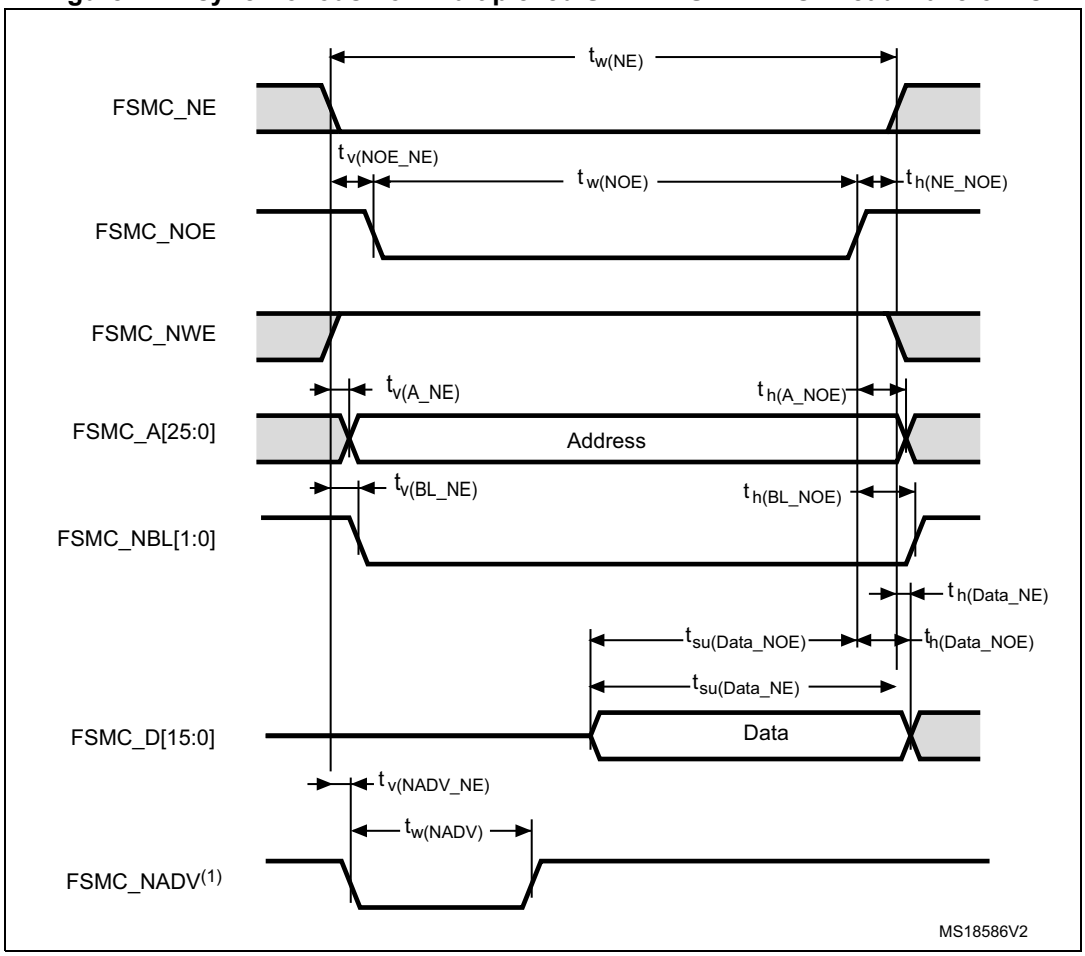
### Asynchronous waveforms and timings

*Figure 22* through *Figure 25* represent asynchronous waveforms and *Table 31* through *Table 35* provide the corresponding timings. The results shown in these tables are obtained with the following FSMC configuration:

- AddressSetupTime = 0
- AddressHoldTime = 1
- DataSetupTime = 1

*Note: On all tables, the $t_{HCLK}$ is the HCLK clock period.*

**Figure 22. Asynchronous non-multiplexed SRAM/PSRAM/NOR read waveforms**




1. Mode 2/B, C and D only. In Mode 1, FSMC_NADV is not used.

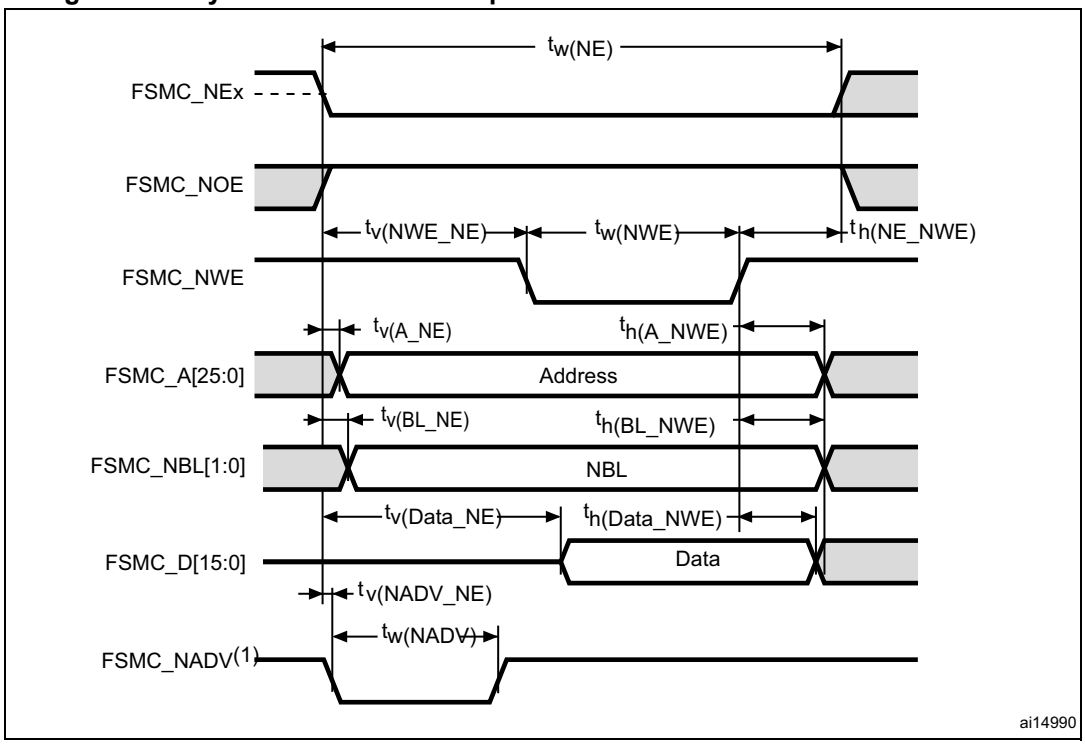
*Note: FSMC_BusTurnAroundDuration = 0.*

**Table 31. Asynchronous non-multiplexed SRAM/PSRAM/NOR read timings(1)**

| Symbol | Parameter | Min | Max | Unit |
|---|---|---|---|---|
| $t_{w(NE)}$ | FSMC_NE low time | $5t_{HCLK}$ + 0.5 | $5t_{HCLK}$ + 2 | ns |
| $t_{v(NOE_NE)}$ | FSMC_NEx low to FSMC_NOE low | 0.5 | 1.5 | ns |
| $t_{w(NOE)}$ | FSMC_NOE low time | $5t_{HCLK}$ – 1 | $5t_{HCLK}$ + 1 | ns |
| $t_{h(NE_NOE)}$ | FSMC_NOE high to FSMC_NE high hold time | 0 | - | ns |
| $t_{v(A_NE)}$ | FSMC_NEx low to FSMC_A valid | - | 3 | ns |
| $t_{h(A_NOE)}$ | Address hold time after FSMC_NOE high | 0 | - | ns |
| $t_{v(BL_NE)}$ | FSMC_NEx low to FSMC_BL valid | - | 0 | ns |
| $t_{h(BL_NOE)}$ | FSMC_BL hold time after FSMC_NOE high | 0.5 | - | ns |
| $t_{su(Data_NE)}$ | Data to FSMC_NEx high setup time | $2t_{HCLK}$ - 1 | - | ns |
| $t_{su(Data_NOE)}$ | Data to FSMC_NOEx high setup time | $2t_{HCLK}$ - 1 | - | ns |
| $t_{h(Data_NOE)}$ | Data hold time after FSMC_NOE high | 0 | - | ns |
| $t_{h(Data_NE)}$ | Data hold time after FSMC_NEx high | 0 | - | ns |
| $t_{v(NADV_NE)}$ | FSMC_NEx low to FSMC_NADV low | - | 0 | ns |
| $t_{w(NADV)}$ | FSMC_NADV low time | - | $t_{HCLK}$ + 2 | ns |

1. $C_L$ = 15 pF.

**Figure 23. Asynchronous non-multiplexed SRAM/PSRAM/NOR write waveforms**




1. Mode 2/B, C and D only. In Mode 1, FSMC_NADV is not used.

**Table 32. Asynchronous non-multiplexed SRAM/PSRAM/NOR write timings(1)**

| Symbol | Parameter | Min | Max | Unit |
|---|---|---|---|---|
| $t_{w(NE)}$ | FSMC_NE low time | $3t_{HCLK}$ + 0.5 | $3t_{HCLK}$ + 1.5 | ns |
| $t_{v(NWE_NE)}$ | FSMC_NEx low to FSMC_NWE low | $t_{HCLK}$ + 0.5 | $t_{HCLK}$ + 1.5 | ns |
| $t_{w(NWE)}$ | FSMC_NWE low time | $t_{HCLK}$ – 0.5 | $t_{HCLK}$ + 1 | ns |
| $t_{h(NE_NWE)}$ | FSMC_NWE high to FSMC_NE high hold time | $t_{HCLK}$ – 0.5 | - | ns |
| $t_{v(A_NE)}$ | FSMC_NEx low to FSMC_A valid | - | 0 | ns |
| $t_{h(A_NWE)}$ | Address hold time after FSMC_NWE high | $t_{HCLK}$ | - | ns |
| $t_{v(BL_NE)}$ | FSMC_NEx low to FSMC_BL valid | - | 1.5 | ns |
| $t_{h(BL_NWE)}$ | FSMC_BL hold time after FSMC_NWE high | $t_{HCLK}$ – 1.5 | - | ns |
| $t_{v(Data_NE)}$ | FSMC_NEx low to Data valid | - | $t_{HCLK}$ | ns |
| $t_{h(Data_NWE)}$ | Data hold time after FSMC_NWE high | $t_{HCLK}$ | - | ns |
| $t_{v(NADV_NE)}$ | FSMC_NEx low to FSMC_NADV low | - | 0 | ns |
| $t_{w(NADV)}$ | FSMC_NADV low time | - | $t_{HCLK}$ + 1.5 | ns |

1. $C_L$ = 15 pF.

**Table 33. Asynchronous multiplexed read timings**

| Symbol | Parameter | Min | Max | Unit |
|---|---|---|---|---|
| $t_{w(NE)}$ | FSMC_NE low time | $7t_{HCLK}$ + 0.5 | $7t_{HCLK}$ + 2 | ns |
| $t_{v(NOE_NE)}$ | FSMC_NEx low to FSMC_NOE low | $3t_{HCLK}$ + 0.5 | $3t_{HCLK}$ + 1.5 | |
| $t_{w(NOE)}$ | FSMC_NOE low time | $4t_{HCLK}$ – 1 | $4t_{HCLK}$ + 1 | |
| $t_{h(NE_NOE)}$ | FSMC_NOE high to FSMC_NE high hold time | 0.5 | - | |
| $t_{v(A_NE)}$ | FSMC_NEx low to FSMC_A valid | - | 0 | |
| $t_{v(NADV_NE)}$ | FSMC_NEx low to FSMC_NADV low | 0 | 1 | |
| $t_{w(NADV)}$ | FSMC_NADV low time | $t_{HCLK}$ + 0.5 | $t_{HCLK}$ + 2 | |
| $t_{h(AD_NADV)}$ | FSMC_AD (address) valid hold time after FSMC NADV high | $t_{HCLK}$ | - | |
| $t_{h(A_NOE)}$ | Address hold time after FSMC_NOE high | $t_{HCLK}$ – 2 | - | |
| $t_{h(BL_NOE)}$ | FSMC_BL time after FSMC_NOE high | 0.5 | - | |
| $t_{v(BL_NE)}$ | FSMC_NEx low to FSMC_BL valid | - | 0 | |
| $t_{su(Data_NE)}$ | Data to FSMC_NEx high setup time | $4t_{HCLK}$ – 0.5 | - | |
| $t_{su(Data_NOE)}$ | Data to FSMC_NOE high setup time | $4t_{HCLK}$ – 1 | - | |
| $t_{h(Data_NE)}$ | Data hold time after FSMC_NEx high | 0 | - | |
| $t_{h(Data_NOE)}$ | Data hold time after FSMC_NOE high | 0 | - | |

**Figure 24. Asynchronous multiplexed PSRAM/NOR read waveforms**

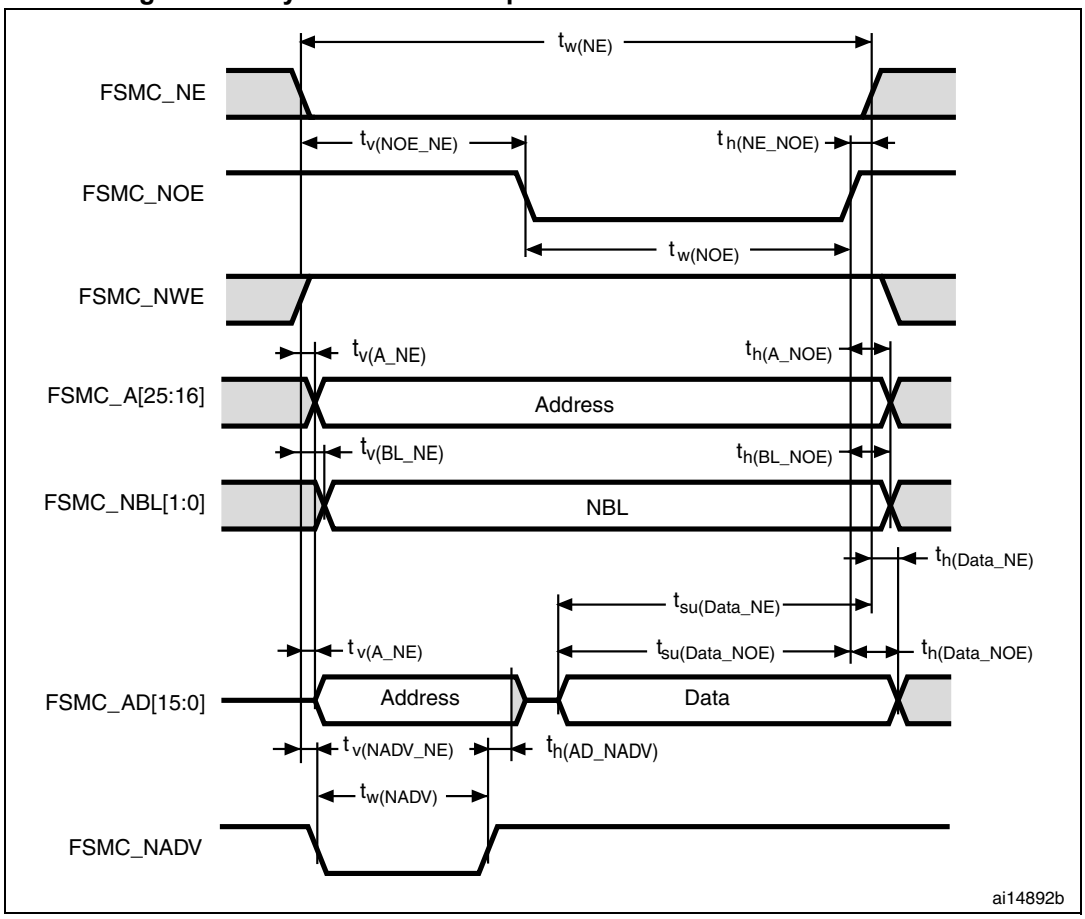



**Table 34. Asynchronous multiplexed PSRAM/NOR read timings(1)**

| Symbol | Parameter | Min | Max | Unit |
|---|---|---|---|---|
| $t_{w(NE)}$ | FSMC_NE low time | $7t_{HCLK}$ + 0.5 | $7t_{HCLK}$ + 2 | ns |
| $t_{v(NOE_NE)}$ | FSMC_NEx low to FSMC_NOE low | $3t_{HCLK}$ + 0.5 | $3t_{HCLK}$ + 1.5 | ns |
| $t_{w(NOE)}$ | FSMC_NOE low time | $4t_{HCLK}$ – 1 | $4t_{HCLK}$ + 1 | ns |
| $t_{h(NE_NOE)}$ | FSMC_NOE high to FSMC_NE high hold time | 0.5 | - | ns |
| $t_{v(A_NE)}$ | FSMC_NEx low to FSMC_A valid | - | 0 | ns |
| $t_{v(NADV_NE)}$ | FSMC_NEx low to FSMC_NADV low | 0 | 1 | ns |
| $t_{w(NADV)}$ | FSMC_NADV low time | $t_{HCLK}$ + 0.5 | $t_{HCLK}$ + 2 | ns |
| $t_{h(AD_NADV)}$ | FSMC_AD (address) valid hold time after FSMC_NADV high | $t_{HCLK}$ | - | ns |
| $t_{h(A_NOE)}$ | Address hold time after FSMC_NOE high | $t_{HCLK}$ -2 | - | ns |
| $t_{h(BL_NOE)}$ | FSMC_BL hold time after FSMC_NOE high | 0.5 | - | ns |
| $t_{v(BL_NE)}$ | FSMC_NEx low to FSMC_BL valid | - | 0 | ns |
| $t_{su(Data_NE)}$ | Data to FSMC_NEx high setup time | $4t_{HCLK}$ - 0.5 | - | ns |
| $t_{su(Data_NOE)}$ | Data to FSMC_NOE high setup time | $4t_{HCLK}$ - 1 | - | ns |

**Table 34. Asynchronous multiplexed PSRAM/NOR read timings(1) (continued)**

| Symbol | Parameter | Min | Max | Unit |
|---|---|---|---|---|
| $t_{h(Data_NE)}$ | Data hold time after FSMC_NEx high | 0 | - | ns |
| $t_{h(Data_NOE)}$ | Data hold time after FSMC_NOE high | 0 | - | ns |

1. $C_L$ = 15 pF.

**Figure 25. Asynchronous multiplexed PSRAM/NOR write waveforms**

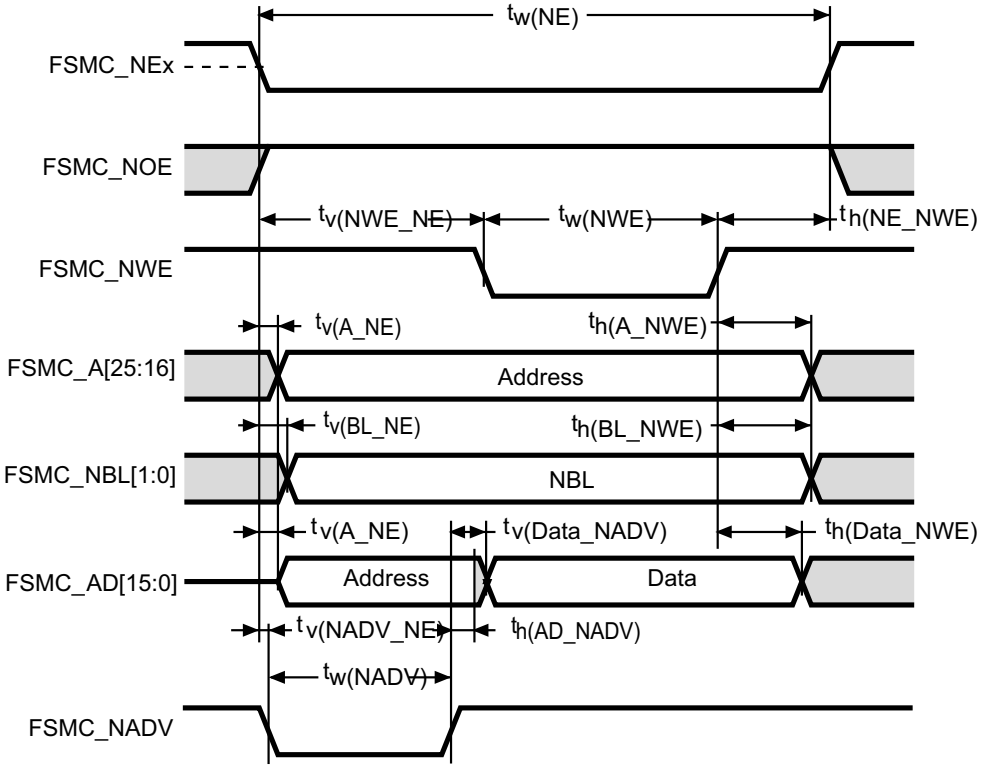



**Table 35. Asynchronous multiplexed PSRAM/NOR write timings(1)**

| Symbol | Parameter | Min | Max | Unit |
|---|---|---|---|---|
| $t_{w(NE)}$ | FSMC_NE low time | $5t_{HCLK}$ + 0.5 | $5t_{HCLK}$ + 2 | ns |
| $t_{v(NWE_NE)}$ | FSMC_NEx low to FSMC_NWE low | $t_{HCLK}$ + 1 | $t_{HCLK}$ + 1.5 | ns |
| $t_{w(NWE)}$ | FSMC_NWE low time | $3t_{HCLK}$ + 0.5 | $3t_{HCLK}$ + 1 | ns |
| $t_{h(NE_NWE)}$ | FSMC_NWE high to FSMC_NE high hold time | $t_{HCLK}$ – 0.5 | - | ns |
| $t_{v(A_NE)}$ | FSMC_NEx low to FSMC_A valid | - | 3.5 | ns |
| $t_{v(NADV_NE)}$ | FSMC_NEx low to FSMC_NADV low | 0 | 1 | ns |
| $t_{w(NADV)}$ | FSMC_NADV low time | $t_{HCLK}$ + 0.5 | $t_{HCLK}$ + 1.5 | ns |
| $t_{h(AD_NADV)}$ | FSMC_AD (address) valid hold time after FSMC_NADV high | $t_{HCLK}$ – 0.5 | - | ns |

**Table 35. Asynchronous multiplexed PSRAM/NOR write timings(1)**

| Symbol | Parameter | Min | Max | Unit |
|---|---|---|---|---|
| $t_{h(A_NWE)}$ | Address hold time after FSMC_NWE high | $4t_{HCLK} - 2$ | - | ns |
| $t_{v(BL_NE)}$ | FSMC_NEx low to FSMC_BL valid | - | 0.5 | ns |
| $t_{h(BL_NWE)}$ | FSMC_BL hold time after FSMC_NWE high | $t_{HCLK} - 1.5$ | - | ns |
| $t_{v(Data_NADV)}$ | FSMC_NADV high to Data valid | - | $t_{HCLK} + 6$ | ns |
| $t_{h(Data_NWE)}$ | Data hold time after FSMC_NWE high | $t_{HCLK} - 0.5$ | - | ns |

1. $C_L$ = 15 pF.

## Synchronous waveforms and timings

*Figure 26* through *Figure 29* represent synchronous waveforms and *Table 37* through *Table 39* provide the corresponding timings. The results shown in these tables are obtained with the following FSMC configuration:

- BurstAccessMode = FSMC_BurstAccessMode_Enable;
- MemoryType = FSMC_MemoryType_CRAM;
- WriteBurst = FSMC_WriteBurst_Enable;
- CLKDivision = 1; (0 is not supported, see the STM32F10xxx reference manual)
- DataLatency = 1 for NOR Flash; DataLatency = 0 for PSRAM

**Figure 26. Synchronous multiplexed NOR/PSRAM read timings**

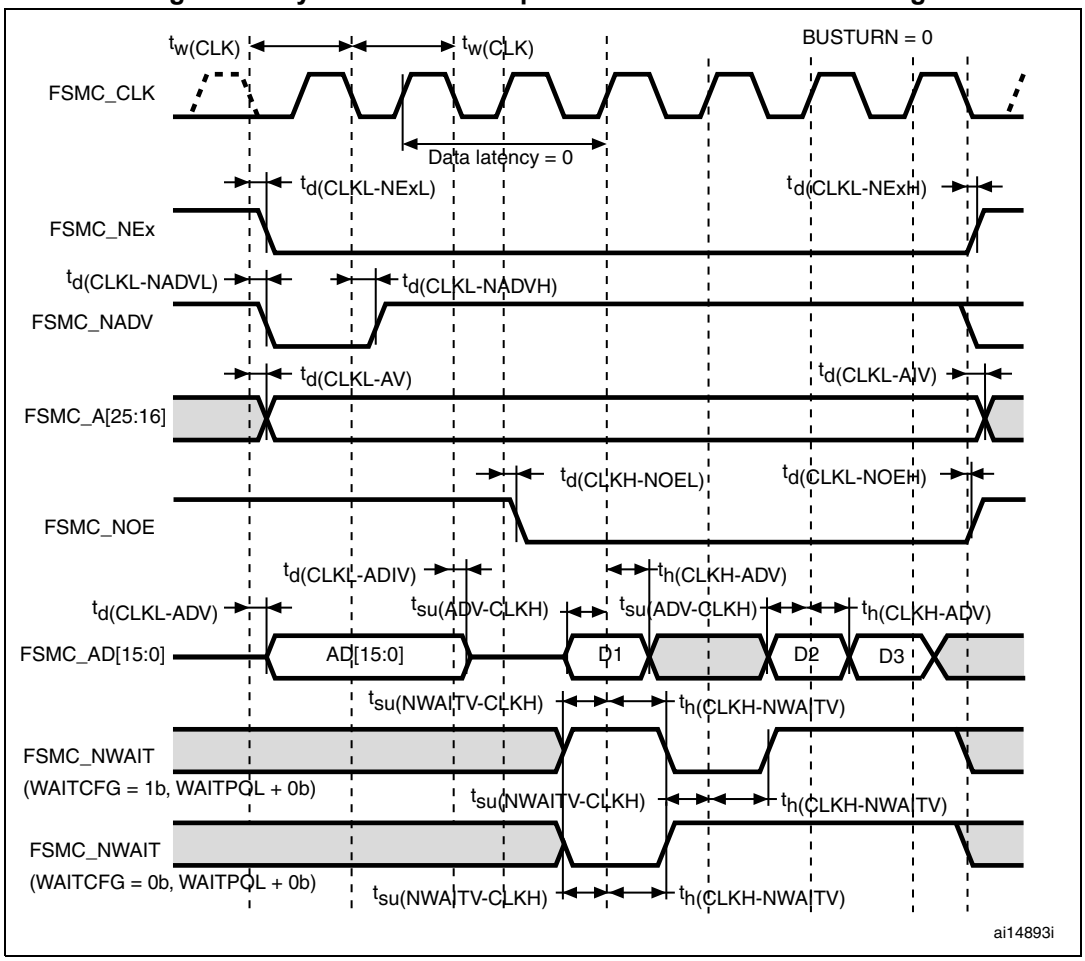


**Table 36. Synchronous multiplexed NOR/PSRAM read timings(1)**

| Symbol | Parameter | Min | Max | Unit |
|---|---|---|---|---|
| $t_{w(CLK)}$ | FSMC_CLK period | 27.6 | - | ns |
| $t_{d(CLKL-NExL)}$ | FSMC_CLK low to FSMC_NEx low (x = 0...2) | - | 0.5 | ns |
| $t_{d(CLKL-NExH)}$ | FSMC_CLK low to FSMC_NEx high (x = 0...2) | 1 | - | ns |
| $t_{d(CLKL-NADVL)}$ | FSMC_CLK low to FSMC_NADV low | - | 1 | ns |
| $t_{d(CLKL-NADVH)}$ | FSMC_CLK low to FSMC_NADV high | 0.5 | - | ns |
| $t_{d(CLKL-AV)}$ | FSMC_CLK low to FSMC_Ax valid (x = 16...25) | - | 0 | ns |
| $t_{d(CLKL-AIV)}$ | FSMC_CLK low to FSMC_Ax invalid (x = 16...25) | 1.5 | - | ns |
| $t_{d(CLKL-NOEL)}$ | FSMC_CLK low to FSMC_NOE low | - | 14 | ns |
| $t_{d(CLKL-NOEH)}$ | FSMC_CLK low to FSMC_NOE high | 1 | - | ns |
| $t_{d(CLKL-ADV)}$ | FSMC_CLK low to FSMC_AD[15:0] valid | - | 11 | ns |
| $t_{d(CLKL-ADIV)}$ | FSMC_CLK low to FSMC_AD[15:0] invalid | 0.5 | - | ns |
| $t_{su(ADV-CLKH)}$ | FSMC_A/D[15:0] valid data before FSMC_CLK high | 2 | - | ns |
| $t_{h(CLKH-ADV)}$ | FSMC_A/D[15:0] valid data after FSMC_CLK high | 0 | - | ns |
| $t_{su(NWAITV-CLKH)}$ | FSMC_NWAIT valid before FSMC_CLK high | 8 | - | ns |
| $t_{h(CLKH-NWAITV)}$ | FSMC_NWAIT valid after FSMC_CLK high | 2 | - | ns |

1. $C_L$ = 15 pF.

**Figure 27. Synchronous multiplexed PSRAM write timings**

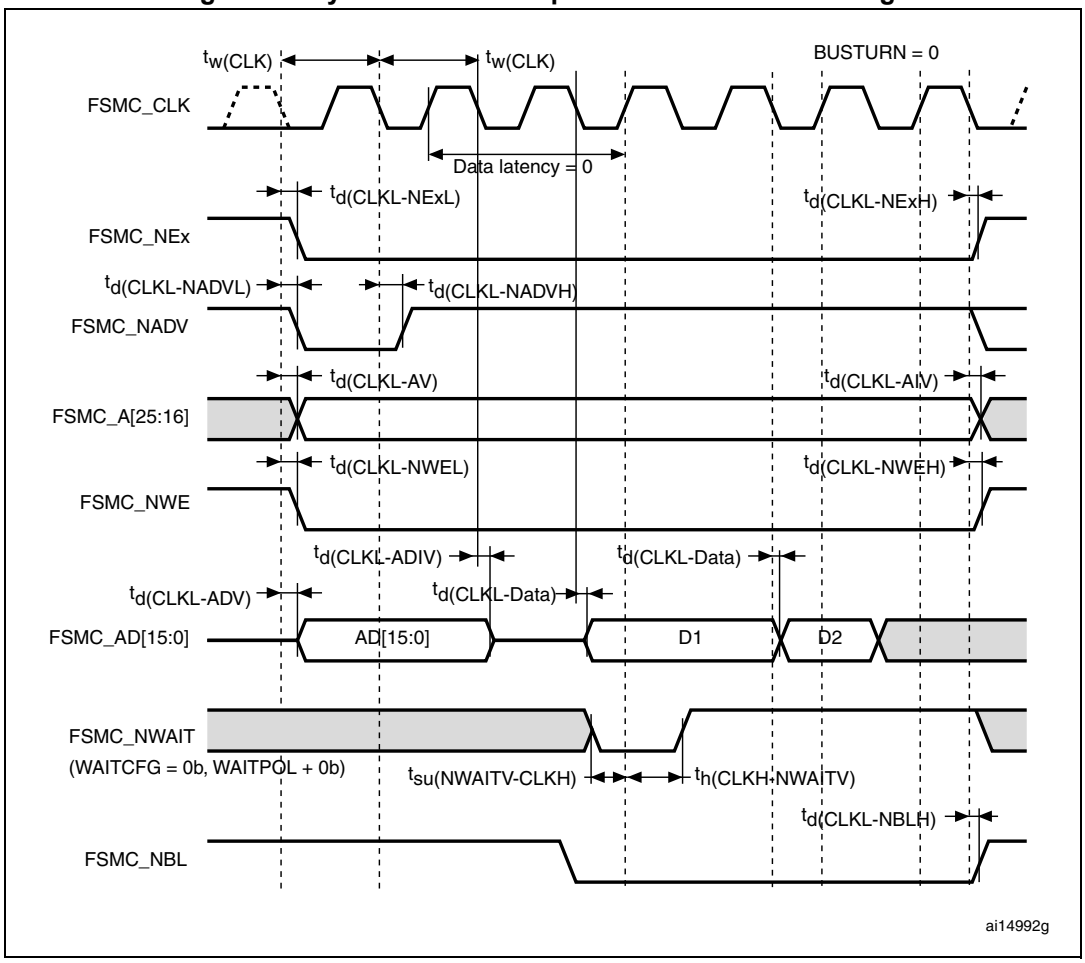


**Table 37. Synchronous multiplexed PSRAM write timings(1)**

| Symbol | Parameter | Min | Max | Unit |
|---|---|---|---|---|
| $t_{w(CLK)}$ | FSMC_CLK period | 27.5 | - | ns |
| $t_{d(CLKL-NExL)}$ | FSMC_CLK low to FSMC_Nex low (x = 0...2) | - | 0 | ns |
| $t_{d(CLKL-NExH)}$ | FSMC_CLK low to FSMC_NEx high (x = 0...2) | 1 | - | ns |
| $t_{d(CLKL-NADVL)}$ | FSMC_CLK low to FSMC_NADV low | - | 1 | ns |
| $t_{d(CLKL-NADVH)}$ | FSMC_CLK low to FSMC_NADV high | 1 | - | ns |
| $t_{d(CLKL-AV)}$ | FSMC_CLK low to FSMC_Ax valid (x = 16...25) | - | 0 | ns |
| $t_{d(CLKL-AIV)}$ | FSMC_CLK low to FSMC_Ax invalid (x = 16...25) | 1 | - | ns |
| $t_{d(CLKL-NWEL)}$ | FSMC_CLK low to FSMC_NWE low | - | 1 | ns |
| $t_{d(CLKL-NWEH)}$ | FSMC_CLK low to FSMC_NWE high | 1.5 | - | ns |
| $t_{d(CLKL-ADV)}$ | FSMC_CLK low to FSMC_AD[15:0] valid | - | 10 | ns |
| $t_{d(CLKL-ADIV)}$ | FSMC_CLK low to FSMC_AD[15:0] invalid | 1 | - | ns |
| $t_{d(CLKL-Data)}$ | FSMC_A/D[15:0] valid after FSMC_CLK low | - | 6 | ns |
| $t_{d(CLKL-NBLH)}$ | FSMC_CLK low to FSMC_NBL high | 1 | - | ns |
| $t_{su(NWAITV-CLKH)}$ | FSMC_NWAIT valid before FSMC_CLK high | 7 | - | ns |
| $t_{h(CLKH-NWAITV)}$ | FSMC_NWAIT valid after FSMC_CLK high | 2 | - | ns |

1. $C_L$ = 15 pF.

**Figure 28. Synchronous non-multiplexed NOR/PSRAM read timings**

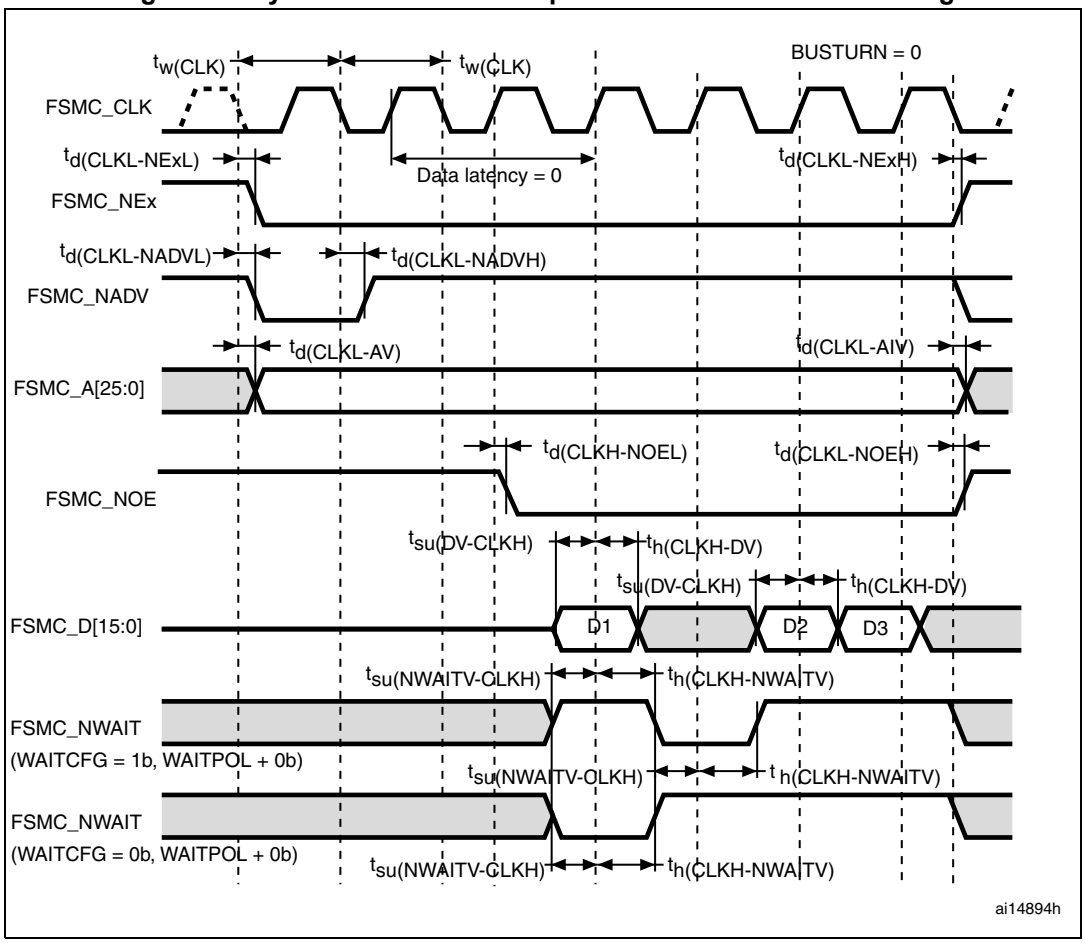



**Table 38. Synchronous non-multiplexed NOR/PSRAM read timings(1)**

| Symbol | Parameter | Min | Max | Unit |
|---|---|---|---|---|
| $t_{w(CLK)}$ | FSMC_CLK period | 27.6 | - | ns |
| $t_{d(CLKL-NExL)}$ | FSMC_CLK low to FSMC_NEx low (x = 0...2) | - | 1.5 | ns |
| $t_{d(CLKL-NExH)}$ | FSMC_CLK low to FSMC_NEx high (x = 0...2) | 2 | - | ns |
| $t_{d(CLKL-NADVL)}$ | FSMC_CLK low to FSMC_NADV low | - | 0.5 | ns |
| $t_{d(CLKL-NADVH)}$ | FSMC_CLK low to FSMC_NADV high | 1 | - | ns |
| $t_{d(CLKL-AV)}$ | FSMC_CLK low to FSMC_Ax valid (x = 0...25) | - | 0 | ns |
| $t_{d(CLKL-AIV)}$ | FSMC_CLK low to FSMC_Ax invalid (x = 0...25) | 2 | - | ns |
| $t_{d(CLKL-NOEL)}$ | FSMC_CLK low to FSMC_NOE low | - | $t_{HCLK}$ + 1 | ns |
| $t_{d(CLKL-NOEH)}$ | FSMC_CLK low to FSMC_NOE high | 1.5 | - | ns |
| $t_{su(DV-CLKH)}$ | FSMC_D[15:0] valid data before FSMC_CLK high | 3.5 | - | ns |
| $t_{h(CLKH-DV)}$ | FSMC_D[15:0] valid data after FSMC_CLK high | 0 | - | ns |
| $t_{su(NWAITV-CLKH)}$ | FSMC_NWAIT valid before FSMC_SMCLK high | 7 | - | ns |
| $t_{h(CLKH-NWAITV)}$ | FSMC_NWAIT valid after FSMC_CLK high | 2 | - | ns |

1. $C_L$ = 15 pF.

**Figure 29. Synchronous non-multiplexed PSRAM write timings**

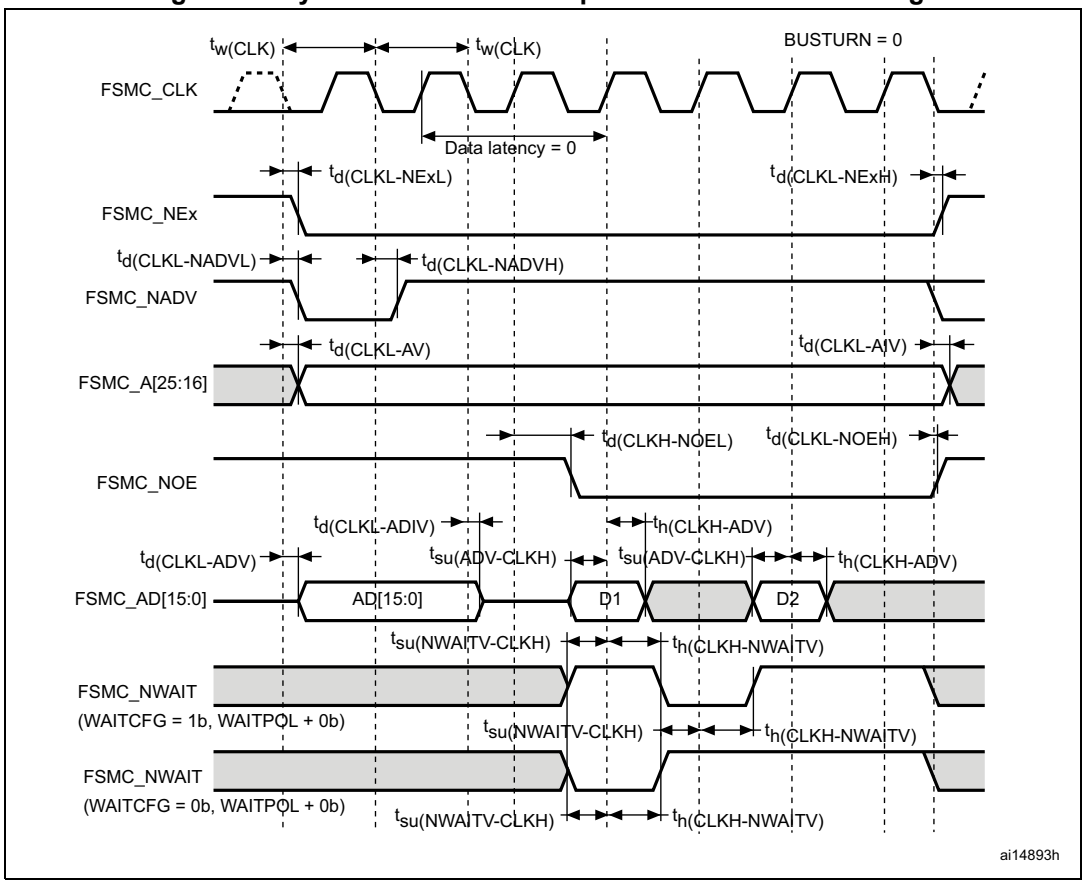



**Table 39. Synchronous non-multiplexed PSRAM write timings(1)**

| Symbol | Parameter | Min | Max | Unit |
|---|---|---|---|---|
| $t_{w(CLK)}$ | FSMC_CLK period | 27.6 | - | ns |
| $t_{d(CLKL-NExL)}$ | FSMC_CLK low to FSMC_NEx low (x = 0...2) | - | 0.5 | ns |
| $t_{d(CLKL-NExH)}$ | FSMC_CLK low to FSMC_NEx high (x = 0...2) | 1.5 | - | ns |
| $t_{d(CLKL-NADVL)}$ | FSMC_CLK low to FSMC_NADV low | - | 1 | ns |
| $t_{d(CLKL-NADVH)}$ | FSMC_CLK low to FSMC_NADV high | 0.5 | - | ns |
| $t_{d(CLKL-AV)}$ | FSMC_CLK low to FSMC_Ax valid (x = 16...25) | - | 0 | ns |
| $t_{d(CLKL-AIV)}$ | FSMC_CLK low to FSMC_Ax invalid (x = 16...25) | 1.5 | - | ns |
| $t_{d(CLKL-NWEL)}$ | FSMC_CLK low to FSMC_NWE low | - | 1 | ns |
| $t_{d(CLKL-NWEH)}$ | FSMC_CLK low to FSMC_NWE high | 1.5 | - | ns |
| $t_{d(CLKL-Data)}$ | FSMC_D[15:0] valid data after FSMC_CLK low | - | 2.5 | ns |
| $t_{d(CLKL-NBLH)}$ | FSMC_CLK low to FSMC_NBL high | 0.5 | - | ns |
| $t_{su(NWAITV-CLKH)}$ | FSMC_NWAIT valid before FSMC_CLK high | 7 | - | ns |
| $t_{h(CLKH-NWAITV)}$ | FSMC_NWAIT valid after FSMC_CLK high | 2 | - | ns |

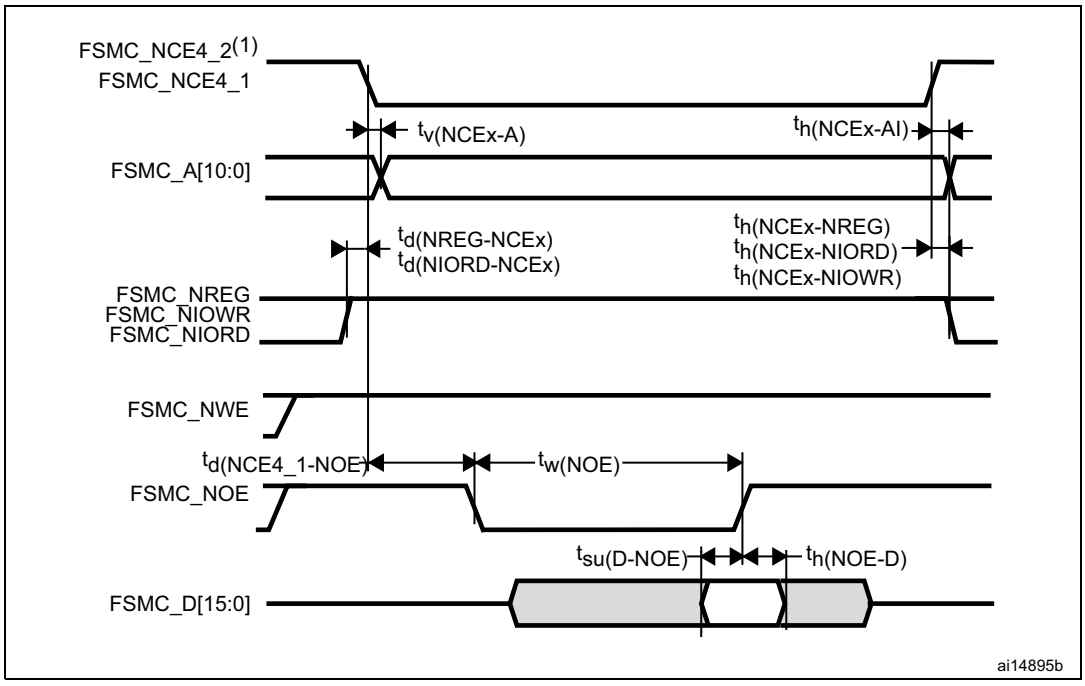
1. $C_L$ = 15 pF.

## PC Card/CompactFlash controller waveforms and timings

*Figure 30* through *Figure 35* represent synchronous waveforms and *Table 42* provides the corresponding timings. The results shown in this table are obtained with the following FSMC configuration:

- COM.FSMC_SetupTime = 0x04;
- COM.FSMC_WaitSetupTime = 0x07;
- COM.FSMC_HoldSetupTime = 0x04;
- COM.FSMC_HiZSetupTime = 0x00;
- ATT.FSMC_SetupTime = 0x04;
- ATT.FSMC_WaitSetupTime = 0x07;
- ATT.FSMC_HoldSetupTime = 0x04;
- ATT.FSMC_HiZSetupTime = 0x00;
- IO.FSMC_SetupTime = 0x04;
- IO.FSMC_WaitSetupTime = 0x07;
- IO.FSMC_HoldSetupTime = 0x04;
- IO.FSMC_HiZSetupTime = 0x00;
- TCLRSetupTime = 0;
- TARSetupTime = 0;

**Figure 30. PC Card/CompactFlash controller waveforms for common memory read access**




1. FSMC_NCE4_2 remains high (inactive during 8-bit access.

**Figure 31. PC Card/CompactFlash controller waveforms for common memory write access**

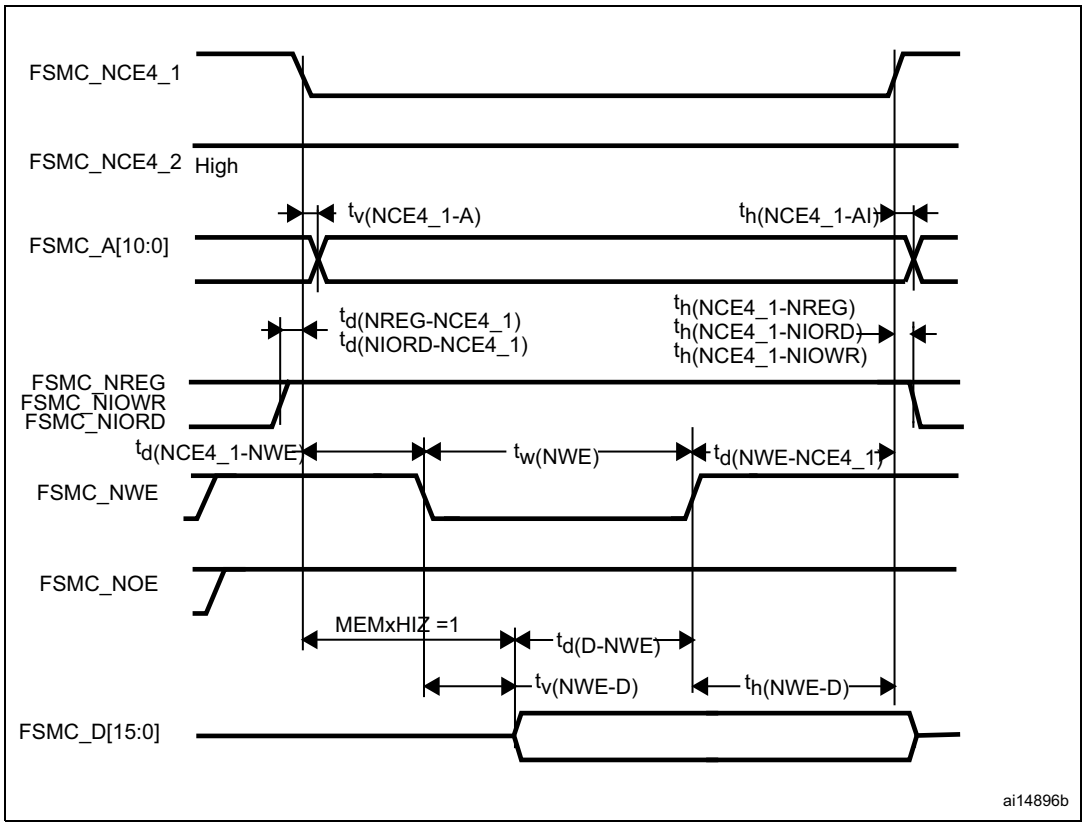
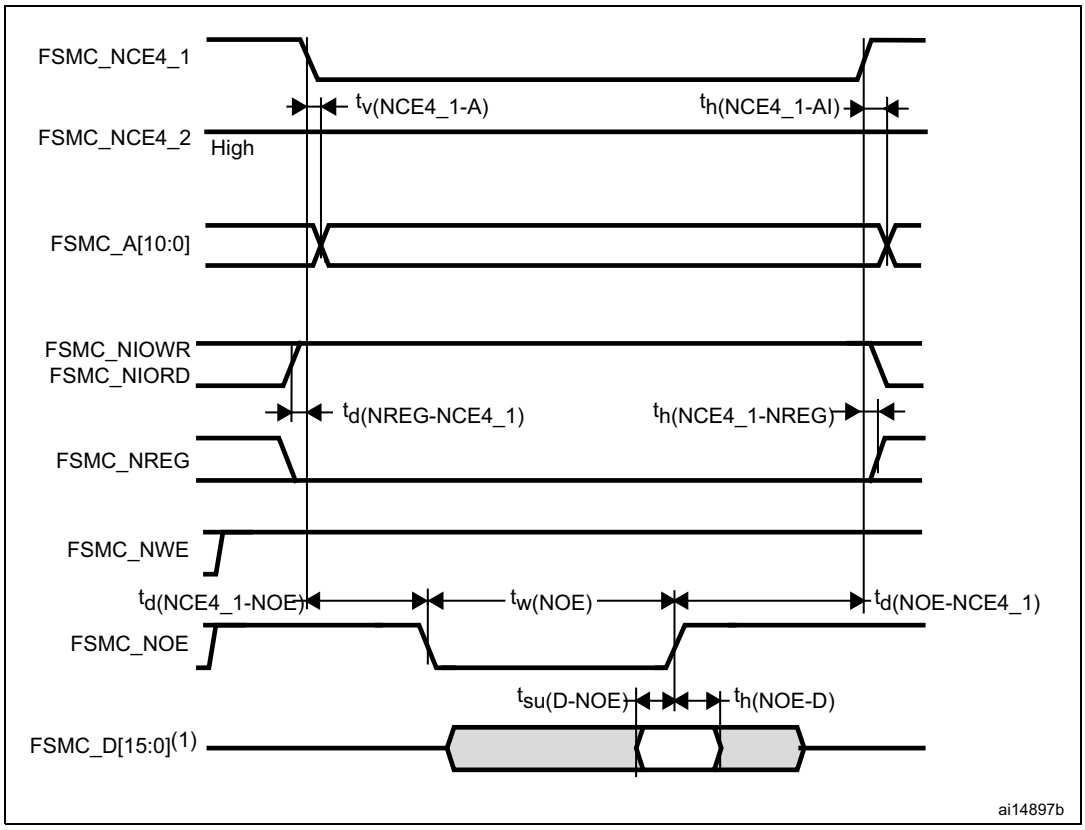
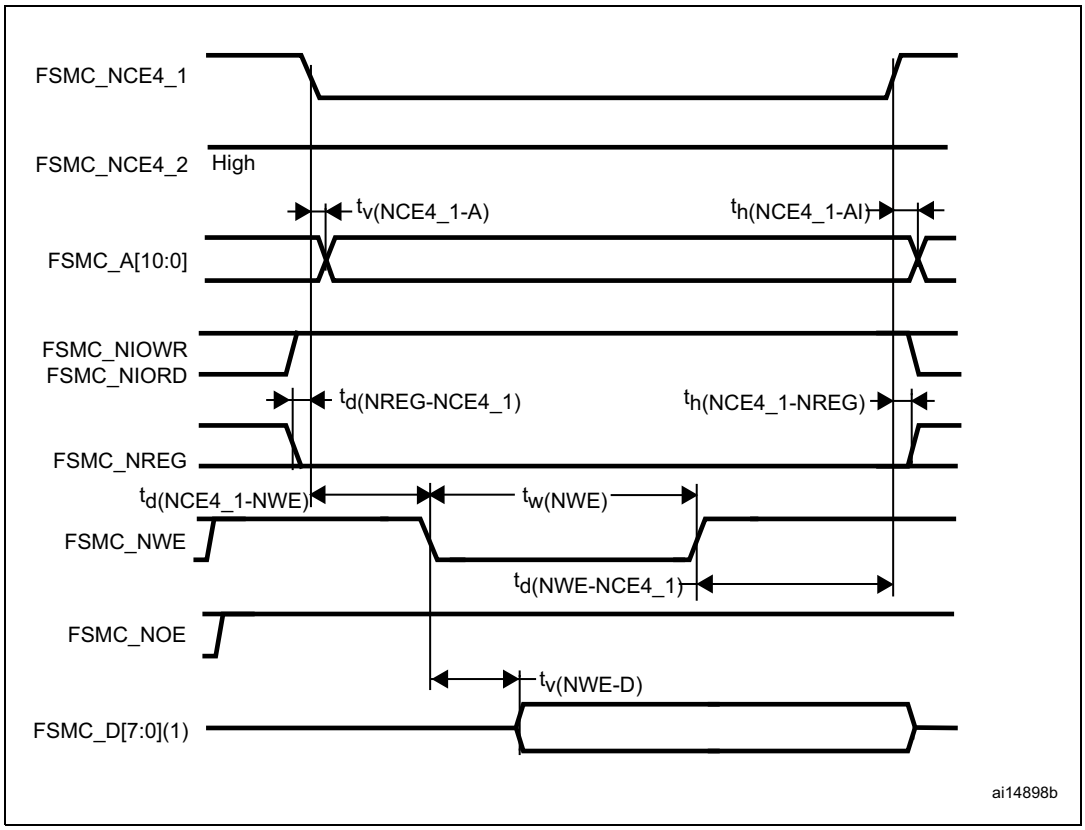


**Figure 32. PC Card/CompactFlash controller waveforms for attribute memory read access**




1. Only data bits 0...7 are read (bits 8...15 are disregarded).

**Figure 33. PC Card/CompactFlash controller waveforms for attribute memory write access**




1. Only data bits 0...7 are driven (bits 8...15 remains HiZ).

**Figure 34. PC Card/CompactFlash controller waveforms for I/O space read access**

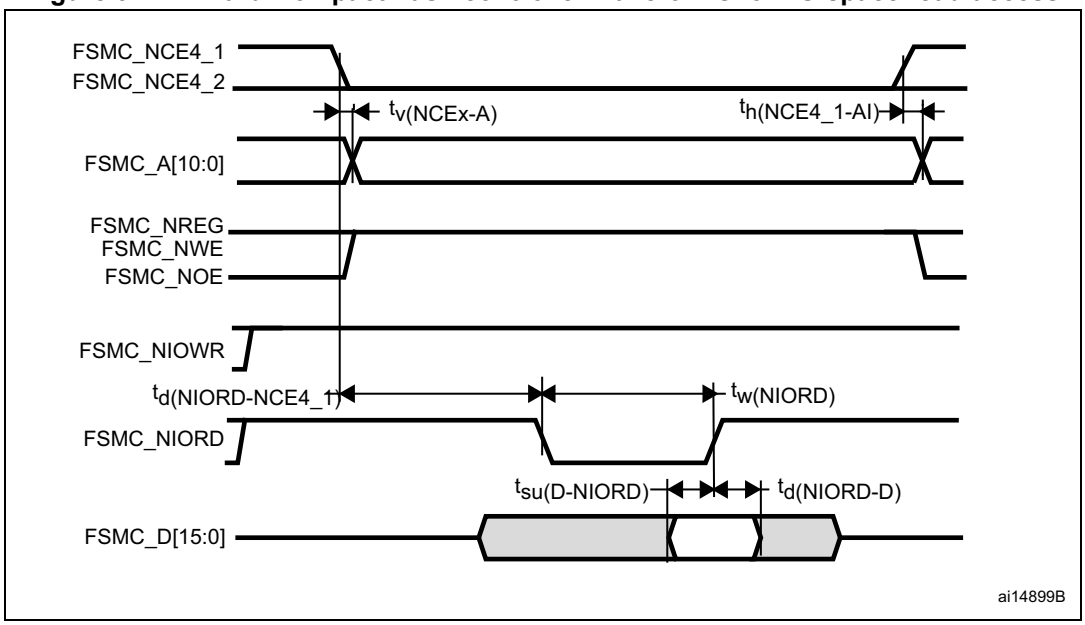


**Figure 35. PC Card/CompactFlash controller waveforms for I/O space write access**

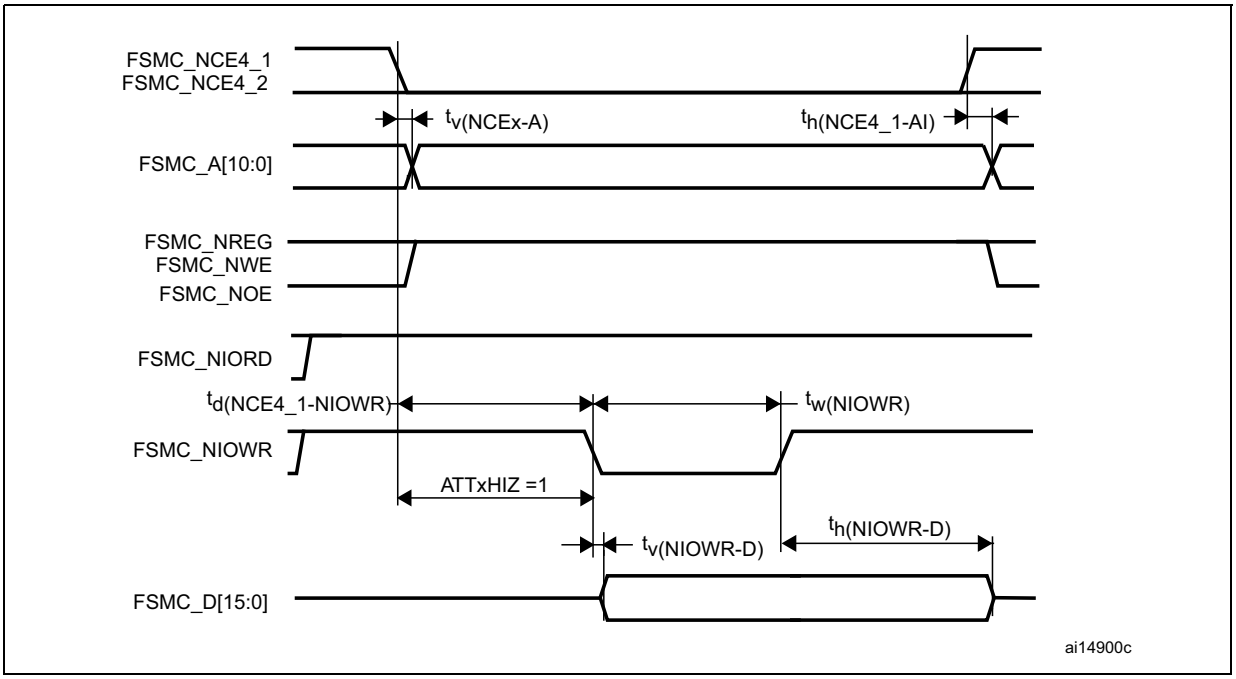



**Table 40. Switching characteristics for PC Card/CF read and write cycles in attribute/common space**

| Symbol | Parameter | Min | Max | Unit |
|---|---|---|---|---|
| $t_{v(NCEx-A)}$ | FSMC_NCEx low to FSMC_Ay valid | - | 0 | ns |
| $t_{h(NCEx-AI)}$ | FSMC_NCEx high to FSMC_Ax invalid | 0 | - | |
| $t_{d(NREG-NCEx)}$ | FSMC_NCEx low to FSMC_NREG valid | - | 2 | |
| $t_{h(NCEx-NREG)}$ | FSMC_NCEx high to FSMC_NREG invalid | $t_{HCLK}$ + 4 | - | |
| $t_{d(NCEx_NWE)}$ | FSMC_NCEx low to FSMC_NWE low | - | $5t_{HCLK}$ + 1 | |
| $t_{d(NCEx_NOE)}$ | FSMC_NCEx low to FSMC_NOE low | - | $5t_{HCLK}$ + 1 | |
| $t_{w(NOE)}$ | FSMC_NOE low width | $8t_{HCLK}$ - 0.5 | $8t_{HCLK}$ + 1 | |
| $t_{d(NOE-NCEx}$ | FSMC_NOE high to FSMC_NCEx high | $5t_{HCLK}$ - 0.5 | - | |
| $t_{su(D-NOE)}$ | FSMC_D[15:0] valid data before FSMC_NOE high | 32 | - | |
| $t_{h(NOE-D)}$ | FSMC_NOE high to FSMC_D[15:0] invalid | $t_{HCLK}$ | - | |
| $t_{w(NWE)}$ | FSMC_NWE low width | $8t_{HCLK}$ – 1 | $8t_{HCLK}$ + 4 | |
| $t_{d(NWE_NCEx)}$ | FSMC_NWE high to FSMC_NCEx high | $5t_{HCLK}$ + 1.5 | - | |
| $t_{d(NCEx-NWE)}$ | FSMC_NCEx low to FSMC_NWE low | - | $5t_{HCLK}$ + 1 | |
| $t_{v(NWE-D)}$ | FSMC_NWE low to FSMC_D[15:0] valid | - | 0 | |
| $t_{h(NWE-D)}$ | FSMC_NWE high to FSMC_D[15:0] invalid | $11t_{HCLK}$ | - | |
| $t_{d(D-NWE)}$ | FSMC_D[15:0] valid before FSMC_NWE high | $13t_{HCLK}$ + 2.5 | - | |

**Table 41. Switching characteristics for PC Card/CF read and write cycles in I/O space**

| Symbol | Parameter | Min | Max | Unit |
|---|---|---|---|---|
| $tw_{(NIOWR)}$ | FSMC_NIOWR low width | 8 THCLK | - | ns |
| $tv_{(NIOWR-D)}$ | FSMC_NIOWR low to FSMC_D[15:0] valid | - | 5 THCLK - 4 | ns |
| $th_{(NIOWR-D)}$ | FSMC_NIOWR high to FSMC_D[15:0] invalid | 11THCLK - 7 | - | ns |
| $td_{(NCE4_1-NIOWR)}$ | FSMC_NCE4_1 low to FSMC_NIOWR valid | - | 5THCLK + 1 | ns |
| $th_{(NCEx-NIOWR)}$ | FSMC_NCEx high to FSMC_NIOWR invalid | 5THCLK - 2.5 | - | ns |
| $td_{(NIORD-NCEx)}$ | FSMC_NCEx low to FSMC_NIORD valid | - | 5THCLK - 0.5 | ns |
| $th_{(NCEx-NIORD)}$ | FSMC_NCEx high to FSMC_NIORD) valid | 5 THCLK - 0.5 | - | ns |
| $tw_{(NIORD)}$ | FSMC_NIORD low width | 8THCLK | - | ns |
| $tsu_{(D-NIORD)}$ | FSMC_D[15:0] valid before FSMC_NIORD high | 28 | - | ns |
| $td_{(NIORD-D)}$ | FSMC_D[15:0] valid after FSMC_NIORD high | 3 | - | ns |

### NAND controller waveforms and timings

*Figure 36* through *Figure 39* represent synchronous waveforms and *Table 43* provides the corresponding timings. The results shown in this table are obtained with the following FSMC configuration:

- COM.FSMC_SetupTime = 0x00;
- COM.FSMC_WaitSetupTime = 0x02;
- COM.FSMC_HoldSetupTime = 0x01;
- COM.FSMC_HiZSetupTime = 0x00;
- ATT.FSMC_SetupTime = 0x00;
- ATT.FSMC_WaitSetupTime = 0x02;
- ATT.FSMC_HoldSetupTime = 0x01;
- ATT.FSMC_HiZSetupTime = 0x00;
- Bank = FSMC_Bank_NAND;
- MemoryDataWidth = FSMC_MemoryDataWidth_16b;
- ECC = FSMC_ECC_Enable;
- ECCPageSize = FSMC_ECCPageSize_512Bytes;
- TCLRSetupTime = 0;
- TARSetupTime = 0;

**Figure 36. NAND controller waveforms for read access**

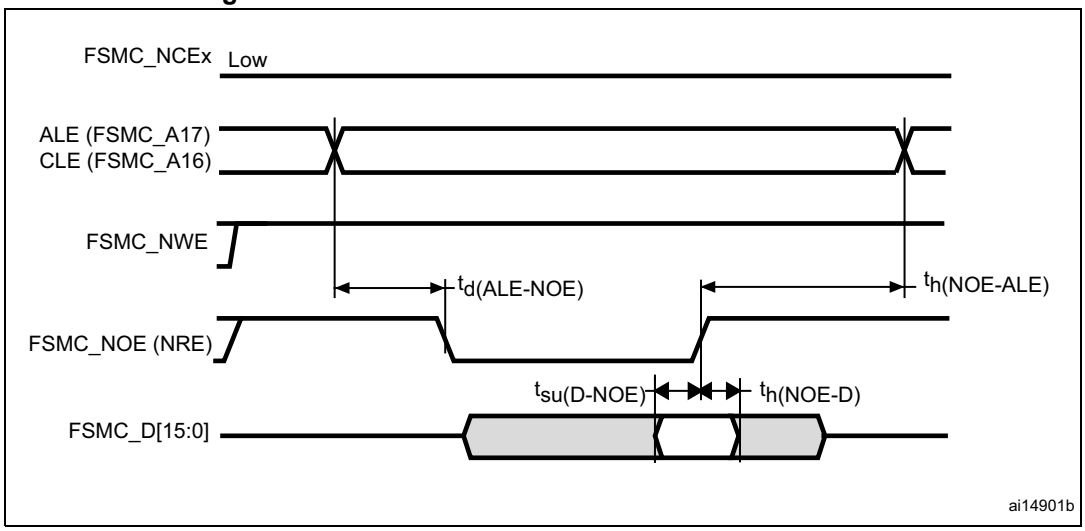



**Figure 37. NAND controller waveforms for write access**

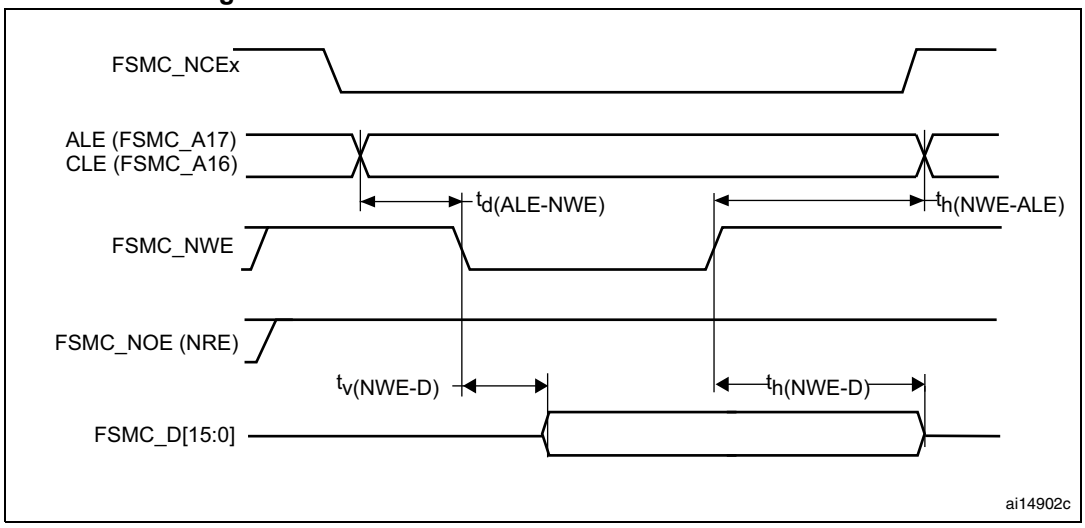


**Figure 38. NAND controller waveforms for common memory read access**

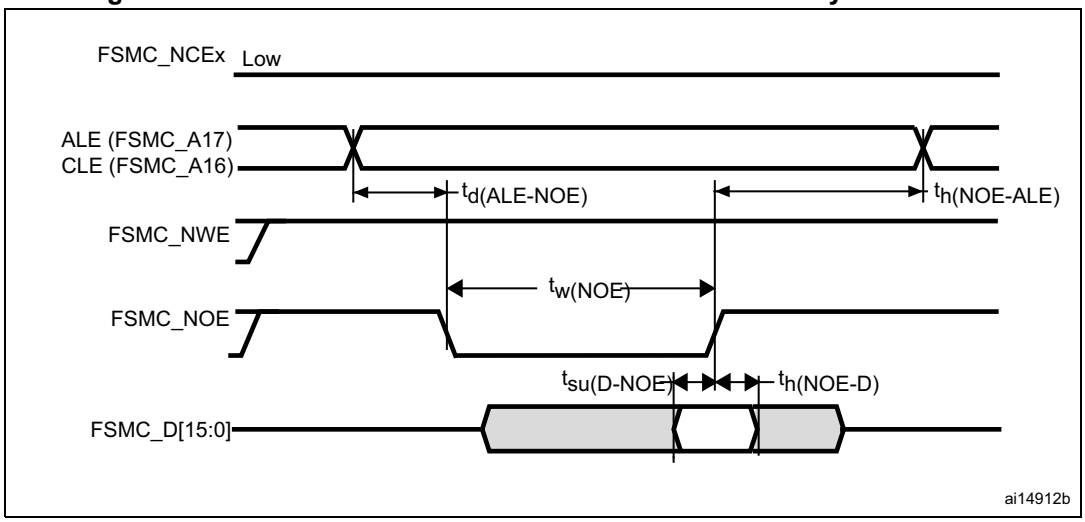



**Figure 39. NAND controller waveforms for common memory write access**

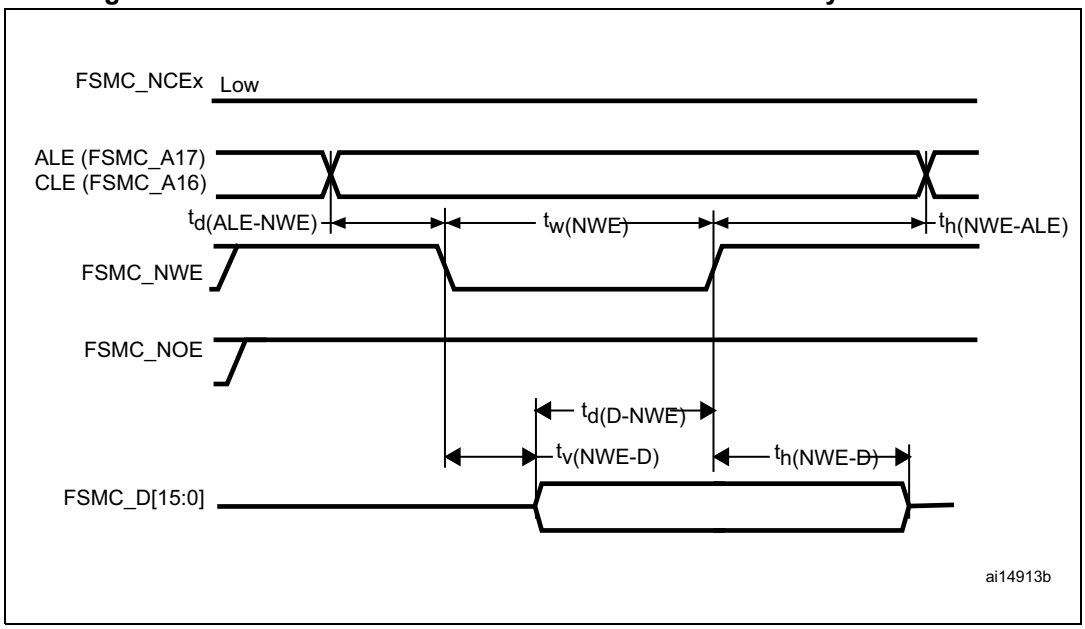



**Table 42. Switching characteristics for NAND Flash read cycles(1)**

| Symbol | Parameter | Min | Max | Unit |
|---|---|---|---|---|
| $t_{w(NOE)}$ | FSMC_NOE low width | $3t_{HCLK} - 1$ | $3t_{HCLK} + 1$ | ns |
| $t_{su(D-NOE)}$ | FSMC_D[15:0] valid data before FSMC_NOE high | 13 | - | ns |
| $t_{h(NOE-D)}$ | FSMC_D[15:0] valid data after FSMC_NOE high | 0 | - | ns |
| $t_{d(ALE-NOE)}$ | FSMC_ALE valid before FSMC_NOE low | - | $2t_{HCLK}$ | ns |
| $t_{h(NOE-ALE)}$ | FSMC_NWE high to FSMC_ALE invalid | $2t_{HCLK}$ | - | ns |

1. $C_L$ = 15 pF.

**Table 43. Switching characteristics for NAND Flash write cycles(1)**

| Symbol | Parameter | Min | Max | Unit |
|---|---|---|---|---|
| $t_{w(NWE)}$ | FSMC_NWE low width | $3t_{HCLK}$ | $3t_{HCLK}$ | ns |
| $t_{v(NWE-D)}$ | FSMC_NWE low to FSMC_D[15:0] valid | - | 0 | ns |
| $t_{h(NWE-D)}$ | FSMC_NWE high to FSMC_D[15:0] invalid | $2t_{HCLK} + 2$ | - | ns |
| $t_{d(ALE-NWE)}$ | FSMC_ALE valid before FSMC_NWE low | - | $3t_{HCLK} + 1.5$ | ns |
| $t_{h(NWE-ALE)}$ | FSMC_NWE high to FSMC_ALE invalid | $3t_{HCLK} + 8$ | - | ns |
| $t_{d(ALE-NOE)}$ | FSMC_ALE valid before FSMC_NOE low | - | $2t_{HCLK}$ | ns |
| $t_{h(NOE-ALE)}$ | FSMC_NWE high to FSMC_ALE invalid | $2t_{HCLK}$ | - | ns |

1. $C_L$ = 15 pF.

## 5.3.11 EMC characteristics

Susceptibility tests are performed on a sample basis during device characterization.

### Functional EMS (electromagnetic susceptibility)

While a simple application is executed on the device (toggling 2 LEDs through I/O ports). the device is stressed by two electromagnetic events until a failure occurs. The failure is indicated by the LEDs:

- **Electrostatic discharge (ESD)** (positive and negative) is applied to all device pins until a functional disturbance occurs. This test is compliant with the IEC 61000-4-2 standard.
- **FTB**: A Burst of Fast Transient voltage (positive and negative) is applied to $V_{DD}$ and $V_{SS}$ through a 100 pF capacitor, until a functional disturbance occurs. This test is compliant with the IEC 61000-4-4 standard.

A device reset allows normal operations to be resumed.

The test results are given in *Table 44*. They are based on the EMS levels and classes defined in application note AN1709.

**Table 44. EMS characteristics**

| Symbol | Parameter | Conditions | Level/ Class |
|---|---|---|---|
| $V_{FESD}$ | Voltage limits to be applied on any I/O pin to induce a functional disturbance | $V_{DD}$ = 3.3 V, LQFP144, $T_A$ = +25 °C, $f_{HCLK}$ = 72 MHz conforms to IEC 61000-4-2 | 2B |
| $V_{EFTB}$ | Fast transient voltage burst limits to be applied through 100 pF on $V_{DD}$ and $V_{SS}$ pins to induce a functional disturbance | $V_{DD}$ = 3.3 V, LQFP144, $T_A$ = +25 °C, $f_{HCLK}$ = 72 MHz conforms to IEC 61000-4-4 | 4A |

### Designing hardened software to avoid noise problems

EMC characterization and optimization are performed at component level with a typical application environment and simplified MCU software. It should be noted that good EMC performance is highly dependent on the user application and the software in particular.

Therefore it is recommended that the user applies EMC software optimization and prequalification tests in relation with the EMC level requested for his application.

Software recommendations

The software flowchart must include the management of runaway conditions such as:

- Corrupted program counter
- Unexpected reset
- Critical Data corruption (control registers...)

Prequalification trials

Most of the common failures (unexpected reset and program counter corruption) can be reproduced by manually forcing a low state on the NRST pin or the Oscillator pins for 1 second.

To complete these trials, ESD stress can be applied directly on the device, over the range of specification values. When unexpected behavior is detected, the software can be hardened to prevent unrecoverable errors occurring (see application note AN1015).

### Electromagnetic Interference (EMI)

The electromagnetic field emitted by the device are monitored while a simple application is executed (toggling 2 LEDs through the I/O ports). This emission test is compliant with IEC 61967-2 standard which specifies the test board and the pin loading.

**Table 45. EMI characteristics**

| Symbol | Parameter | Conditions | Monitored frequency band | Max vs. [$f_{HSE}/f_{HCLK}$] | | Unit |
|---|---|---|---|---|---|---|
| | | | | 8/48 MHz | 8/72 MHz | |
| $S_{EMI}$ | Peak level | $V_{DD}$ = 3.3 V, $T_A$ = 25 °C, LQFP144 package compliant with IEC 61967-2 | 0.1 to 30 MHz | 8 | 12 | dBµV |
| | | | 30 to 130 MHz | 31 | 21 | |
| | | | 130 MHz to 1GHz | 28 | 33 | |
| | | | SAE EMI Level | 4 | 4 | - |

## 5.3.12 Absolute maximum ratings (electrical sensitivity)

Based on three different tests (ESD, LU) using specific measurement methods, the device is stressed in order to determine its performance in terms of electrical sensitivity.

### Electrostatic discharge (ESD)

Electrostatic discharges (a positive then a negative pulse separated by 1 second) are applied to the pins of each sample according to each pin combination. The sample size depends on the number of supply pins in the device (3 parts × (n+1) supply pins). This test conforms to the JESD22-A114/C101 standard.

**Table 46. ESD absolute maximum ratings**

| Symbol | Ratings | Conditions | Class | Maximum value(1) | Unit |
|---|---|---|---|---|---|
| $V_{ESD(HBM)}$ | Electrostatic discharge voltage (human body model) | $T_A$ = +25 °C, conforming to JESD22-A114 | 2 | 2000 | V |
| $V_{ESD(CDM)}$ | Electrostatic discharge voltage (charge device model) | $T_A$ = +25 °C, conforming to JESD22-C101 | III | 500 | |

1. Guaranteed by characterization results, not tested in production.

### Static latch-up

Two complementary static tests are required on six parts to assess the latch-up performance:

- A supply overvoltage is applied to each power supply pin
- A current injection is applied to each input, output and configurable I/O pin

These tests are compliant with EIA/JESD 78A IC latch-up standard.

**Table 47. Electrical sensitivities**

| Symbol | Parameter | Conditions | Class |
|---|---|---|---|
| LU | Static latch-up class | $T_A$ = +105 °C conforming to JESD78A | II level A |

## 5.3.13 I/O current injection characteristics

As a general rule, current injection to the I/O pins, due to external voltage below $V_{SS}$ or above $V_{DD}$ (for standard, 3 V-capable I/O pins) should be avoided during normal product operation. However, in order to give an indication of the robustness of the microcontroller in cases when abnormal injection accidentally happens, susceptibility tests are performed on a sample basis during device characterization.

### Functional susceptibilty to I/O current injection

While a simple application is executed on the device, the device is stressed by injecting current into the I/O pins programmed in floating input mode. While current is injected into the I/O pin, one at a time, the device is checked for functional failures.

The failure is indicated by an out of range parameter: ADC error above a certain limit (>5 LSB TUE), out of spec current injection on adjacent pins or other functional failure (for example reset, oscillator frequency deviation).

The test results are given in *Table 48*

**Table 48. I/O current injection susceptibility**

| Symbol | Description | Functional susceptibility | | Unit |
|---|---|---|---|---|
| | | Negative injection | Positive injection | |
| $I_{INJ}$ | Injected current on OSC_IN32, OSC_OUT32, PA4, PA5, PC13 | -0 | +0 | mA |
| | Injected current on all FT pins | -5 | +0 | |
| | Injected current on any other pin | -5 | +5 | |

## 5.3.14 I/O port characteristics

### General input/output characteristics

Unless otherwise specified, the parameters given in *Table 49* are derived from tests performed under the conditions summarized in *Table 10*. All I/Os are CMOS and TTL compliant.

**Table 49. I/O static characteristics**

| Symbol | Parameter | Conditions | Min | Typ | Max | Unit |
|---|---|---|---|---|---|---|
| $V_{IL}$ | Standard IO input low level voltage | - | –0.3 | - | 0.28*($V_{DD}$-2 V)+0.8 V | V |
| | IO FT(1) input low level voltage | | –0.3 | - | 0.32*($V_{DD}$-2 V)+0.75 V | V |
| $V_{IH}$ | Standard IO input high level voltage | - | 0.41*($V_{DD}$-2 V)+1.3 V | - | $V_{DD}$+0.3 | V |
| | IO FT(1) input high level voltage | $V_{DD}$ > 2 V | 0.42*($V_{DD}$-2 V)+1 V | - | 5.5 | V |
| | | $V_{DD} \leq$ 2 V | | | 5.2 | |
| $V_{hys}$ | Standard IO Schmitt trigger voltage hysteresis(2) | - | 200 | - | - | mV |
| | IO FT Schmitt trigger voltage hysteresis(2) | | 5% $V_{DD}$(3) | - | - | mV |
| $I_{lkg}$ | Input leakage current (4) | $V_{SS} \leq V_{IN} \leq V_{DD}$ Standard I/Os | - | - | ±1 | µA |
| | | $V_{IN}$= 5 V, I/O FT | - | - | 3 | |
| $R_{PU}$ | Weak pull-up equivalent resistor(5) | $V_{IN} = V_{SS}$ | 30 | 40 | 50 | kΩ |
| $R_{PD}$ | Weak pull-down equivalent resistor(5) | $V_{IN} = V_{DD}$ | 30 | 40 | 50 | kΩ |
| $C_{IO}$ | I/O pin capacitance | - | - | 5 | - | pF |

1. FT = Five-volt tolerant. In order to sustain a voltage higher than $V_{DD}$+0.3 the internal pull-up/pull-down resistors must be disabled.
2. Hysteresis voltage between Schmitt trigger switching levels. Guaranteed by characterization results, not tested in production.
3. With a minimum of 100 mV.
4. Leakage could be higher than max. if negative current is injected on adjacent pins.
5. Pull-up and pull-down resistors are designed with a true resistance in series with a switchable PMOS/NMOS. This MOS/NMOS contribution to the series resistance is minimum (~10% order).

All I/Os are CMOS and TTL compliant (no software configuration required). Their characteristics cover more than the strict CMOS-technology or TTL parameters. The coverage of these requirements is shown in *Figure 40* and *Figure 41* for standard I/Os, and in *Figure 42* and *Figure 43* for 5 V tolerant I/Os.

**Figure 40. Standard I/O input characteristics - CMOS port**

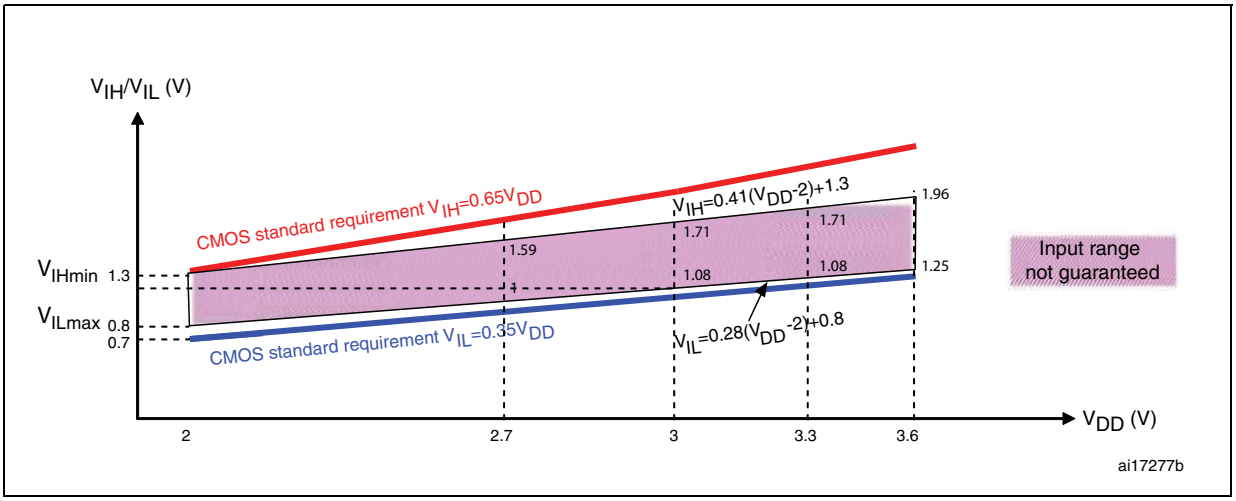



**Figure 41. Standard I/O input characteristics - TTL port**

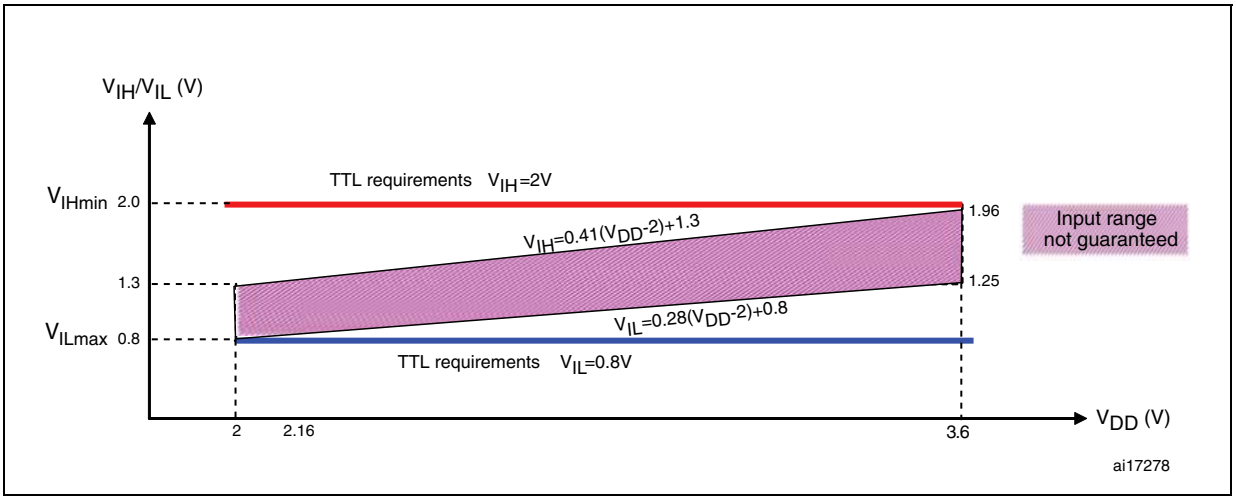



**Figure 42. 5 V tolerant I/O input characteristics - CMOS port**

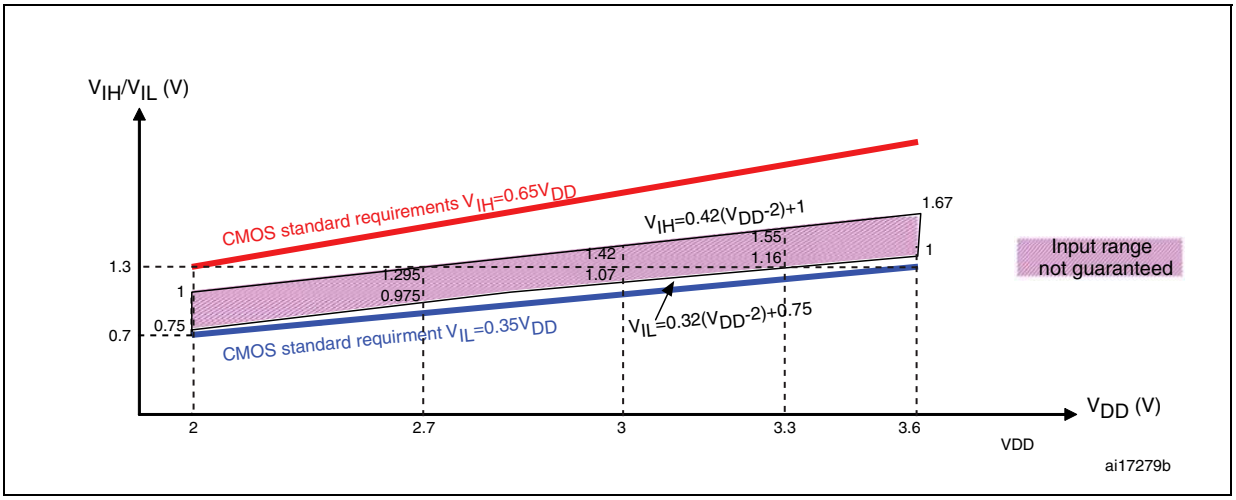
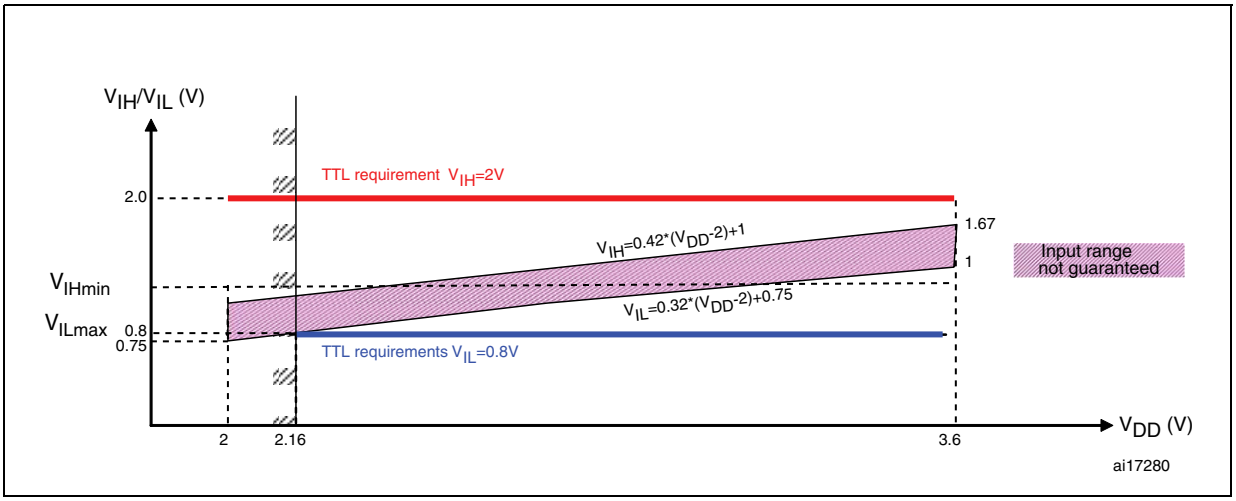


**Figure 43. 5 V tolerant I/O input characteristics - TTL port**




## Output driving current

The GPIOs (general purpose input/outputs) can sink or source up to ±8 mA, and sink or source up to ± 20 mA (with a relaxed $V_{OL}/V_{OH}$) except PC13, PC14 and PC15 which can sink or source up to ±3 mA. When using the GPIOs PC13 to PC15 in output mode, the speed should not exceed 2 MHz with a maximum load of 30 pF.

In the user application, the number of I/O pins which can drive current must be limited to respect the absolute maximum rating specified in *Section 5.2*:

- The sum of the currents sourced by all the I/Os on $V_{DD,}$ plus the maximum Run consumption of the MCU sourced on $V_{DD,}$ cannot exceed the absolute maximum rating $I_{VDD}$ (see *Table 8*).
- The sum of the currents sunk by all the I/Os on $V_{SS}$ plus the maximum Run consumption of the MCU sunk on $V_{SS}$ cannot exceed the absolute maximum rating $I_{VSS}$ (see *Table 8*).

## Output voltage levels

Unless otherwise specified, the parameters given in *Table 50* are derived from tests performed under ambient temperature and $V_{DD}$ supply voltage conditions summarized in *Table 10*. All I/Os are CMOS and TTL compliant.

**Table 50. Output voltage characteristics**

| Symbol | Parameter | Conditions | Min | Max | Unit |
|---|---|---|---|---|---|
| $V_{OL}$ (1) | Output low level voltage for an I/O pin when 8 pins are sunk at same time | TTL port(3) $I_{IO}$ = +8 mA 2.7 V < $V_{DD}$ < 3.6 V | - | 0.4 | V |
| $V_{OH}$ (2) | Output high level voltage for an I/O pin when 8 pins are sourced at same time | | $V_{DD}$–0.4 | - | |
| $V_{OL}$ (1) | Output low level voltage for an I/O pin when 8 pins are sunk at same time | CMOS port(3) $I_{IO}$ =+ 8mA 2.7 V < $V_{DD}$ < 3.6 V | - | 0.4 | V |
| $V_{OH}$ (2) | Output high level voltage for an I/O pin when 8 pins are sourced at same time | | 2.4 | - | |

**Table 50. Output voltage characteristics (continued)**

| Symbol | Parameter | Conditions | Min | Max | Unit |
|---|---|---|---|---|---|
| $V_{OL}$(1)(4) | Output low level voltage for an I/O pin when 8 pins are sunk at same time | $I_{IO}$ = +20 mA<br>2.7 V < $V_{DD}$ < 3.6 V | - | 1.3 | V |
| $V_{OH}$(2)(4) | Output high level voltage for an I/O pin when 8 pins are sourced at same time | | $V_{DD}$–1.3 | - | |
| $V_{OL}$(1)(4) | Output low level voltage for an I/O pin when 8 pins are sunk at same time | $I_{IO}$ = +6 mA<br>2 V < $V_{DD}$ < 2.7 V | - | 0.4 | V |
| $V_{OH}$(2)(4) | Output high level voltage for an I/O pin when 8 pins are sourced at same time | | $V_{DD}$–0.4 | - | |

1. The $I_{IO}$ current sunk by the device must always respect the absolute maximum rating specified in *Table 8* and the sum of $I_{IO}$ (I/O ports and control pins) must not exceed $I_{VSS}$.
2. The $I_{IO}$ current sourced by the device must always respect the absolute maximum rating specified in *Table 8* and the sum of $I_{IO}$ (I/O ports and control pins) must not exceed $I_{VDD}$.
3. TTL and CMOS outputs are compatible with JEDEC standards JESD36 and JESD52.
4. Guaranteed by characterization results, not tested in production.

### Input/output AC characteristics

The definition and values of input/output AC characteristics are given in *Figure 44* and *Table 51*, respectively.

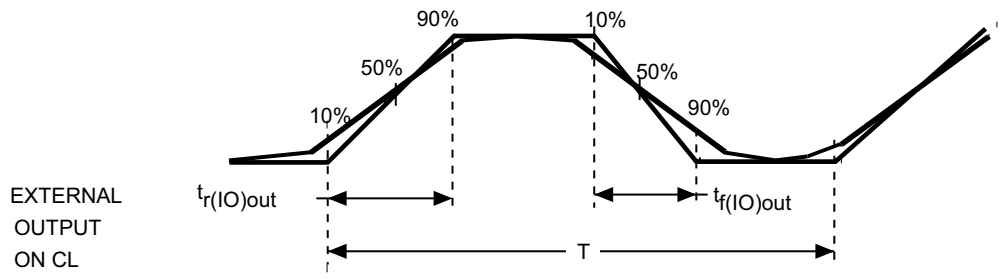
Unless otherwise specified, the parameters given in *Table 51* are derived from tests performed under ambient temperature and $V_{DD}$ supply voltage conditions summarized in *Table 10*.

**Table 51. I/O AC characteristics(1)**

| MODEx[1:0] bit value(1) | Symbol | Parameter | Conditions | Min | Max | Unit |
|---|---|---|---|---|---|---|
| 10 | $f_{max(IO)out}$ | Maximum frequency(2) | $C_L$ = 50 pF, $V_{DD}$ = 2 V to 3.6 V | - | 2 | MHz |
| | $t_{f(IO)out}$ | Output high to low level fall time | $C_L$ = 50 pF, $V_{DD}$ = 2 V to 3.6 V | - | 125(3) | ns |
| | $t_{r(IO)out}$ | Output low to high level rise time | | - | 125(3) | |
| 01 | $f_{max(IO)out}$ | Maximum frequency(2) | $C_L$ = 50 pF, $V_{DD}$ = 2 V to 3.6 V | - | 10 | MHz |
| | $t_{f(IO)out}$ | Output high to low level fall time | $C_L$ = 50 pF, $V_{DD}$ = 2 V to 3.6 V | - | 25(3) | ns |
| | $t_{r(IO)out}$ | Output low to high level rise time | | - | 25(3) | |
| 11 | $F_{max(IO)out}$ | Maximum frequency(2) | $C_L$ = 30 pF, $V_{DD}$ = 2.7 V to 3.6 V | - | 50 | MHz |
| | | | $C_L$ = 50 pF, $V_{DD}$ = 2.7 V to 3.6 V | - | 30 | MHz |
| | | | $C_L$ = 50 pF, $V_{DD}$ = 2 V to 2.7 V | - | 20 | MHz |
| | $t_{f(IO)out}$ | Output high to low level fall time | $C_L$ = 30 pF, $V_{DD}$ = 2.7 V to 3.6 V | - | 5(3) | ns |
| | | | $C_L$ = 50 pF, $V_{DD}$ = 2.7 V to 3.6 V | - | 8(3) | |
| | | | $C_L$ = 50 pF, $V_{DD}$ = 2 V to 2.7 V | - | 12(3) | |
| | $t_{r(IO)out}$ | Output low to high level rise time | $C_L$ = 30 pF, $V_{DD}$ = 2.7 V to 3.6 V | - | 5(3) | |
| | | | $C_L$ = 50 pF, $V_{DD}$ = 2.7 V to 3.6 V | - | 8(3) | |
| | | | $C_L$ = 50 pF, $V_{DD}$ = 2 V to 2.7 V | - | 12(3) | |
| - | $t_{EXTIpw}$ | Pulse width of external signals detected by the EXTI controller | - | 10 | - | ns |

1. The I/O speed is configured using the MODEx[1:0] bits. Refer to the STM32F10xxx reference manual for a description of GPIO Port configuration register.
2. The maximum frequency is defined in *Figure 44*.
3. Guaranteed by design, not tested in production.

**Figure 44. I/O AC characteristics definition**




Maximum frequency is achieved if ($t_r + t_f$) ≤ (2/3)T and if the duty cycle is (45-55%) when loaded by CL specified in the table " *I/O AC characteristics*".

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## 5.3.15 NRST pin characteristics

The NRST pin input driver uses CMOS technology. It is connected to a permanent pull-up resistor, $R_{PU}$ (see *Table 49*).

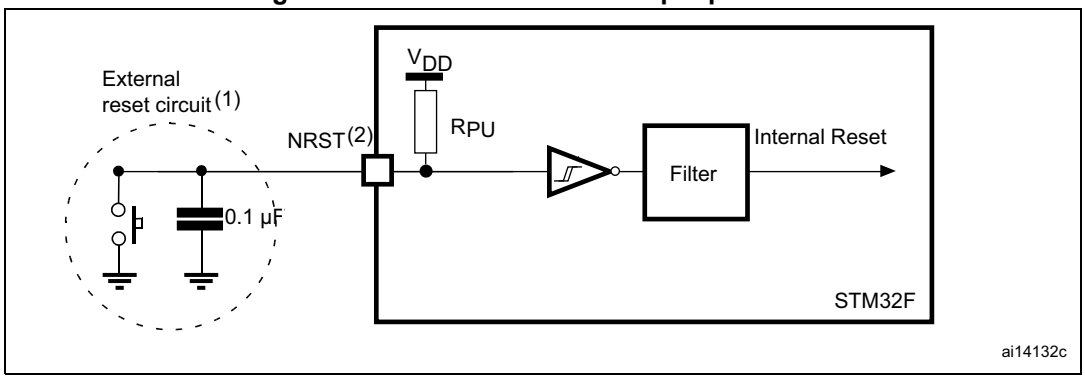
Unless otherwise specified, the parameters given in *Table 52* are derived from tests performed under ambient temperature and $V_{DD}$ supply voltage conditions summarized in *Table 10*.

**Table 52. NRST pin characteristics**

| Symbol | Parameter | Conditions | Min | Typ | Max | Unit |
|---|---|---|---|---|---|---|
| $V_{IL(NRST)}$(1) | NRST Input low level voltage | - | –0.5 | - | 0.8 | V |
| $V_{IH(NRST)}$(1) | NRST Input high level voltage | - | 2 | - | $V_{DD}$+0.5 | |
| $V_{hys(NRST)}$ | NRST Schmitt trigger voltage hysteresis | - | - | 200 | - | mV |
| $R_{PU}$ | Weak pull-up equivalent resistor(2) | $V_{IN} = V_{SS}$ | 30 | 40 | 50 | kΩ |
| $V_{F(NRST)}$(1) | NRST Input filtered pulse | - | - | - | 100 | ns |
| $V_{NF(NRST)}$(1) | NRST Input not filtered pulse | - | 300 | - | - | ns |

1. Guaranteed by design, not tested in production.
2. The pull-up is designed with a true resistance in series with a switchable PMOS. This PMOS contribution to the series resistance must be minimum (~10% order).

**Figure 45. Recommended NRST pin protection**




1. The reset network protects the device against parasitic resets.
2. The user must ensure that the level on the NRST pin can go below the $V_{IL(NRST)}$ max level specified in *Table 52*. Otherwise the reset will not be taken into account by the device.

## 5.3.16 TIM timer characteristics

The parameters given in *Table 53* are guaranteed by design.

Refer to *Section 5.3.14: I/O port characteristics* for details on the input/output alternate function characteristics (output compare, input capture, external clock, PWM output).

**Table 53. TIMx(1) characteristics**

| Symbol | Parameter | Conditions | Min | Max | Unit |
|---|---|---|---|---|---|
| $t_{res(TIM)}$ | Timer resolution time | - | 1 | - | $t_{TIMxCLK}$ |
| | | $f_{TIMxCLK}$ = 72 MHz | 13.9 | - | ns |
| $f_{EXT}$ | Timer external clock frequency on CH1 to CH4 | - | 0 | $f_{TIMxCLK}/2$ | MHz |
| | | $f_{TIMxCLK}$ = 72 MHz | 0 | 36 | MHz |
| $Res_{TIM}$ | Timer resolution | - | - | 16 | bit |
| $t_{COUNTER}$ | 16-bit counter clock period when internal clock is selected | - | 1 | 65536 | $t_{TIMxCLK}$ |
| | | $f_{TIMxCLK}$ = 72 MHz | 0.0139 | 910 | µs |
| $t_{MAX_COUNT}$ | Maximum possible count | - | - | 65536 × 65536 | $t_{TIMxCLK}$ |
| | | $f_{TIMxCLK}$ = 72 MHz | - | 59.6 | s |

1. TIMx is used as a general term to refer to the TIM1, TIM2, TIM3 and TIM4 timers.

## 5.3.17 Communications interfaces

### I²C interface characteristics

The STM32F103xF, STM32F103xD and STM32F103xGSTM32F103xF and STM32F103xG performance line I²C interface meets the requirements of the standard I²C communication protocol with the following restrictions: the I/O pins SDA and SCL are mapped to are not “true” open-drain. When configured as open-drain, the PMOS connected between the I/O pin and $V_{DD}$ is disabled, but is still present.

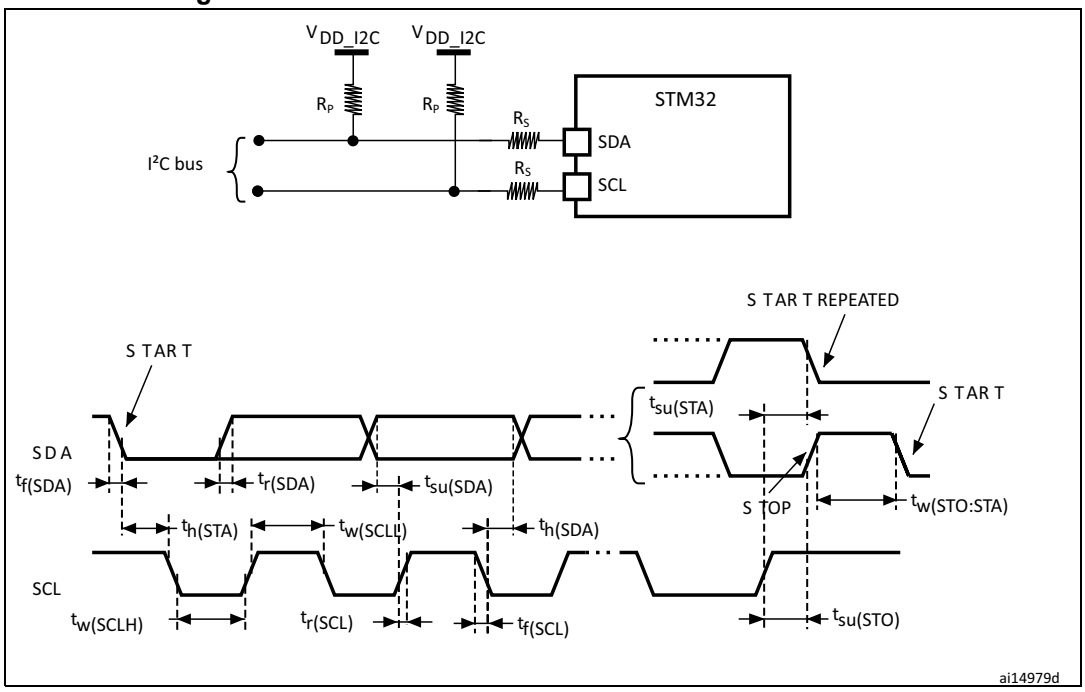
The I²C characteristics are described in *Table 54*. Refer also to *Section 5.3.14: I/O port characteristics* for more details on the input/output alternate function characteristics (SDA and SCL).

**Table 54. I²C characteristics**

| Symbol | Parameter | Standard mode I²C(1)(2) | | Fast mode I²C(1)(2) | | Unit |
|---|---|---|---|---|---|---|
| | | Min | Max | Min | Max | |
| $t_{w(SCLL)}$ | SCL clock low time | 4.7 | - | 1.3 | - | µs |
| $t_{w(SCLH)}$ | SCL clock high time | 4.0 | - | 0.6 | - | |
| $t_{su(SDA)}$ | SDA setup time | 250 | - | 100 | - | ns |
| $t_{h(SDA)}$ | SDA data hold time | - | 3450(3) | - | 900(3) | |
| $t_{r(SDA)}$ $t_{r(SCL)}$ | SDA and SCL rise time | - | 1000 | - | 300 | |
| $t_{f(SDA)}$ $t_{f(SCL)}$ | SDA and SCL fall time | - | 300 | - | 300 | |
| $t_{h(STA)}$ | Start condition hold time | 4.0 | - | 0.6 | - | µs |
| $t_{su(STA)}$ | Repeated Start condition setup time | 4.7 | - | 0.6 | - | |
| $t_{su(STO)}$ | Stop condition setup time | 4.0 | - | 0.6 | - | µs |
| $t_{w(STO:STA)}$ | Stop to Start condition time (bus free) | 4.7 | - | 1.3 | - | µs |
| $C_b$ | Capacitive load for each bus line | - | 400 | - | 400 | pF |
| $t_{SP}$ | Pulse width of the spikes that are suppressed by the analog filter for standard and fast mode | 0 | 50(4) | 0 | 50(4) | µs |

1. Guaranteed by design, not tested in production.
2. $f_{PCLK1}$ must be at least 2 MHz to achieve standard mode I²C frequencies. It must be at least 4 MHz to achieve the fast mode I²C frequencies and it must be a multiple of 10 MHz in order to reach the I2C fast mode maximum clock speed of 400 kHz.
3. The device must internally provide a hold time of at least 300ns for the SDA signal in order to bridge the undefined region on the falling edge of SCL.
4. The minimum width of the spikes filtered by the analog filter is above $t_{SP}$(max).

**Figure 46. I²C bus AC waveforms and measurement circuit**




1. Measurement points are done at CMOS levels: $0.3V_{DD}$ and $0.7V_{DD}$.
2. Rs: Series protection resistors.
3. Rp: Pull-up resistors.
4. VDD_I2C : I2C bus supply

**Table 55. SCL frequency ($f_{PCLK1}$= 36 MHz.,$V_{DD_I2C}$ = 3.3 V)(1)(2)**

| $f_{SCL}$ (kHz) | I2C_CCR value |
|---|---|
| | $R_P$ = 4.7 kΩ |
| 400 | 0x801E |
| 300 | 0x8028 |
| 200 | 0x803C |
| 100 | 0x00B4 |
| 50 | 0x0168 |
| 20 | 0x0384 |

1. $R_P$ = External pull-up resistance, $f_{SCL}$ = I²C speed.
2. For speeds around 200 kHz, the tolerance on the achieved speed is of ±5%. For other speed ranges, the tolerance on the achieved speed ±2%. These variations depend on the accuracy of the external components used to design the application.

## $I^2S$ - SPI characteristics

Unless otherwise specified, the parameters given in *Table 56* for SPI or in *Table 57* for $I^2S$ are derived from tests performed under ambient temperature, $f_{PCLKx}$ frequency and $V_{DD}$ supply voltage conditions summarized in *Table 10*.

Refer to *Section 5.3.14: I/O port characteristics* for more details on the input/output alternate function characteristics (NSS, SCK, MOSI, MISO for SPI and WS, CK, SD for $I^2S$).

**Table 56. SPI characteristics**

| Symbol | Parameter | Conditions | Min | Max | Unit |
|---|---|---|---|---|---|
| $f_{SCK}$<br>$1/t_{c(SCK)}$ | SPI clock frequency | Master mode | - | 18 | MHz |
| | | Slave mode | - | 18 | |
| $t_{r(SCK)}$<br>$t_{f(SCK)}$ | SPI clock rise and fall time | Capacitive load: C = 30 pF | - | 8 | ns |
| DuCy(SCK) | SPI slave input clock duty cycle | Slave mode | 30 | 70 | % |
| $t_{su(NSS)}$ (1) | NSS setup time | Slave mode | $4t_{PCLK}$ | - | ns |
| $t_{h(NSS)}$ (1) | NSS hold time | Slave mode | $2t_{PCLK}$ | - | |
| $t_{w(SCKH)}$ (1)<br>$t_{w(SCKL)}$ (1) | SCK high and low time | Master mode, $f_{PCLK}$ = 36 MHz, presc = 4 | 50 | 60 | |
| $t_{su(MI)}$ (1)<br>$t_{su(SI)}$ (1) | Data input setup time | Master mode | 5 | - | |
| | | Slave mode | 5 | - | |
| $t_{h(MI)}$ (1) | Data input hold time | Master mode | 5 | - | |
| $t_{h(SI)}$ (1) | | Slave mode | 4 | - | |
| $t_{a(SO)}$ (1)(2) | Data output access time | Slave mode, $f_{PCLK}$ = 20 MHz | 0 | $3t_{PCLK}$ | |
| $t_{dis(SO)}$ (1)(3) | Data output disable time | Slave mode | 2 | 10 | |
| $t_{v(SO)}$ (1) | Data output valid time | Slave mode (after enable edge) | - | 25 | |
| $t_{v(MO)}$ (1) | Data output valid time | Master mode (after enable edge) | - | 5 | |
| $t_{h(SO)}$ (1) | Data output hold time | Slave mode (after enable edge) | 15 | - | |
| $t_{h(MO)}$ (1) | | Master mode (after enable edge) | 2 | - | |

1. Guaranteed by characterization results, not tested in production.
2. Min time is for the minimum time to drive the output and the max time is for the maximum time to validate the data.
3. Min time is for the minimum time to invalidate the output and the max time is for the maximum time to put the data in Hi-Z

**Figure 47. SPI timing diagram - slave mode and CPHA = 0**

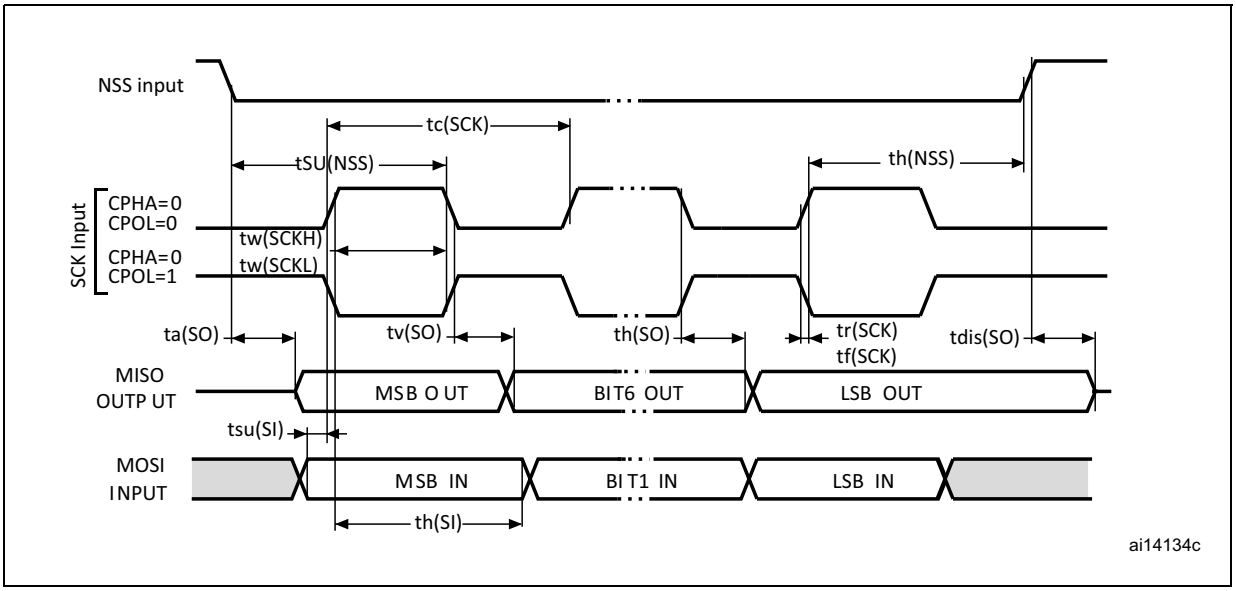
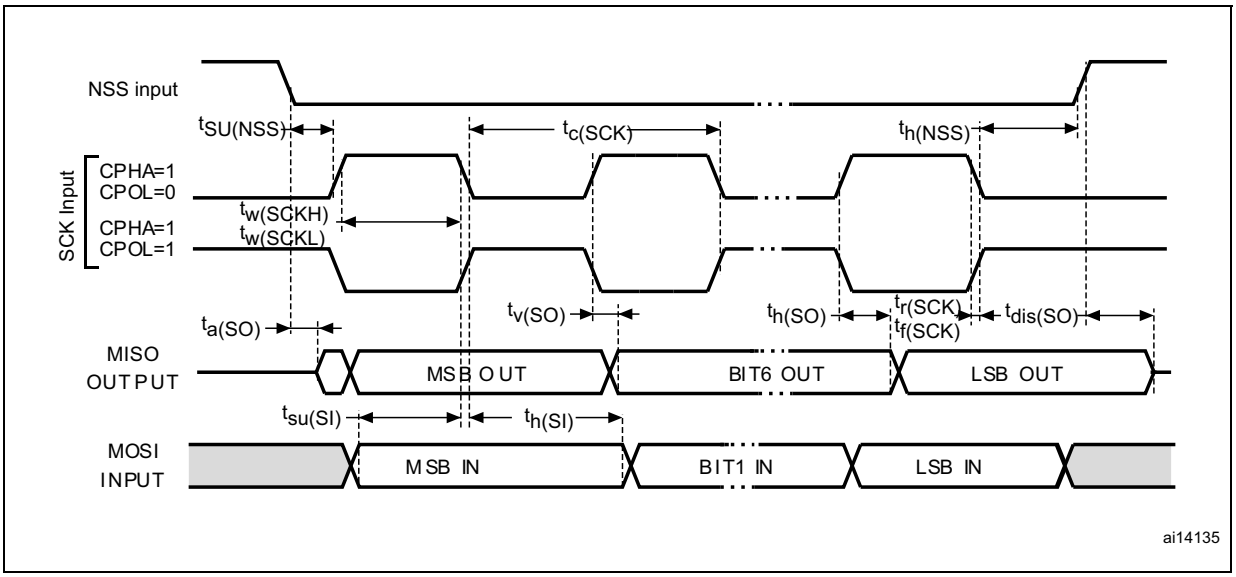
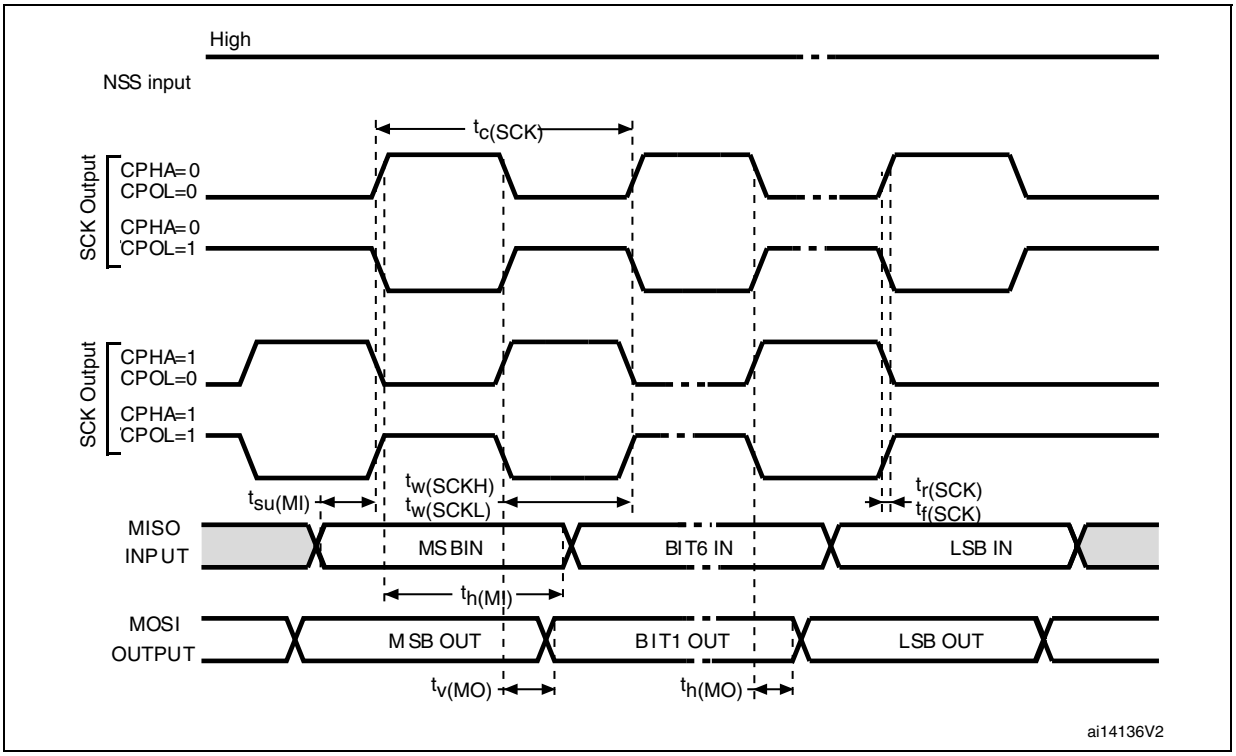



**Figure 48. SPI timing diagram - slave mode and CPHA = 1(1)**




1. Measurement points are done at CMOS levels: $0.3V_{DD}$ and $0.7V_{DD}$.

**Figure 49. SPI timing diagram - master mode(1)**



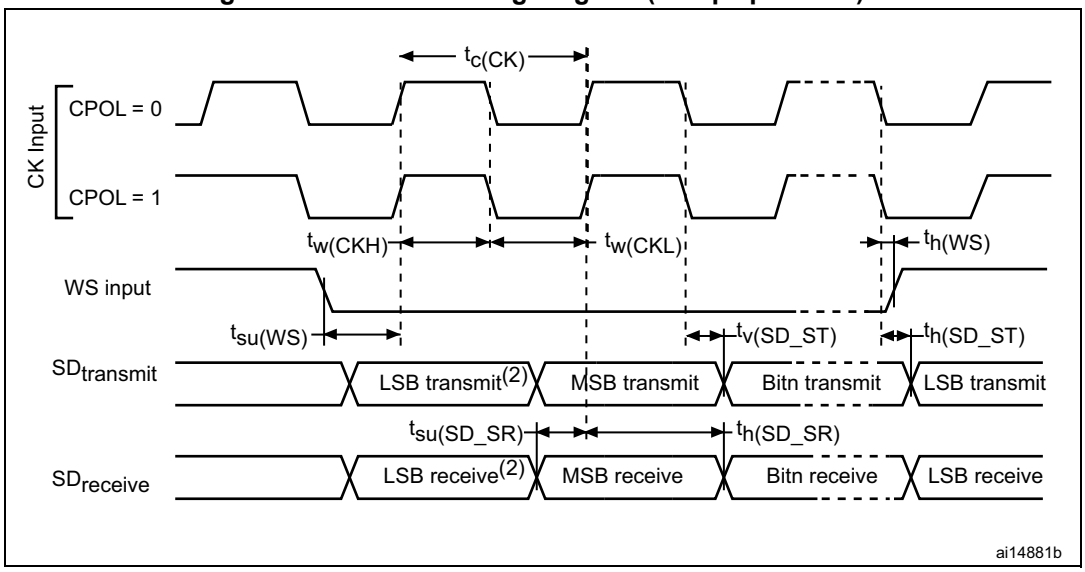

1. Measurement points are done at CMOS levels: $0.3V_{DD}$ and $0.7V_{DD}$.

**Table 57. $I^2S$ characteristics**

| Symbol | Parameter | Conditions | | Min | Max | Unit |
|---|---|---|---|---|---|---|
| DuCy(SCK) | I2S slave input clock duty cycle | Slave mode | | 30 | 70 | % |
| $f_{CK}$<br>$1/t_{c(CK)}$ | $I^2S$ clock frequency | Master mode (data: 16 bits, Audio frequency = 48 kHz) | | 1.522 | 1.525 | MHz |
| | | Slave mode | | 0 | 6.5 | |
| $t_{r(CK)}$<br>$t_{f(CK)}$ | $I^2S$ clock rise and fall time | Capacitive load $C_L$ = 50 pF | | - | 8 | ns |
| $t_{v(WS)}$ (1) | WS valid time | Master mode | | 3 | - | |
| $t_{h(WS)}$ (1) | WS hold time | Master mode | I2S2 | 2 | - | |
| | | | I2S3 | 0 | - | |
| $t_{su(WS)}$ (1) | WS setup time | Slave mode | | 4 | - | |
| $t_{h(WS)}$ (1) | WS hold time | Slave mode | | 0 | - | |
| $t_{w(CKH)}$ (1) | CK high and low time | Master $f_{PCLK}$= 16 MHz, audio frequency = 48 kHz | | 312.5 | - | |
| $t_{w(CKL)}$ (1) | | | | 345 | - | |
| $t_{su(SD_MR)}$ (1) | Data input setup time | Master receiver | I2S2 | 2 | - | |
| | | | I2S3 | 6.5 | - | |
| $t_{su(SD_SR)}$ (1) | Data input setup time | Slave receiver | | 1.5 | - | |
| $t_{h(SD_MR)}$ (1)(2) | Data input hold time | Master receiver | | 0 | - | |
| $t_{h(SD_SR)}$ (1)(2) | | Slave receiver | | 0.5 | - | |
| $t_{v(SD_ST)}$ (1)(2) | Data output valid time | Slave transmitter (after enable edge) | | - | 18 | |
| $t_{h(SD_ST)}$ (1) | Data output hold time | Slave transmitter (after enable edge) | | 11 | - | |
| $t_{v(SD_MT)}$ (1)(2) | Data output valid time | Master transmitter (after enable edge) | | - | 3 | |
| $t_{h(SD_MT)}$ (1) | Data output hold time | Master transmitter (after enable edge) | | 0 | - | |

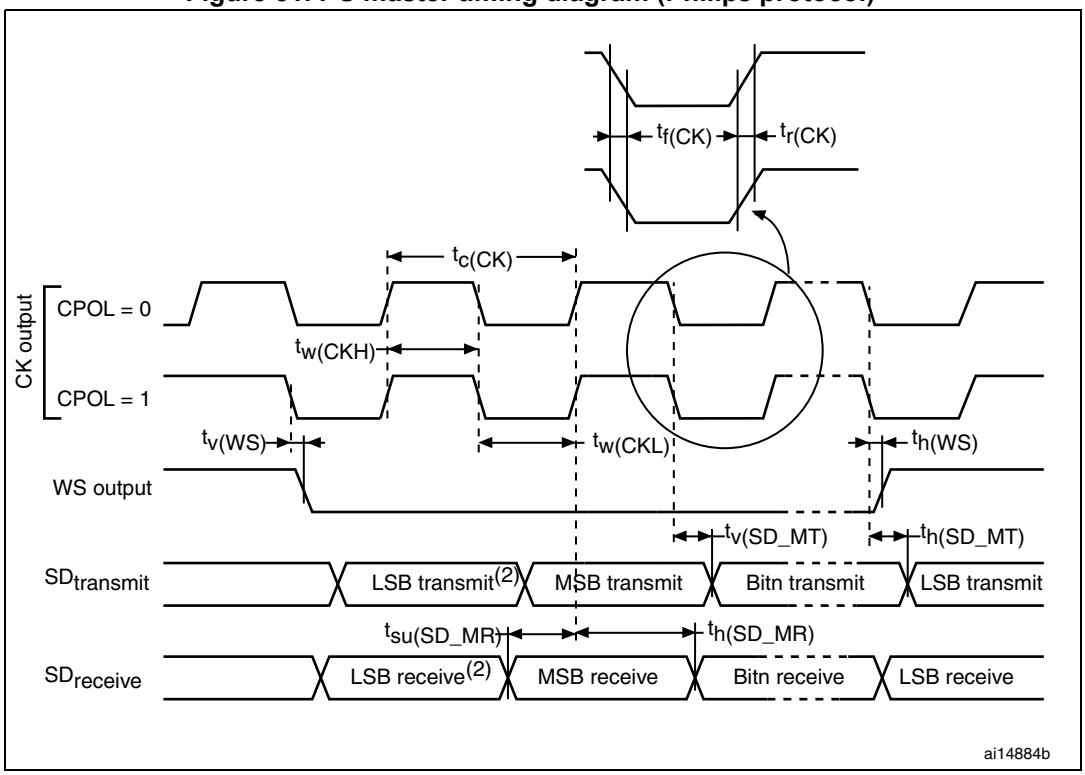
1. Guaranteed by design and/or characterization results, not tested in production.
2. Depends on $f_{PCLK}$. For example, if $f_{PCLK}$=8 MHz, then $T_{PCLK}$ = $1/f_{PLCLK}$ =125 ns.

**Figure 50. I²S slave timing diagram (Philips protocol)(1)**




1. Measurement points are done at CMOS levels: $0.3 \times V_{DD}$ and $0.7 \times V_{DD}$.
2. LSB transmit/receive of the previously transmitted byte. No LSB transmit/receive is sent before the first byte.

**Figure 51. I²S master timing diagram (Philips protocol)(1)**




1. Guaranteed by characterization results, not tested in production.
2. LSB transmit/receive of the previously transmitted byte. No LSB transmit/receive is sent before the first byte.

### SD/SDIO MMC card host interface (SDIO) characteristics

Unless otherwise specified, the parameters given in *Table 58* are derived from tests performed under ambient temperature, $f_{PCLKx}$ frequency and $V_{DD}$ supply voltage conditions summarized in *Table 10*.

Refer to *Section 5.3.14: I/O port characteristics* for more details on the input/output alternate function characteristics (D[7:0], CMD, CK).

**Figure 52. SDIO high-speed mode**

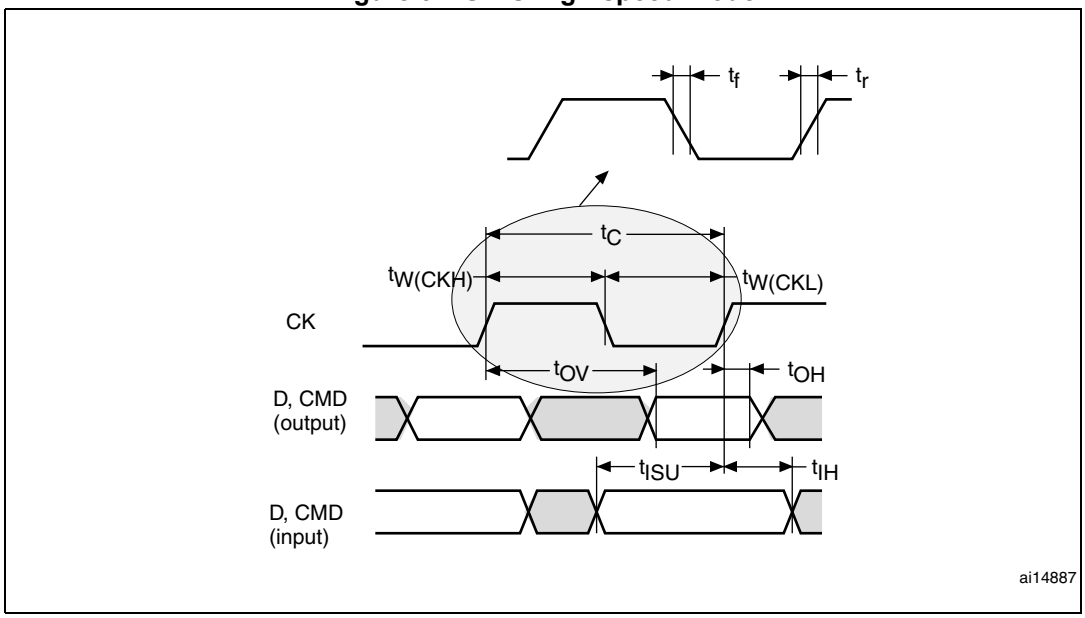



**Figure 53. SD default mode**

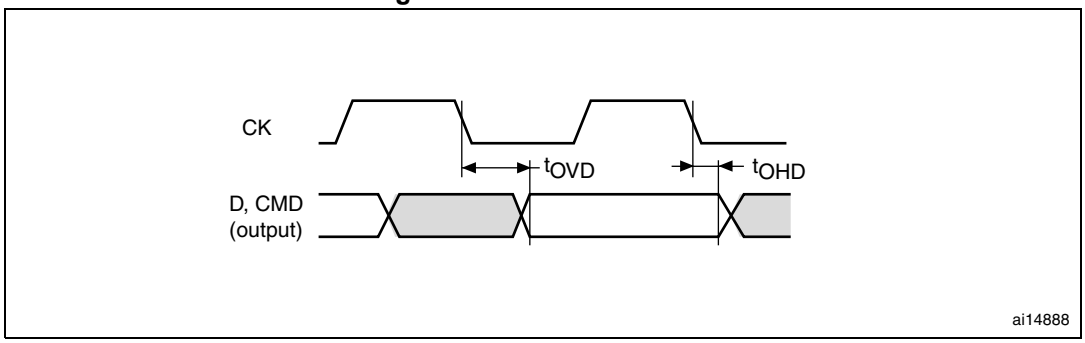



**Table 58. SD / MMC characteristics**

| Symbol | Parameter | Conditions | Min | Max | Unit |
|---|---|---|---|---|---|
| $f_{PP}$ | Clock frequency in data transfer mode | $C_L \leq$ 30 pF | 0 | 48 | MHz |
| tW(CKL) | Clock low time, $f_{PP}$ = 16 MHz | $C_L \leq$ 30 pF | 32 | - | ns |
| tW(CKH) | Clock high time, $f_{PP}$ = 16 MHz | $C_L \leq$ 30 pF | 30 | - | |
| $t_r$ | Clock rise time | $C_L \leq$ 30 pF | - | 4 | |
| $t_f$ | Clock fall time | $C_L \leq$ 30 pF | - | 5 | |

**Table 58. SD / MMC characteristics**

| Symbol | Parameter | Conditions | Min | Max | Unit |
|---|---|---|---|---|---|
| CMD, D inputs (referenced to CK) | | | | | |
| $t_{ISU}$ | Input setup time | $C_L \leq 30$ pF | 2 | - | ns |
| $t_{IH}$ | Input hold time | $C_L \leq 30$ pF | 0 | - | |
| CMD, D outputs (referenced to CK) in MMC and SD HS mode | | | | | |
| $t_{OV}$ | Output valid time | $C_L \leq 30$ pF | - | 6 | ns |
| $t_{OH}$ | Output hold time | $C_L \leq 30$ pF | 0 | - | |
| **CMD, D outputs (referenced to CK) i**n SD default mode(1) | | | | | |
| $t_{OVD}$ | Output valid default time | $C_L \leq 30$ pF | - | 7 | ns |
| $t_{OHD}$ | Output hold default time | $C_L \leq 30$ pF | 0.5 | - | |

1. Refer to SDIO_CLKCR, the SDI clock control register to control the CK output.

## USB characteristics

The USB interface is USB-IF certified (Full Speed).

**Table 59. USB startup time**

| Symbol | Parameter | Max | Unit |
|---|---|---|---|
| $t_{STARTUP}$(1) | USB transceiver startup time | 1 | µs |

1. Guaranteed by design, not tested in production.

**Table 60. USB DC electrical characteristics**

| Symbol | Parameter | Conditions | Min.(1) | Max.(1) | Unit |
|---|---|---|---|---|---|
| **Input levels** | | | | | |
| $V_{DD}$ | USB operating voltage(2) | - | 3.0(3) | 3.6 | V |
| $V_{DI}$(4) | Differential input sensitivity | I(USB_DP, USB_DM) | 0.2 | - | V |
| $V_{CM}$(4) | Differential common mode range | Includes $V_{DI}$ range | 0.8 | 2.5 | |
| $V_{SE}$(4) | Single ended receiver threshold | | 1.3 | 2.0 | |
| **Output levels** | | | | | |
| $V_{OL}$ | Static output level low | $R_L$ of 1.5 kΩ to 3.6 V(5) | - | 0.3 | V |
| $V_{OH}$ | Static output level high | $R_L$ of 15 kΩ to $V_{SS}$(5) | 2.8 | 3.6 | |

1. All the voltages are measured from the local ground potential.
2. To be compliant with the USB 2.0 full-speed electrical specification, the USB_DP (D+) pin should be pulled up with a 1.5 kΩ resistor to a 3.0-to-3.6 V voltage range.
3. The STM32F103xF/G USB functionality is ensured down to 2.7 V but not the full USB electrical characteristics which are degraded in the 2.7-to-3.0 V $V_{DD}$ voltage range.
4. Guaranteed by characterization results, not tested in production.
5. $R_L$ is the load connected on the USB drivers

**Figure 54. USB timings: definition of data signal rise and fall time**

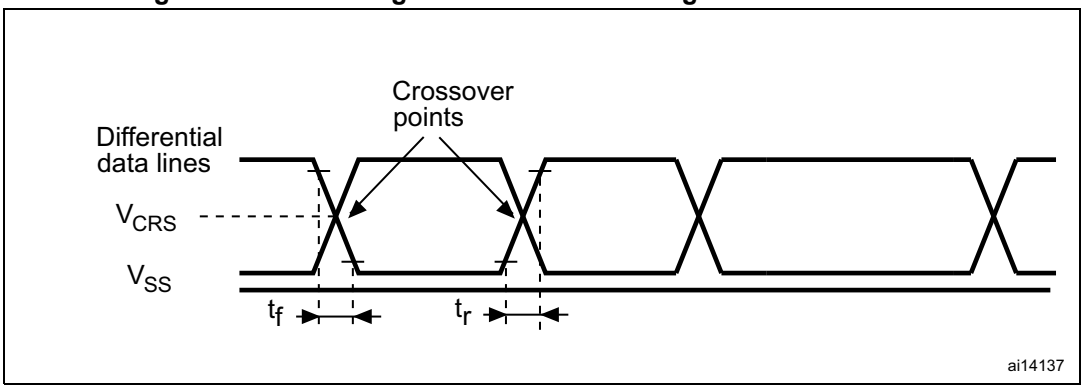



**Table 61. USB: full-speed electrical characteristics**

| Driver characteristics(1) | | | | | |
|---|---|---|---|---|---|
| **Symbol** | **Parameter** | **Conditions** | **Min** | **Max** | **Unit** |
| $t_r$ | Rise time(2) | $C_L$ = 50 pF | 4 | 20 | ns |
| $t_f$ | Fall Time(2) | $C_L$ = 50 pF | 4 | 20 | ns |
| $t_{rfm}$ | Rise/ fall time matching | $t_r/t_f$ | 90 | 110 | % |
| $V_{CRS}$ | Output signal crossover voltage | - | 1.3 | 2.0 | V |

1. Guaranteed by design, not tested in production.
2. Measured from 10% to 90% of the data signal. For more detailed informations, please refer to USB Specification - Chapter 7 (version 2.0).

### 5.3.18 CAN (controller area network) interface

Refer to *Section 5.3.14: I/O port characteristics* for more details on the input/output alternate function characteristics (CAN_TX and CAN_RX).

### 5.3.19 12-bit ADC characteristics

Unless otherwise specified, the parameters given in *Table 62* are preliminary values derived from tests performed under ambient temperature, $f_{PCLK2}$ frequency and $V_{DDA}$ supply voltage conditions summarized in *Table 10*.

*Note: It is recommended to perform a calibration after each power-up.*

**Table 62. ADC characteristics**

| Symbol | Parameter | Conditions | Min | Typ | Max | Unit |
|---|---|---|---|---|---|---|
| $V_{DDA}$ | Power supply | - | 2.4 | - | 3.6 | V |
| $V_{REF+}$ | Positive reference voltage | - | 2.4 | - | $V_{DDA}$ | V |
| $I_{VREF}$ | Current on the $V_{REF}$ input pin | - | - | 160 | 220(1) | µA |
| $f_{ADC}$ | ADC clock frequency | - | 0.6 | - | 14 | MHz |
| $f_S$(2) | Sampling rate | - | 0.05 | - | 1 | MHz |
| $f_{TRIG}$(2) | External trigger frequency | $f_{ADC}$ = 14 MHz | - | - | 823 | kHz |
| | | - | - | - | 17 | $1/f_{ADC}$ |
| $V_{AIN}$ | Conversion voltage range(3) | - | 0 ($V_{SSA}$ or $V_{REF-}$ tied to ground) | - | $V_{REF+}$ | V |
| $R_{AIN}$(2) | External input impedance | See *Equation 1* and *Table 63* for details | - | - | 50 | kΩ |
| $R_{ADC}$(2) | Sampling switch resistance | - | - | - | 1 | kΩ |
| $C_{ADC}$(2) | Internal sample and hold capacitor | - | - | - | 8 | pF |
| $t_{CAL}$(2) | Calibration time | $f_{ADC}$ = 14 MHz | 5.9 | | | µs |
| | | - | 83 | | | $1/f_{ADC}$ |
| $t_{lat}$(2) | Injection trigger conversion latency | $f_{ADC}$ = 14 MHz | - | - | 0.214 | µs |
| | | - | - | - | 3(4) | $1/f_{ADC}$ |
| $t_{latr}$(2) | Regular trigger conversion latency | $f_{ADC}$ = 14 MHz | - | - | 0.143 | µs |
| | | - | - | - | 2(4) | $1/f_{ADC}$ |
| $t_S$(2) | Sampling time | $f_{ADC}$ = 14 MHz | 0.107 | - | 17.1 | µs |
| | | - | 1.5 | - | 239.5 | $1/f_{ADC}$ |
| $t_{STAB}$(2) | Power-up time | - | 0 | 0 | 1 | µs |
| $t_{CONV}$(2) | Total conversion time (including sampling time) | $f_{ADC}$ = 14 MHz | 1 | | 18 | µs |
| | | - | 14 to 252 ($t_S$ for sampling +12.5 for successive approximation) | | | $1/f_{ADC}$ |

1. Guaranteed by characterization results, not tested in production.

2. Guaranteed by design, not tested in production.
3. $V_{REF+}$ can be internally connected to $V_{DDA}$ and $V_{REF-}$ can be internally connected to $V_{SSA}$, depending on the package. Refer to *Section 3: Pinouts and pin descriptions* for further details.
4. For external triggers, a delay of $1/f_{PCLK2}$ must be added to the latency specified in *Table 62*.

**Equation 1: $R_{AIN}$ max formula**

$$R_{AIN} < \frac{T_S}{f_{ADC} \times C_{ADC} \times \ln(2^{N+2})} - R_{ADC}$$

The formula above (*Equation 1*) is used to determine the maximum external impedance allowed for an error below 1/4 of LSB. Here N = 12 (from 12-bit resolution).

**Table 63. $R_{AIN}$ max for $f_{ADC}$ = 14 MHz(1)**

| $T_s$ (cycles) | $t_S$ (µs) | $R_{AIN}$ max (kΩ) |
|---|---|---|
| 1.5 | 0.11 | 0.4 |
| 7.5 | 0.54 | 5.9 |
| 13.5 | 0.96 | 11.4 |
| 28.5 | 2.04 | 25.2 |
| 41.5 | 2.96 | 37.2 |
| 55.5 | 3.96 | 50 |
| 71.5 | 5.11 | NA |
| 239.5 | 17.1 | NA |

1. Guaranteed by design, not tested in production.

**Table 64. ADC accuracy - limited test conditions(1)(2)**

| Symbol | Parameter | Test conditions | Typ | Max(3) | Unit |
|---|---|---|---|---|---|
| ET | Total unadjusted error | $f_{PCLK2}$ = 56 MHz, $f_{ADC}$ = 14 MHz, $R_{AIN}$ < 10 kΩ, $V_{DDA}$ = 3 V to 3.6 V $T_A$ = 25 °C Measurements made after ADC calibration $V_{REF+} = V_{DDA}$ | ±1.3 | ±2 | LSB |
| EO | Offset error | | ±1 | ±1.5 | |
| EG | Gain error | | ±0.5 | ±1.5 | |
| ED | Differential linearity error | | ±0.7 | ±1 | |
| EL | Integral linearity error | | ±0.8 | ±1.5 | |

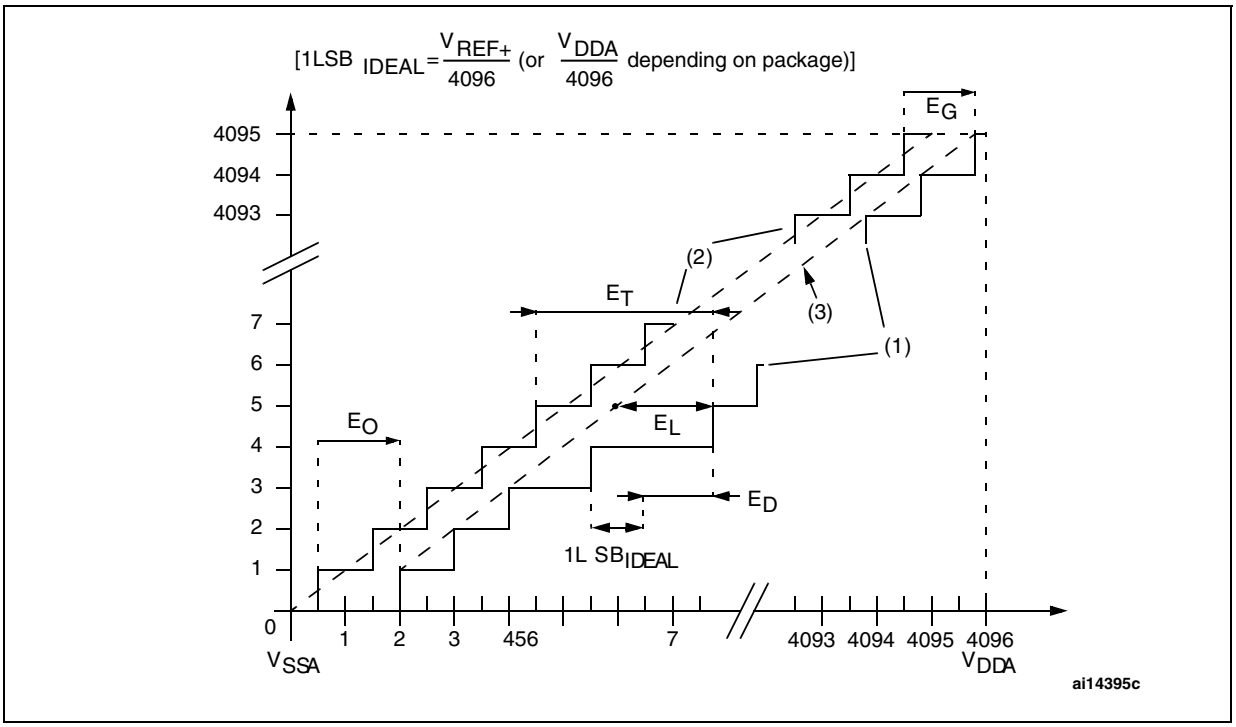
1. ADC DC accuracy values are measured after internal calibration.
2. ADC Accuracy vs. Negative Injection Current: Injecting negative current on any analog input pins should be avoided as this significantly reduces the accuracy of the conversion being performed on another analog input. It is recommended to add a Schottky diode (pin to ground) to analog pins which may potentially inject negative current.
   Any positive injection current within the limits specified for $I_{INJ(PIN)}$ and $\Sigma I_{INJ(PIN)}$ in *Section 5.3.14* does not affect the ADC accuracy.
3. Guaranteed by characterization results, not tested in production.

**Table 65. ADC accuracy(1) (2)(3)**

| Symbol | Parameter | Test conditions | Typ | Max(4) | Unit |
|---|---|---|---|---|---|
| ET | Total unadjusted error | $f_{PCLK2}$ = 56 MHz, $f_{ADC}$ = 14 MHz, $R_{AIN}$ < 10 kΩ, $V_{DDA}$ = 2.4 V to 3.6 V Measurements made after ADC calibration | ±2 | ±5 | LSB |
| EO | Offset error | | ±1.5 | ±2.5 | |
| EG | Gain error | | ±1.5 | ±3 | |
| ED | Differential linearity error | | ±1 | ±2 | |
| EL | Integral linearity error | | ±1.5 | ±3 | |

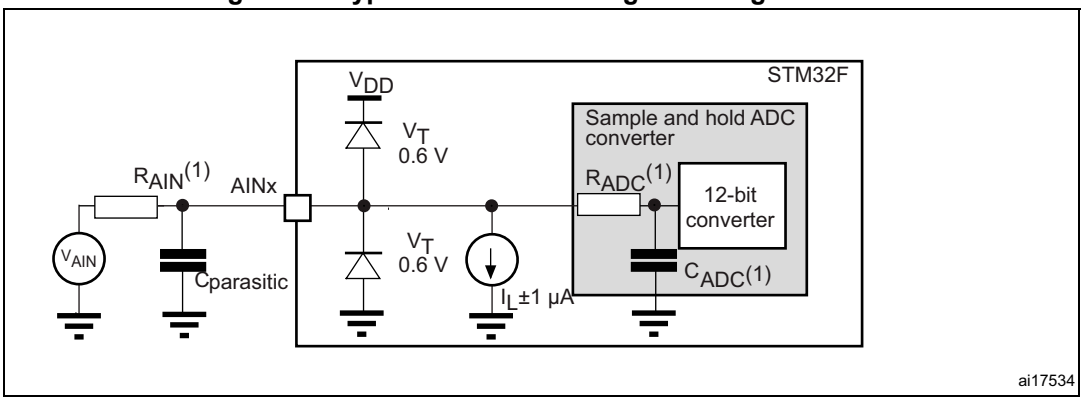
1. ADC DC accuracy values are measured after internal calibration.
2. Better performance could be achieved in restricted $V_{DD}$, frequency, $V_{REF}$ and temperature ranges.
3. ADC Accuracy vs. Negative Injection Current: Injecting negative current on any analog input pins should be avoided as this significantly reduces the accuracy of the conversion being performed on another analog input. It is recommended to add a Schottky diode (pin to ground) to analog pins which may potentially inject negative current.
   Any positive injection current within the limits specified for $I_{INJ(PIN)}$ and $\Sigma I_{INJ(PIN)}$ in *Section 5.3.14* does not affect the ADC accuracy.
4. Preliminary values.

**Figure 55. ADC accuracy characteristics**




1. Example of an actual transfer curve.
2. Ideal transfer curve.
3. End point correlation line.
4. $E_T$ = Total Unadjusted Error: maximum deviation between the actual and the ideal transfer curves.
   EO = Offset Error: deviation between the first actual transition and the first ideal one.
   EG = Gain Error: deviation between the last ideal transition and the last actual one.
   ED = Differential Linearity Error: maximum deviation between actual steps and the ideal one.
   EL = Integral Linearity Error: maximum deviation between any actual transition and the end point correlation line.

**Figure 56. Typical connection diagram using the ADC**

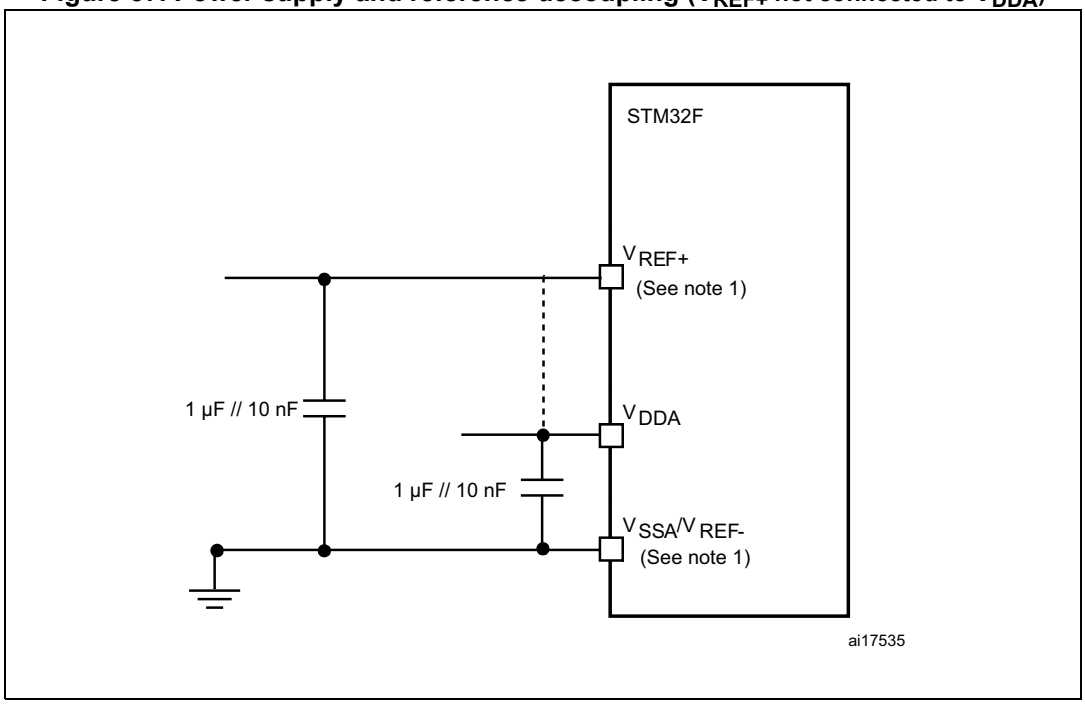



1. Refer to *Table 62* for the values of $R_{AIN}$, $R_{ADC}$ and $C_{ADC}$.
2. $C_{parasitic}$ represents the capacitance of the PCB (dependent on soldering and PCB layout quality) plus the pad capacitance (roughly 7 pF). A high $C_{parasitic}$ value will downgrade conversion accuracy. To remedy this, $f_{ADC}$ should be reduced.

## General PCB design guidelines

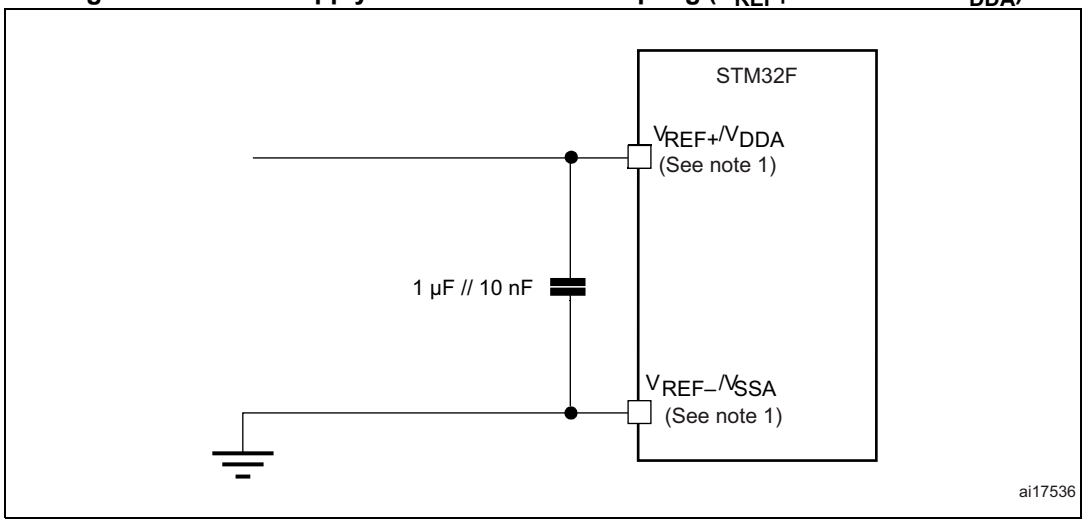
Power supply decoupling should be performed as shown in *Figure 57* or *Figure 58*, depending on whether $V_{REF+}$ is connected to $V_{DDA}$ or not. The 10 nF capacitors should be ceramic (good quality). They should be placed them as close as possible to the chip.

**Figure 57. Power supply and reference decoupling ($V_{REF+}$ not connected to $V_{DDA}$)**




1. $V_{REF+}$ and $V_{REF-}$ inputs are available only on 100-pin packages.

**Figure 58. Power supply and reference decoupling ($V_{REF+}$ connected to $V_{DDA}$)**




1. $V_{REF+}$ and $V_{REF-}$ inputs are available only on 100-pin packages.

### 5.3.20 DAC electrical specifications

**Table 66. DAC characteristics**

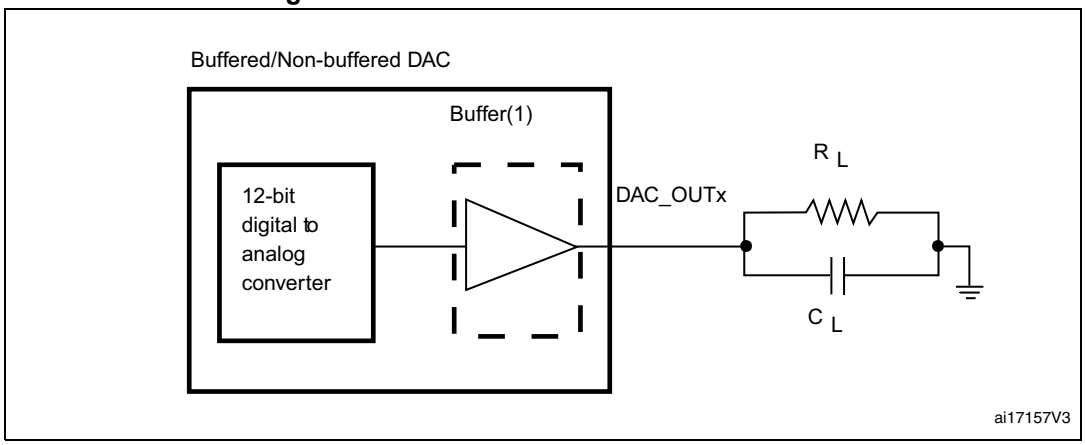
| Symbol | Parameter | Min | Typ | Max | Unit | Comments |
|---|---|---|---|---|---|---|
| $V_{DDA}$ | Analog supply voltage | 2.4 | - | 3.6 | V | |
| $V_{REF+}$ | Reference supply voltage | 2.4 | - | 3.6 | V | $V_{REF+}$ must always be below $V_{DDA}$ |
| $V_{SSA}$ | Ground | 0 | - | 0 | V | |
| $R_{LOAD}$(1) | Resistive load vs. $V_{SSA}$ with buffer ON | 5 | - | - | kΩ | |
| | Resistive load vs. $V_{DDA}$ with buffer ON | 15 | - | - | kΩ | |
| $R_O$(1) | Impedance output with buffer OFF | - | - | 15 | kΩ | When the buffer is OFF, the Minimum resistive load between DAC_OUT and $V_{SS}$ to have a 1% accuracy is 1.5 MΩ |
| $C_{LOAD}$(1) | Capacitive load | - | - | 50 | pF | Maximum capacitive load at DAC_OUT pin (when the buffer is ON). |
| DAC_OUT min(1) | Lower DAC_OUT voltage with buffer ON | 0.2 | - | - | V | It gives the maximum output excursion of the DAC. It corresponds to 12-bit input code (0x0E0) to (0xF1C) at $V_{REF+}$ = 3.6 V and (0x155) and (0xEAB) at $V_{REF+}$ = 2.4 V |
| DAC_OUT max(1) | Higher DAC_OUT voltage with buffer ON | - | - | $V_{DDA}$ – 0.2 | V | |
| DAC_OUT min(1) | Lower DAC_OUT voltage with buffer OFF | - | 0.5 | | mV | It gives the maximum output excursion of the DAC. |
| DAC_(1)OUT max(1) | Higher DAC_OUT voltage with buffer OFF | - | | $V_{REF+}$ – 10 mV | V | |
| $I_{DDVREF+}$ | DAC DC current consumption in quiescent mode (Standby mode) | - | | 380 | µA | With no load, worst code (0x0E4) at $V_{REF+}$ = 3.6 V in terms of DC consumption on the inputs |
| $I_{DDA}$ | DAC DC current consumption in quiescent mode(2) | - | | 380 | µA | With no load, middle code (0x800) on the inputs |
| | | - | | 480 | µA | With no load, worst code (0xF1C) at $V_{REF+}$ = 3.6 V in terms of DC consumption on the inputs |
| DNL(3) | Differential non linearity Difference between two consecutive code-1LSB) | - | | ±0.5 | LSB | Given for the DAC in 10-bit configuration |
| | | - | | ±3 | LSB | Given for the DAC in 12-bit configuration |

**Table 66. DAC characteristics (continued)**

| Symbol | Parameter | Min | Typ | Max | Unit | Comments |
|---|---|---|---|---|---|---|
| INL(2) | Integral non linearity (difference between measured value at Code i and the value at Code i on a line drawn between Code 0 and last Code 1023) | - | - | ±1 | LSB | Given for the DAC in 10-bit configuration |
| | | - | - | ±4 | LSB | Given for the DAC in 12-bit configuration |
| Offset(2) | Offset error (difference between measured value at Code (0x800) and the ideal value = $V_{REF+}$/2) | - | - | ±10 | mV | |
| | | - | - | ±3 | LSB | Given for the DAC in 10-bit at $V_{REF+}$ = 3.6 V |
| | | - | - | ±12 | LSB | Given for the DAC in 12-bit at $V_{REF+}$ = 3.6 V |
| Gain error(2) | Gain error | - | - | ±0.5 | % | Given for the DAC in 12bit configuration |
| $t_{SETTLING}$(2) | Settling time (full scale: for a 10-bit input code transition between the lowest and the highest input codes when DAC_OUT reaches final value ±1LSB | - | 3 | 4 | µs | $C_{LOAD} \leq$ 50 pF, $R_{LOAD} \geq$ 5 kΩ |
| Update rate(2) | Max frequency for a correct DAC_OUT change when small variation in the input code (from code i to i+1LSB) | - | - | 1 | MS/s | $C_{LOAD} \leq$ 50 pF, $R_{LOAD} \geq$ 5 kΩ |
| $t_{WAKEUP}$(2) | Wakeup time from off state (Setting the ENx bit in the DAC Control register) | - | 6.5 | 10 | µs | $C_{LOAD} \leq$ 50 pF, $R_{LOAD} \geq$ 5 kΩ input code between lowest and highest possible ones. |
| PSRR+ (1) | Power supply rejection ratio (to $V_{DDA}$) (static DC measurement | - | –67 | –40 | dB | No $R_{LOAD}$, $C_{LOAD}$ = 50 pF |

1. Guaranteed by design, not tested in production.
2. The quiescent mode corresponds to a state where the DAC maintains a stable output level to ensure that no dynamic consumption occurs.
3. Preliminary values.

**Figure 59. 12-bit buffered /non-buffered DAC**




1. The DAC integrates an output buffer that can be used to reduce the output impedance and to drive external loads directly without the use of an external operational amplifier. The buffer can be bypassed by configuring the BOFFx bit in the DAC_CR register.

## 5.3.21 Temperature sensor characteristics

**Table 67. TS characteristics**

| Symbol | Parameter | Min | Typ | Max | Unit |
|---|---|---|---|---|---|
| $T_L$ (1) | $V_{SENSE}$ linearity with temperature | - | ±1 | ±2 | °C |
| Avg_Slope(1) | Average slope | 4.0 | 4.3 | 4.6 | mV/°C |
| $V_{25}$ (1) | Voltage at 25 °C | 1.34 | 1.43 | 1.52 | V |
| $t_{START}$ (2) | Startup time | 4 | - | 10 | µs |
| $T_{S_temp}$ (3)(2) | ADC sampling time when reading the temperature | - | - | 17.1 | µs |

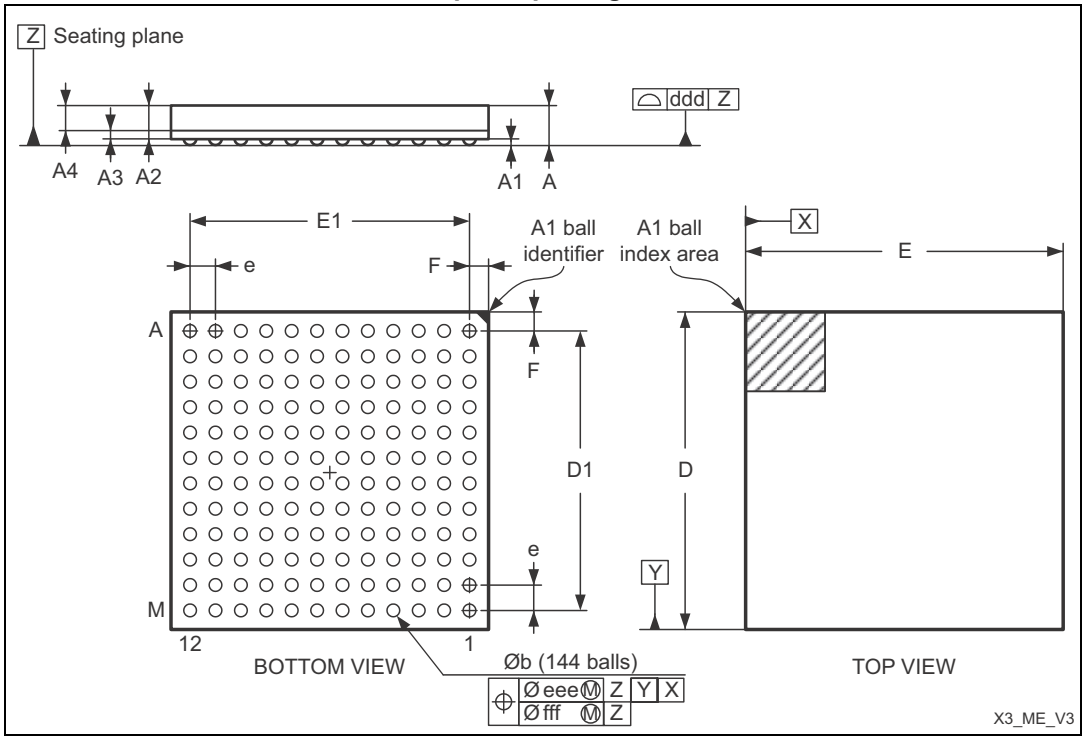
1. Guaranteed on characterization results, not tested in production.
2. Guaranteed by design, not tested in production.
3. Shortest sampling time can be determined in the application by multiple iterations.

# 6 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: *www.st.com*. ECOPACK® is an ST trademark.

## 6.1 LFBGA144 package information

**Figure 60. LFBGA144 – 144-ball low profile fine pitch ball grid array, 10 x 10 mm, 0.8 mm pitch, package outline**




1. Drawing is not to scale.

**Table 68. LFBGA144 – 144-ball low profile fine pitch ball grid array, 10 x 10 mm, 0.8 mm pitch, package mechanical data**

| Symbol | millimeters | | | inches[1] | | |
|---|---|---|---|---|---|---|
| | Min | Typ | Max | Typ | Min | Max |
| A[2] | - | - | 1.700 | | | 0.0669 |
| A1 | 0.210 | - | - | 0.0083 | | |
| A2 | - | 1.060 | - | | 0.0417 | |
| A3 | | 0.026 | | | 0.0010 | |
| A4 | - | 0.800 | - | - | 0.0315 | - |
| b | 0.350 | 0.400 | 0.450 | 0.0138 | 0.0157 | 0.0177 |
| D | 9.850 | 10.000 | 10.150 | 0.3878 | 0.3937 | 0.3996 |
| D1 | - | 8.800 | - | - | 0.3465 | - |
| E | 9.850 | 10.000 | 10.150 | 0.3878 | 0.3937 | 0.3996 |
| E1 | - | 8.800 | - | - | 0.3465 | - |
| e | - | 0.800 | - | - | 0.0315 | - |
| F | - | 0.600 | - | - | 0.0236 | - |
| ddd | - | - | 0.100 | - | - | 0.0039 |

**Table 68. LFBGA144 – 144-ball low profile fine pitch ball grid array, 10 x 10 mm, 0.8 mm pitch, package mechanical data (continued)**

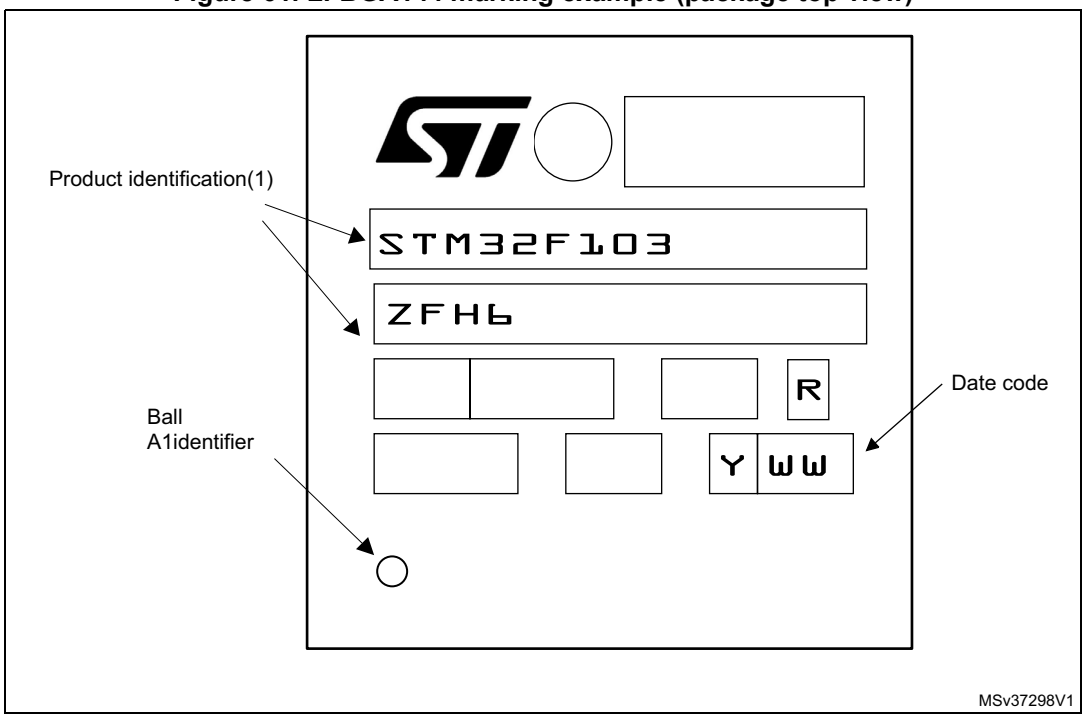
| Symbol | millimeters | | | inches[1] | | |
|---|---|---|---|---|---|---|
| | Min | Typ | Max | Typ | Min | Max |
| eee | - | - | 0.150 | - | - | 0.0059 |
| fff | - | - | 0.080 | - | - | 0.0031 |

1. Values in inches are converted from mm and rounded to 4 decimal digits.
2. STATSChipPAC package dimensions.

## Device marking for LFBGA144 package

The following figure gives an example of topside marking orientation versus ball A1 identifier location.

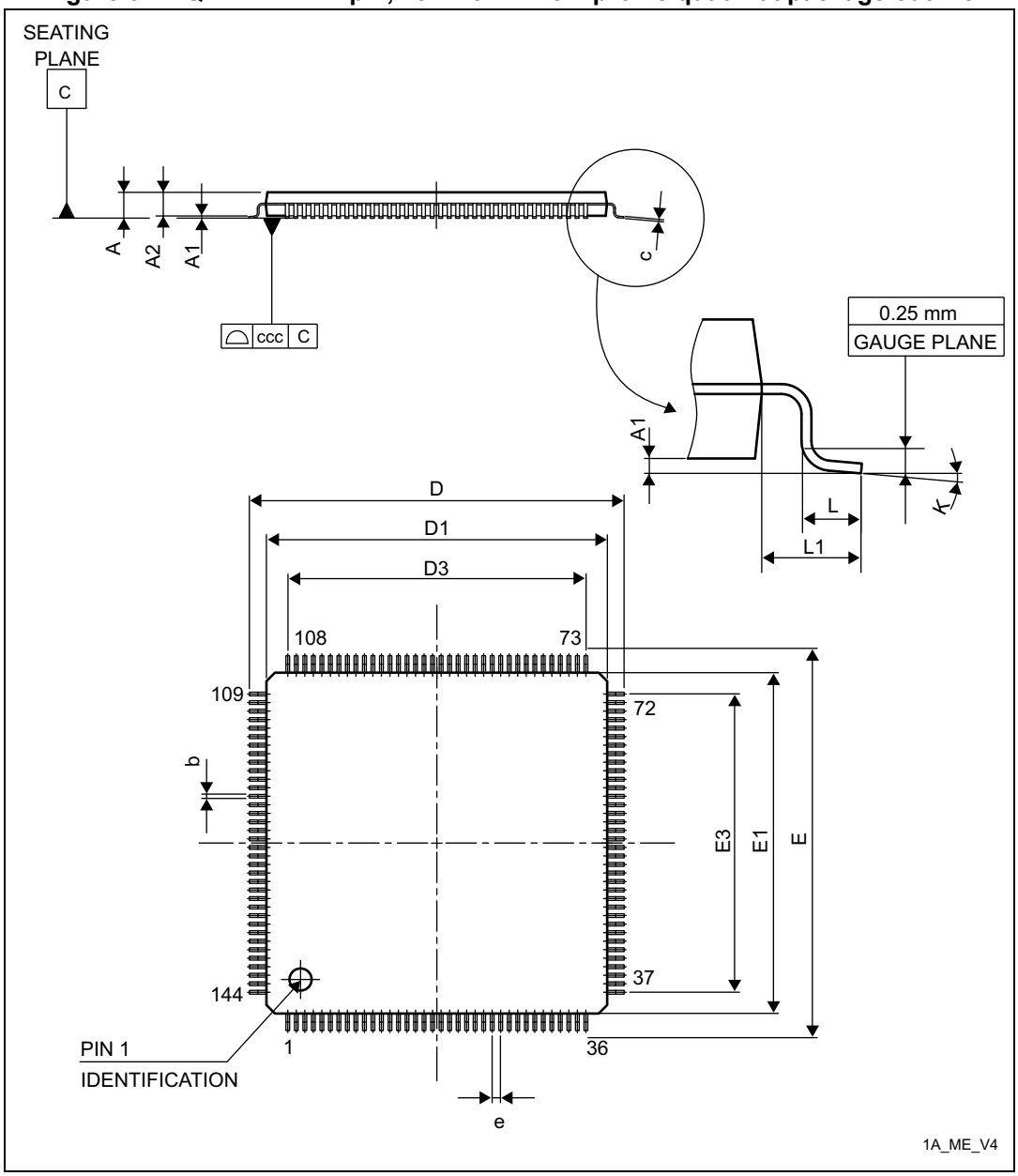
**Figure 61. LFBGA144 marking example (package top view)**




1. Parts marked as “ES”, “E” or accompanied by an Engineering Sample notification letter, are not yet qualified and therefore not yet ready to be used in production and any consequences deriving from such usage will not be at ST charge. In no event, ST will be liable for any customer usage of these engineering samples in production. ST Quality has to be contacted prior to any decision to use these Engineering samples to run qualification activity.

## 6.2 LQFP144 package information

**Figure 62. LQFP144 - 144-pin, 20 x 20 mm low-profile quad flat package outline**



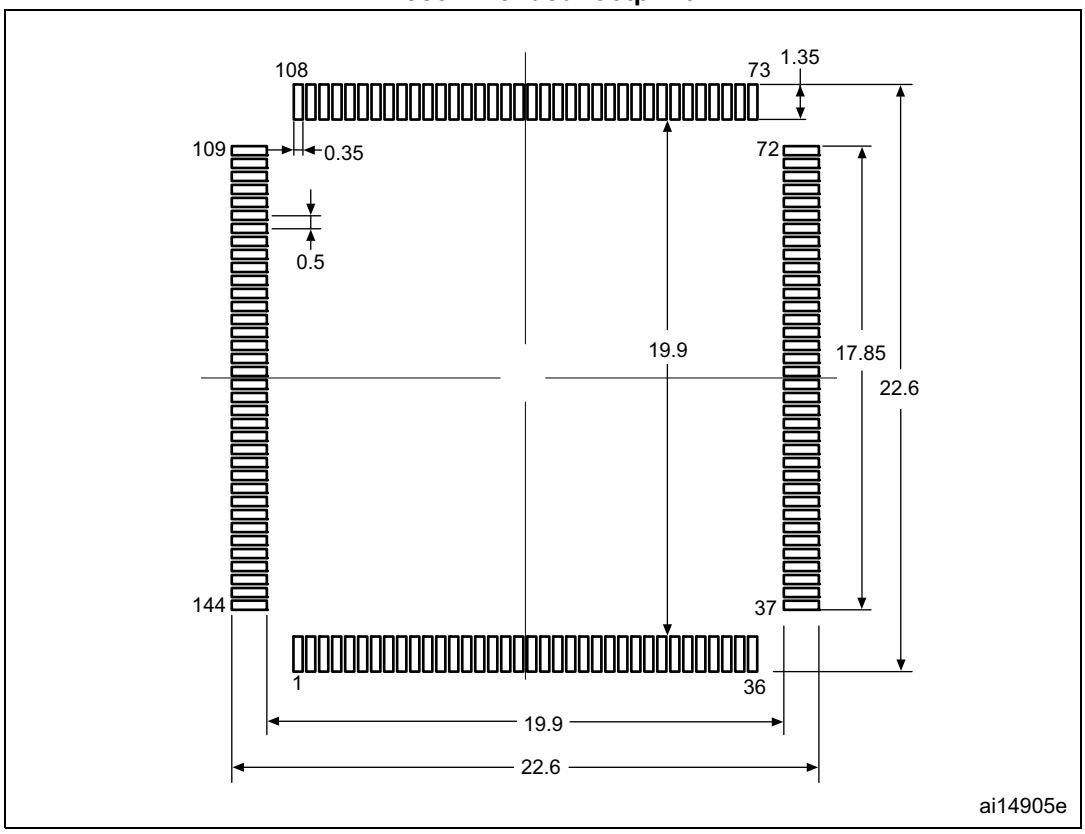

1. Drawing is not to scale.

**Table 69. LQFP144 - 144-pin, 20 x 20 mm low-profile quad flat package mechanical data**

| Symbol | millimeters | | | inches[1] | | |
|---|---|---|---|---|---|---|
| | Min | Typ | Max | Min | Typ | Max |
| A | - | - | 1.600 | - | - | 0.0630 |
| A1 | 0.050 | - | 0.150 | 0.0020 | - | 0.0059 |
| A2 | 1.350 | 1.400 | 1.450 | 0.0531 | 0.0551 | 0.0571 |
| b | 0.170 | 0.220 | 0.270 | 0.0067 | 0.0087 | 0.0106 |
| c | 0.090 | - | 0.200 | 0.0035 | - | 0.0079 |
| D | 21.800 | 22.000 | 22.200 | 0.8583 | 0.8661 | 0.8740 |
| D1 | 19.800 | 20.000 | 20.200 | 0.7795 | 0.7874 | 0.7953 |
| D3 | - | 17.500 | - | - | 0.6890 | - |
| E | 21.800 | 22.000 | 22.200 | 0.8583 | 0.8661 | 0.8740 |
| E1 | 19.800 | 20.000 | 20.200 | 0.7795 | 0.7874 | 0.7953 |
| E3 | - | 17.500 | - | - | 0.6890 | - |
| e | - | 0.500 | - | - | 0.0197 | - |
| L | 0.450 | 0.600 | 0.750 | 0.0177 | 0.0236 | 0.0295 |
| L1 | - | 1.000 | - | - | 0.0394 | - |
| k | 0° | 3.5° | 7° | 0° | 3.5° | 7° |
| ccc | - | - | 0.080 | - | - | 0.0031 |

1. Values in inches are converted from mm and rounded to 4 decimal digits.

**Figure 63. LQFP144 - 144-pin,20 x 20 mm low-profile quad flat package recommended footprint**

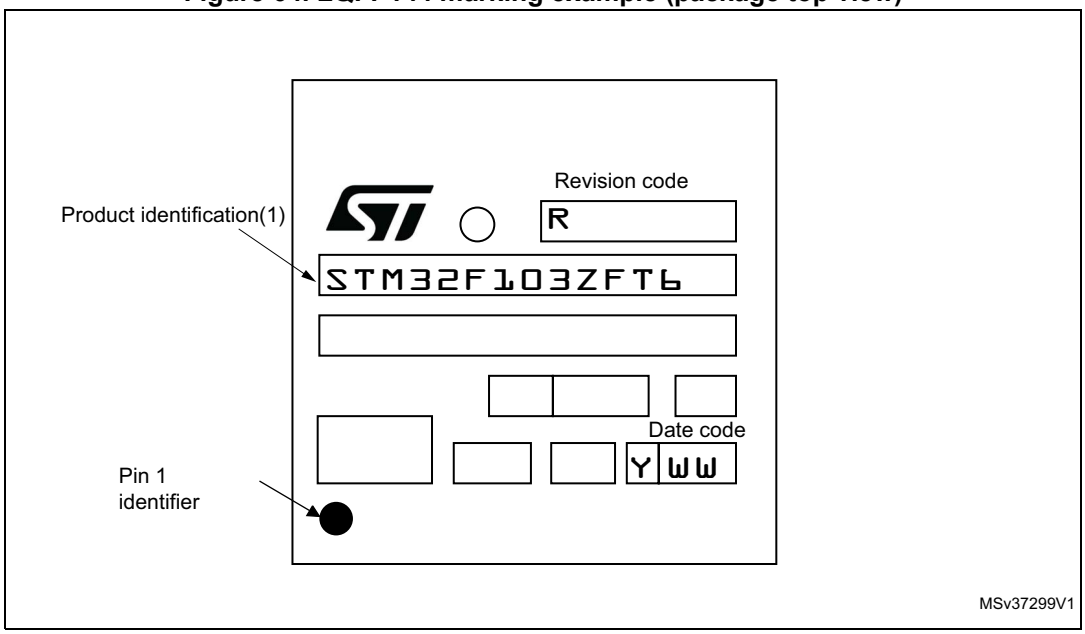



1. Dimensions are expressed in millimeters.

### Device marking for LQFP144 package

The following figure gives an example of topside marking orientation versus pin 1 identifier location.

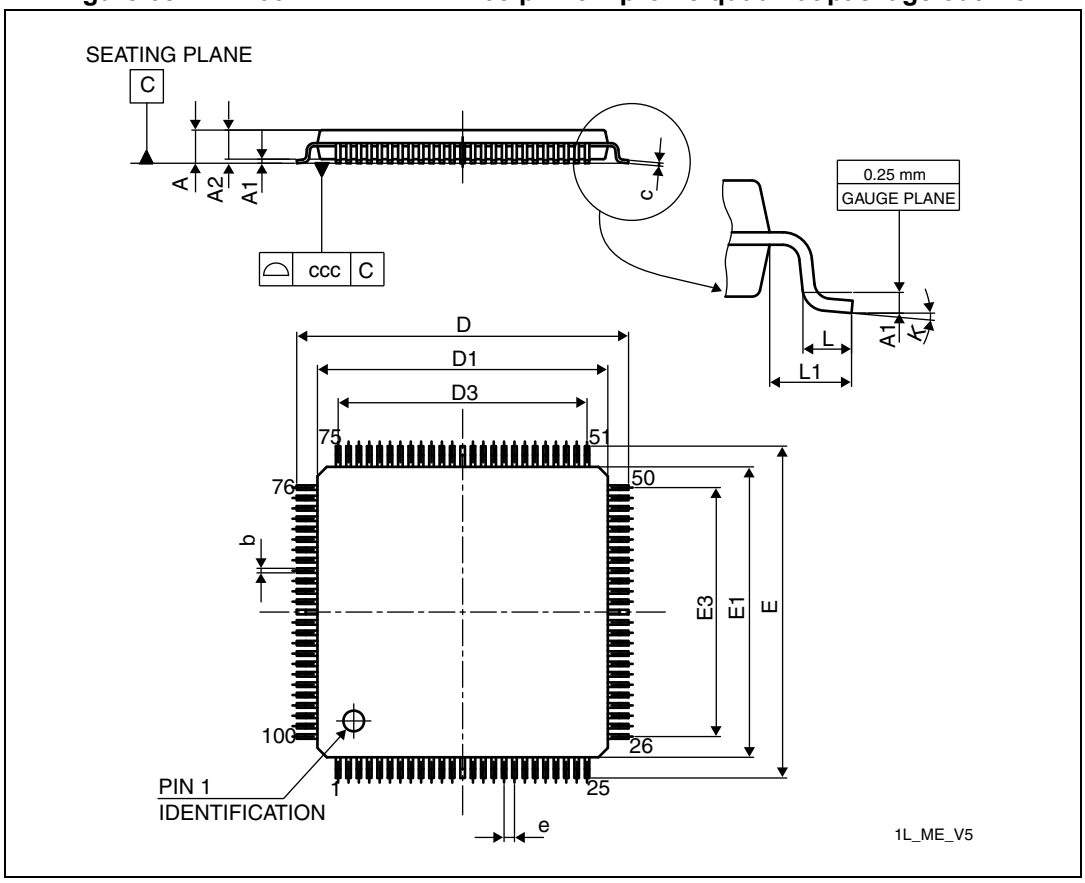
**Figure 64. LQFP144 marking example (package top view)**




1. Parts marked as “ES”, “E” or accompanied by an Engineering Sample notification letter, are not yet qualified and therefore not yet ready to be used in production and any consequences deriving from such usage will not be at ST charge. In no event, ST will be liable for any customer usage of these engineering samples in production. ST Quality has to be contacted prior to any decision to use these Engineering samples to run qualification activity.

## 6.3 LQFP100 package information

**Figure 65. LFP100 – 14 x 14 mm 100 pin low-profile quad flat package outline**




1. Drawing is not to scale.

**Table 70. LQPF100 – 14 x 14 mm 100-pin low-profile quad flat package mechanical data**

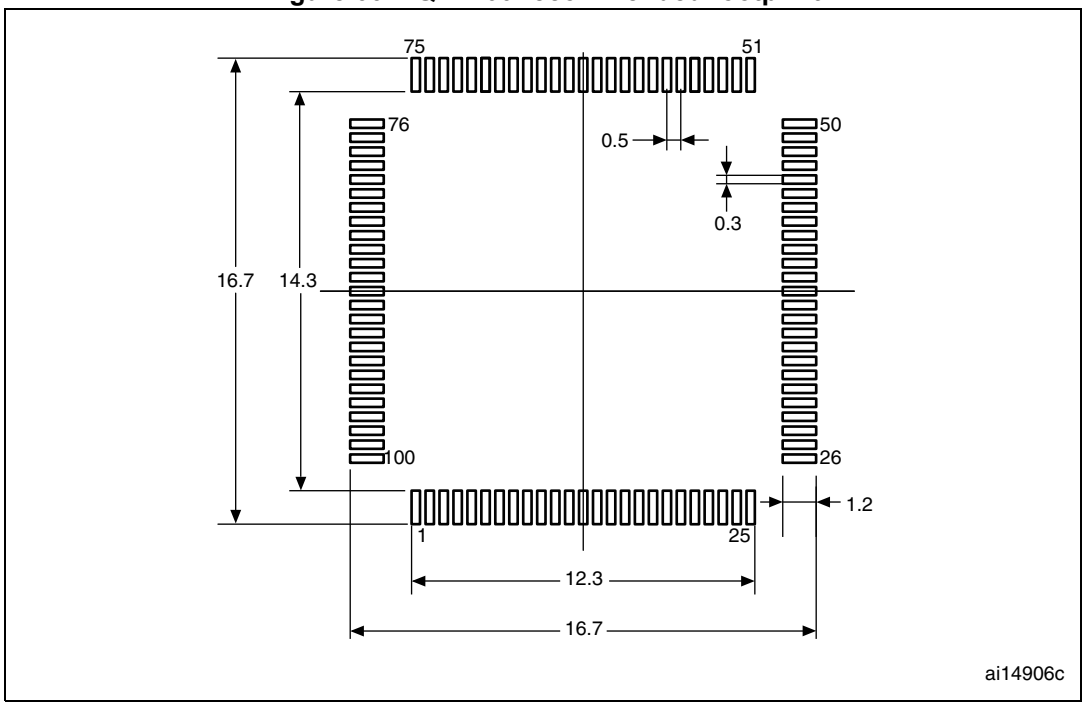
| Symbol | millimeters | | | inches(1) | | |
|---|---|---|---|---|---|---|
| | Min | Typ | Max | Min | Typ | Max |
| A | - | - | 1.600 | - | - | 0.0630 |
| A1 | 0.050 | - | 0.150 | 0.0020 | - | 0.0059 |
| A2 | 1.350 | 1.400 | 1.450 | 0.0531 | 0.0551 | 0.0571 |
| b | 0.170 | 0.220 | 0.270 | 0.0067 | 0.0087 | 0.0106 |
| c | 0.090 | - | 0.200 | 0.0035 | - | 0.0079 |
| D | 15.800 | 16.000 | 16.200 | 0.6220 | 0.6299 | 0.6378 |
| D1 | 13.800 | 14.000 | 14.200 | 0.5433 | 0.5512 | 0.5591 |
| D3 | - | 12.000 | - | - | 0.4724 | - |
| E | 15.800 | 16.000 | 16.200 | 0.6220 | 0.6299 | 0.6378 |
| E1 | 13.800 | 14.000 | 14.200 | 0.5433 | 0.5512 | 0.5591 |
| E3 | - | 12.000 | - | - | 0.4724 | - |

**Table 70. LQPF100 – 14 x 14 mm 100-pin low-profile quad flat package mechanical data (continued)**

| Symbol | millimeters | | | inches[1] | | |
|---|---|---|---|---|---|---|
| | Min | Typ | Max | Min | Typ | Max |
| e | - | 0.500 | - | - | 0.0197 | - |
| L | 0.450 | 0.600 | 0.750 | 0.0177 | 0.0236 | 0.0295 |
| L1 | - | 1.000 | - | - | 0.0394 | - |
| k | 0° | 3.5° | 7° | 0° | 3.5° | 7° |
| ccc | - | - | 0.08 | - | - | 0.0031 |

1. Values in inches are converted from mm and rounded to 4 decimal digits.

**Figure 66. LQFP100 recommended footprint**

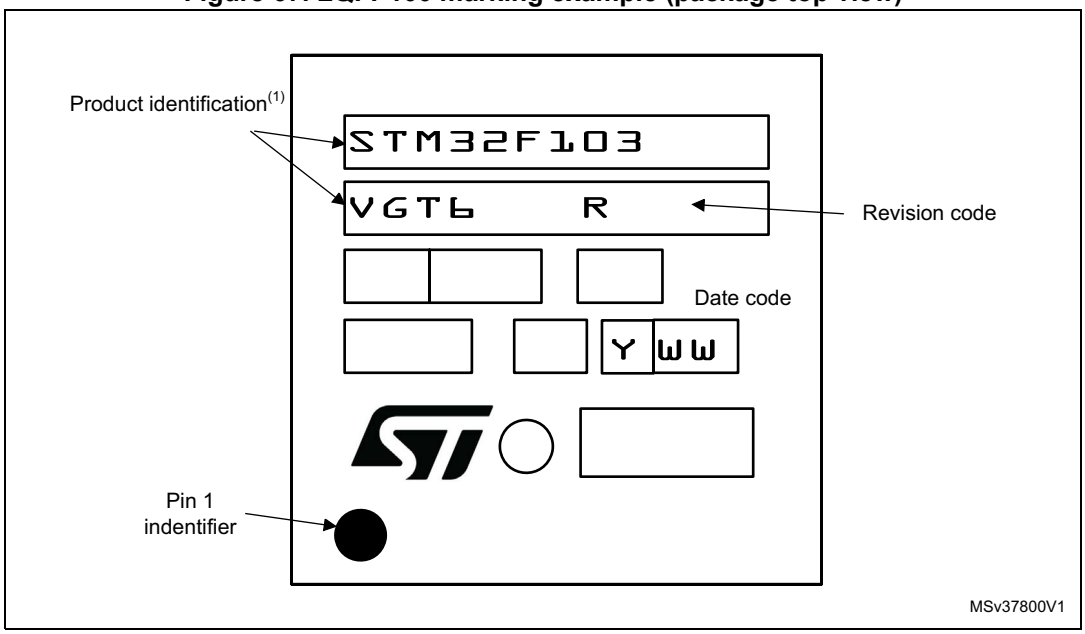



1. Dimensions are in millimeters.

### Device marking for LQFP100 package

The following figure gives an example of topside marking orientation versus pin 1 identifier location.

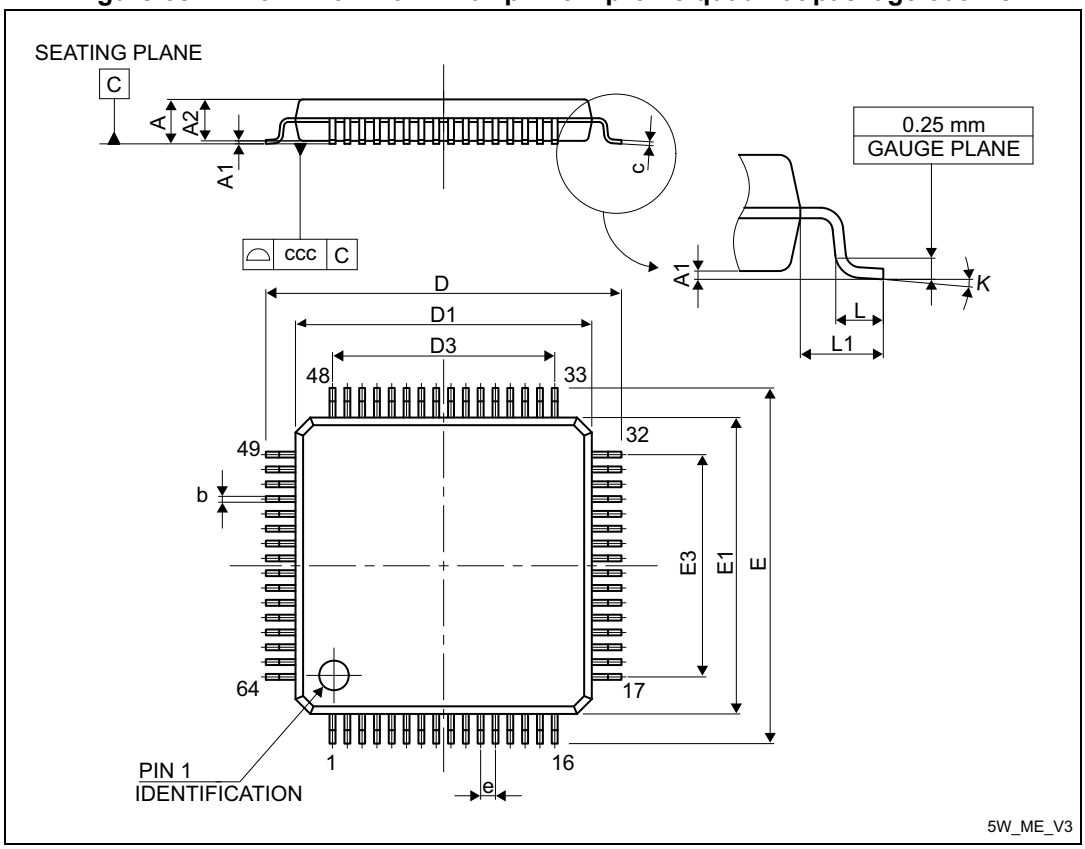
**Figure 67. LQFP100 marking example (package top view)**




1. Parts marked as “ES”, “E” or accompanied by an Engineering Sample notification letter, are not yet qualified and therefore not yet ready to be used in production and any consequences deriving from such usage will not be at ST charge. In no event, ST will be liable for any customer usage of these engineering samples in production. ST Quality has to be contacted prior to any decision to use these Engineering samples to run qualification activity.

## 6.4 LQFP64 package information

**Figure 68. LFP64 – 10 x 10 mm 64 pin low-profile quad flat package outline**




1. Drawing is not in scale.

**Table 71. LQFP64 – 10 x 10 mm 64 pin low-profile quad flat package mechanical data**

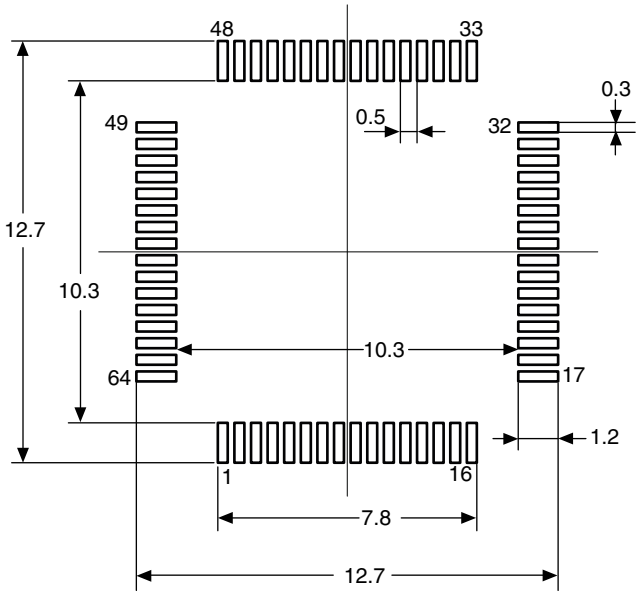
| Symbol | millimeters | | | inches(1) | | |
|---|---|---|---|---|---|---|
| | Min | Typ | Max | Min | Typ | Max |
| A | - | - | 1.600 | - | - | 0.0630 |
| A1 | 0.050 | - | 0.150 | 0.0020 | - | 0.0059 |
| A2 | 1.350 | 1.400 | 1.450 | 0.0531 | 0.0551 | 0.0571 |
| b | 0.170 | 0.220 | 0.270 | 0.0067 | 0.0087 | 0.0106 |
| c | 0.090 | - | 0.200 | 0.0035 | - | 0.0079 |
| D | - | 12.000 | - | - | 0.4724 | - |
| D1 | - | 10.000 | - | - | 0.3937 | - |
| D3 | - | 7.500 | - | - | 0.2953 | - |
| E | - | 12.000 | - | - | 0.4724 | - |
| E1 | - | 10.000 | - | - | 0.3937 | - |

**Table 71. LQFP64 – 10 x 10 mm 64 pin low-profile quad flat package mechanical data (continued)**

| Symbol | millimeters | | | inches[1] | | |
|---|---|---|---|---|---|---|
| | Min | Typ | Max | Min | Typ | Max |
| E3 | - | 7.500 | - | - | 0.2953 | - |
| e | - | 0.500 | - | - | 0.0197 | - |
| θ | 0° | 3.5° | 7° | 0° | 3.5° | 7° |
| L | 0.450 | 0.600 | 0.750 | 0.0177 | 0.0236 | 0.0295 |
| L1 | - | 1.000 | - | - | 0.0394 | - |
| ccc | - | - | 0.080 | - | - | 0.0031 |

1. Values in inches are converted from mm and rounded to 4 decimal digits.

**Figure 69. LQFP64 - 64-pin, 10 x 10 mm low-profile quad flat recommended footprint**

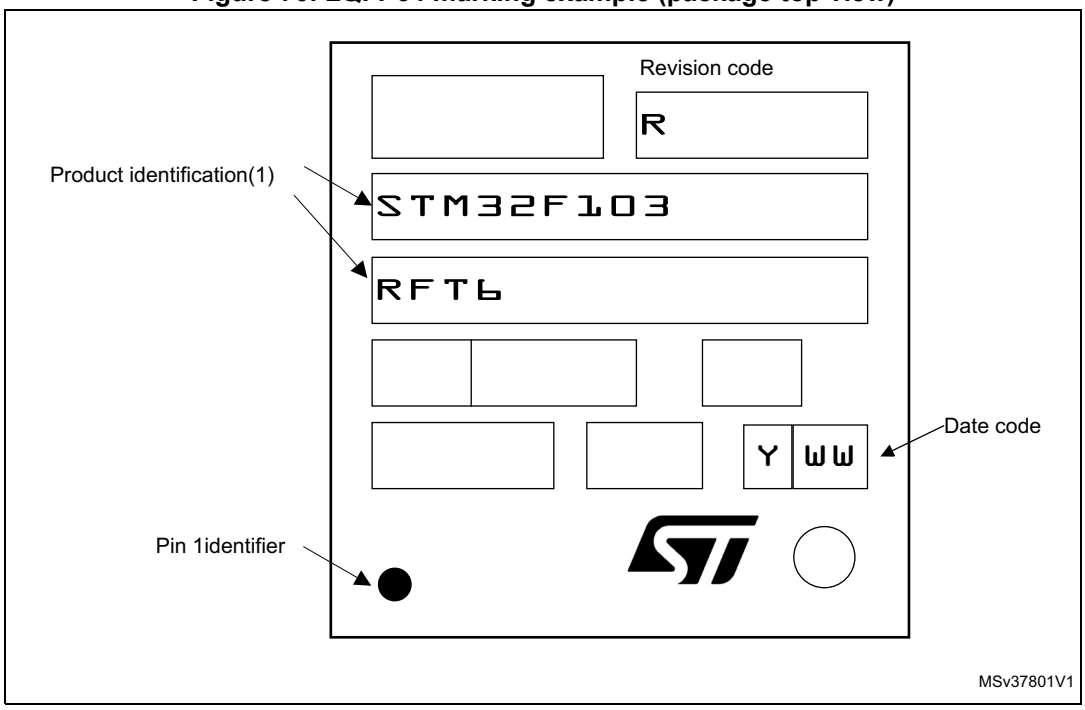



1. Dimensions are in millimeters.

### Device marking for LQFP64 package

The following figure gives an example of topside marking orientation versus pin 1 identifier location.

**Figure 70. LQFP64 marking example (package top view)**




1. Parts marked as “ES”, “E” or accompanied by an Engineering Sample notification letter, are not yet qualified and therefore not yet ready to be used in production and any consequences deriving from such usage will not be at ST charge. In no event, ST will be liable for any customer usage of these engineering samples in production. ST Quality has to be contacted prior to any decision to use these Engineering samples to run qualification activity.

## 6.5 Thermal characteristics

The maximum chip junction temperature ($T_J$max) must never exceed the values given in *Table 10: General operating conditions on page 44*.

The maximum chip-junction temperature, $T_J$ max, in degrees Celsius, may be calculated using the following equation:

$T_J$ max = $T_A$ max + ($P_D$ max x $\Theta_{JA}$)

Where:

- $T_A$ max is the maximum ambient temperature in °C,
- $\Theta_{JA}$ is the package junction-to-ambient thermal resistance, in °C/W,
- $P_D$ max is the sum of $P_{INT}$ max and $P_{I/O}$ max ($P_D$ max = $P_{INT}$ max + $P_{I/O}$max),
- $P_{INT}$ max is the product of $I_{DD}$ and $V_{DD}$, expressed in Watts. This is the maximum chip internal power.

$P_{I/O}$ max represents the maximum power dissipation on output pins where:

$$P_{I/O} \text{ max} = \Sigma (V_{OL} \times I_{OL}) + \Sigma((V_{DD} - V_{OH}) \times I_{OH}),$$

taking into account the actual $V_{OL}$ / $I_{OL}$ and $V_{OH}$ / $I_{OH}$ of the I/Os at low and high level in the application.

**Table 72. Package thermal characteristics**

| Symbol | Parameter | Value | Unit |
|---|---|---|---|
| $\Theta_{JA}$ | **Thermal resistance junction-ambient** LFBGA144 - 10 × 10 mm / 0.8 mm pitch | 40 | °C/W |
| | **Thermal resistance junction-ambient** LQFP144 - 20 × 20 mm / 0.5 mm pitch | 30 | |
| | **Thermal resistance junction-ambient** LQFP100 - 14 × 14 mm / 0.5 mm pitch | 46 | |
| | **Thermal resistance junction-ambient** LQFP64 - 10 × 10 mm / 0.5 mm pitch | 45 | |

### 6.5.1 Reference document

JESD51-2 Integrated Circuits Thermal Test Method Environment Conditions - Natural Convection (Still Air). Available from www.jedec.org

### 6.5.2 Selecting the product temperature range

When ordering the microcontroller, the temperature range is specified in the ordering information scheme shown in *Table 73: STM32F103xF and STM32F103xG ordering information scheme*.

Each temperature range suffix corresponds to a specific guaranteed ambient temperature at maximum dissipation and, to a specific maximum junction temperature.

As applications do not commonly use the STM32F103xF and STM32F103xG at maximum dissipation, it is useful to calculate the exact power consumption and junction temperature to determine which temperature range will be best suited to the application.

The following examples show how to calculate the temperature range needed for a given application.

#### Example 1: High-performance application

Assuming the following application conditions:

Maximum ambient temperature $T_{Amax}$ = 82 °C (measured according to JESD51-2), $I_{DDmax}$ = 50 mA, $V_{DD}$ = 3.5 V, maximum 20 I/Os used at the same time in output at low level with $I_{OL}$ = 8 mA, $V_{OL}$= 0.4 V and maximum 8 I/Os used at the same time in output at low level with $I_{OL}$ = 20 mA, $V_{OL}$= 1.3 V

$P_{INTmax}$ = 50 mA × 3.5 V= 175 mW

$P_{IOmax}$ = 20 × 8 mA × 0.4 V + 8 × 20 mA × 1.3 V = 272 mW

This gives: $P_{INTmax}$ = 175 mW and $P_{IOmax}$ = 272 mW:

$P_{Dmax}$ = 175 + 272 = 447 mW

Thus: $P_{Dmax}$ = 447 mW

Using the values obtained in *Table 72* $T_{Jmax}$ is calculated as follows:

– For LQFP100, 46 °C/W

$T_{Jmax}$ = 82 °C + (46 °C/W × 447 mW) = 82 °C + 20.6 °C = 102.6 °C

This is within the range of the suffix 6 version parts (–40 < $T_J$ < 105 °C).

In this case, parts must be ordered at least with the temperature range suffix 6 (see *Table 73: STM32F103xF and STM32F103xG ordering information scheme*).

#### Example 2: High-temperature application

Using the same rules, it is possible to address applications that run at high ambient temperatures with a low dissipation, as long as junction temperature $T_J$ remains within the specified range.

Assuming the following application conditions:

Maximum ambient temperature $T_{Amax}$ = 115 °C (measured according to JESD51-2), $I_{DDmax}$ = 20 mA, $V_{DD}$ = 3.5 V, maximum 20 I/Os used at the same time in output at low level with $I_{OL}$ = 8 mA, $V_{OL}$= 0.4 V

$P_{INTmax}$ = 20 mA × 3.5 V= 70 mW

$P_{IOmax}$ = 20 × 8 mA × 0.4 V = 64 mW

This gives: $P_{INTmax}$ = 70 mW and $P_{IOmax}$ = 64 mW:

$P_{Dmax}$ = 70 + 64 = 134 mW

Thus: $P_{Dmax}$ = 134 mW

Using the values obtained in *Table 72* $T_{Jmax}$ is calculated as follows:

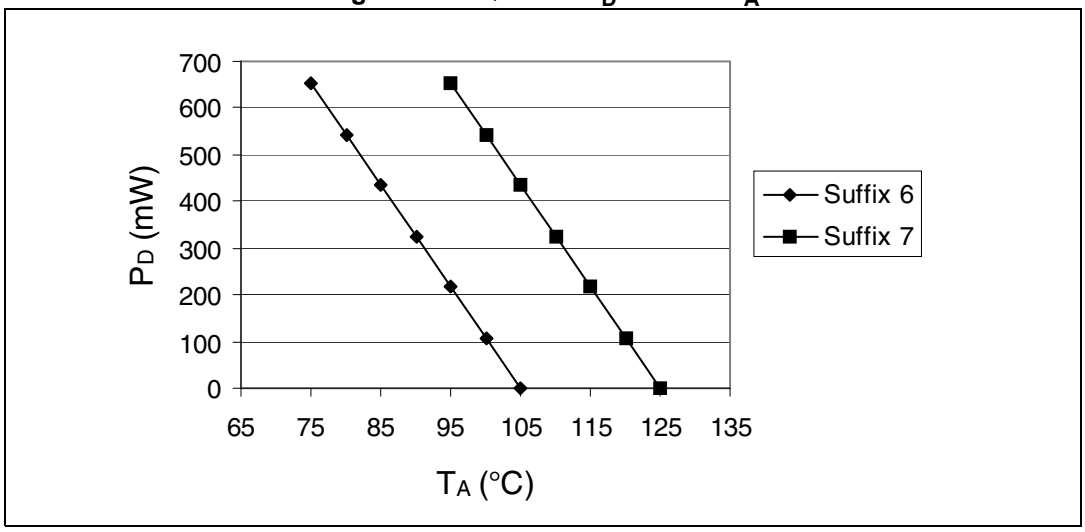
– For LQFP100, 46 °C/W

$T_{Jmax}$ = 115 °C + (46 °C/W × 134 mW) = 115 °C + 6.2 °C = 121.2 °C

This is within the range of the suffix 7 version parts (–40 < $T_J$ < 125 °C).

In this case, parts must be ordered at least with the temperature range suffix 7 (see *Section 7: Part numbering*).

**Figure 71. LQFP100 $P_D$ max vs. $T_A$**



# 7 Part numbering

**Table 73. STM32F103xF and STM32F103xG ordering information scheme**

Example: STM32 F 103 R F T 6 xxx

**Device family**

STM32 = ARM-based 32-bit microcontroller

**Product type**

F = general-purpose

**Device subfamily**

103 = performance line

**Pin count**

R = 64 pins

V = 100 pins

Z = 144 pins

**Flash memory size**

F = 768 Kbytes of Flash memory

G = 1 Mbyte of Flash memory

**Package**

H = BGA

T = LQFP

**Temperature range**

6 = Industrial temperature range, –40 to 85 °C.

7 = Industrial temperature range, –40 to 105 °C.

**Options**

xxx = programmed parts

TR = tape and real

For a list of available options (speed, package, etc.) or for further information on any aspect of this device, please contact your nearest ST sales office.

# 8 Revision history

**Table 74. Document revision history**

| Date | Revision | Changes |
|---|---|---|
| 27-Oct-2009 | 1 | Initial release. |
| 15-Nov-2010 | 2 | LQFP64 package mechanical data updated: see *Figure 66: LQFP64 – 10 x 10 mm 64 pin low-profile quad flat package outline* and *Table 71: LQFP64 – 10 x 10 mm 64 pin low-profile quad flat package mechanical data*.<br>Internal code removed from *Table 73: STM32F103xF and STM32F103xG ordering information scheme*.<br>Updated note 2 below *Table 54: $I^2C$ characteristics*<br>Updated *Figure 46: $I^2C$ bus AC waveforms and measurement circuit*<br>Updated *Figure 45: Recommended NRST pin protection*<br>Updated note 1 below *Table 49: I/O static characteristics*<br>Updated *Table 20: Peripheral current consumption*<br>Updated *Table 14: Maximum current consumption in Run mode, code with data processing running from Flash*<br>Updated *Table 15: Maximum current consumption in Run mode, code with data processing running from RAM*<br>Updated *Table 16: Maximum current consumption in Sleep mode, code running from Flash or RAM*<br>Updated *Table 17: Typical and maximum current consumptions in Stop and Standby modes*<br>Updated *Table 18: Typical current consumption in Run mode, code with data processing running from Flash*<br>Updated *Table 19: Typical current consumption in Sleep mode, code running from Flash or RAM*<br>Updated *Table 24: LSE oscillator characteristics ($f_{LSE}$ = 32.768 kHz)*<br>Updated *Figure 22: Asynchronous non-multiplexed SRAM/PSRAM/NOR read waveforms on page 63*<br>Added *Section 5.3.13: I/O current injection characteristics on page 84* |
| 18-Jan-2012 | 3 | *Section 2.3.26: GPIOs (general-purpose inputs/outputs)*: modified text of last sentence.<br>*Table 5: STM32F103xF and STM32F103xG pin definitions*: updated pins PD0, PD1, OSC_IN, OSC_OUT, PB8, PB9, and PF8.<br>*Table 7: Voltage characteristics*: Removed the previous footnotes 2 and 3 and added current footnote *2*.<br>*Table 8: Current characteristics*: updated footnotes *3*, *4*, and *5*.<br>*Table 21: High-speed external user clock characteristics*: replaced the $t_{w(HSE)}$ min value by 5 (instead of 16).<br>*Table 24: LSE oscillator characteristics ($f_{LSE}$ = 32.768 kHz)*: updated symbols and footnotes. |

**Table 74. Document revision history**

| Date | Revision | Changes |
|---|---|---|
| 18-Jan-2012 | 3 | *Asynchronous waveforms and timings*: added notes about $t_{HCLK}$ clock period and FSMC_BusTurnAroundDuration; updated conditions, modified *Table 31: Asynchronous non-multiplexed SRAM/PSRAM/NOR read timings*, *Table 32: Asynchronous non-multiplexed SRAM/PSRAM/NOR write timings*, *Table 34: Asynchronous multiplexed PSRAM/NOR read timings*, and *Table 35: Asynchronous multiplexed PSRAM/NOR write timings*; added *Table 33: Asynchronous multiplexed read timings*.<br>*Synchronous waveforms and timings*: updated *Figure 27: Synchronous multiplexed PSRAM write timings*; updated *Table 36: Synchronous multiplexed NOR/PSRAM read timings*, *Table 37: Synchronous multiplexed PSRAM write timings*, *Table 38: Synchronous non-multiplexed NOR/PSRAM read timings*, and *Table 39: Synchronous non-multiplexed PSRAM write timings*.<br>*PC Card/CompactFlash controller waveforms and timings*: updated *Figure 35: PC Card/CompactFlash controller waveforms for I/O space write access*; split switching characteristics into *Table 40: Switching characteristics for PC Card/CF read and write cycles in attribute/common space* and *Table 41: Switching characteristics for PC Card/CF read and write cycles in I/O space*, modified values, and removed footnote concerning preliminary values.<br>*NAND controller waveforms and timings*: updated conditions, split switching characteristics into *Table 42: Switching characteristics for NAND Flash read cycles* and *Table 43: Switching characteristics for NAND Flash write cycles*, and values modified.<br>*Section 5.3.14: I/O port characteristics*: updated footnote *1* of *Table 49: I/O static characteristics*; updated *Output driving current*.<br>*Table 50: Output voltage characteristics*: swapped “TTL and “CMOS” ports in the conditions column.<br>*Table 54: $I^2C$ characteristics*: updated footnote *2.*<br>Updated *Table 58: SD / MMC characteristics*.<br>*Table 62: ADC characteristics*: updated footnote *1.*<br>*Table 64: ADC accuracy - limited test conditions*: updated footnote *3.*<br>*Table 67: TS characteristics*: updated footnote *1.* |

**Table 74. Document revision history**

| Date | Revision | Changes |
|---|---|---|
| 15-May-2015 | 4 | Added document status on first page.<br>Replace DAC1_OUT/DAC2_OUT by DAC_OUT1/DAC_OUT2, and updated TIM5 in *Figure 1: STM32F103xF and STM32F103xG performance line block diagram on page 12*.<br>Replaced USBDP/USBDM by USB_DP/USB_DM in the whole document.<br>Updated notes related to electrical values guaranteed by characterization results.<br>Updated *Table 20: Peripheral current consumption*.<br>Updated *Table 36: Synchronous multiplexed NOR/PSRAM read timings* to *Table 39: Synchronous non-multiplexed PSRAM write timings*(added FSMC_NWAIT timings). Updated *Figure 26: Synchronous multiplexed NOR/PSRAM read timings on page 73* and *Figure 28: Synchronous non-multiplexed NOR/PSRAM read timings on page 77* and *Figure 35: PC Card/CompactFlash controller waveforms for I/O space write access on page 83*.<br>Updated CDM class in *Table 46: ESD absolute maximum ratings*.<br>Updated *Figure 44: I/O AC characteristics definition on page 96* and *Figure 45: Recommended NRST pin protection on page 97*.<br>Updated *Figure 49: SPI timing diagram - master mode(1) on page 96*.<br>Modified note 3 in *Table 56: SPI characteristics*.<br>*Section : I2C interface characteristics*: Updated introduction, updated *Table 54: $I^2C$ characteristics* and *Figure 46: $I^2C$ bus AC waveforms and measurement circuit on page 99*.<br>Modified note 2 in *Table 64: ADC accuracy - limited test conditions*, *Figure 55: ADC accuracy characteristics on page 110* and *Figure 56: Typical connection diagram using the ADC on page 111*. Updated *Figure 57: Power supply and reference decoupling ($V_{REF+}$ not connected to $V_{DDA}$) on page 111* and *Figure 58: Power supply and reference decoupling ($V_{REF+}$ connected to $V_{DDA}$) on page 112*.<br>Updated $I_{DDA}$ description and Offset comment in *Table 66: DAC characteristics*.<br>Updated *Section 6.1: LFBGA144 package information* and added *Section : Device marking for LFBGA144 package*.<br>Updated *Section 6.2: LQFP144 package information* and added *Section : Device marking for LQFP144 package*.<br>Updated *Section 6.3: LQFP100 package information* and added *Section : Device marking for LQFP100 package*.<br>Updated *Section 6.4: LQFP64 package information* and added *Section : Device marking for LQFP64 package*. |

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